

HYB18T256400AF(L)  
HYB18T256800AF(L)  
HYB18T256160AF(L)

256-Mbit DDR2 SDRAM

DDR2 SDRAM  
RoHS Compliant Products

Memory Products



N e v e r   s t o p   t h i n k i n g .

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	Added DDR2-800 components
	Added DDR2-800 to speed grade dependant table-values

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## 256-Mbit DDR2 SDRAM DDR2 SDRAM

HYB18T256400AF(L)  
HYB18T256800AF(L)  
HYB18T256160AF(L)

# 1 Overview

This chapter gives an overview of the 256-Mbit DDR2 SDRAM product family and describes its main characteristics.

## 1.1 Features

The 256-Mbit DDR2 SDRAM offers the following key features:

- 1.8 V  $\pm$  0.1 V Power Supply
- 1.8 V  $\pm$  0.1 V (SSTL\_18) compatible I/O
- DRAM organisations with 4, 8 and 16 data in/outputs
- Double Data Rate architecture: two data transfers per clock cycle, four internal banks for concurrent operation
- CAS Latency: (2), 3, 4, 5 and 6
- Burst Length: 4 and 8
- All speed grades faster than DDR2–400 comply with DDR2–400 timing specifications
- Differential clock inputs (CK and  $\overline{\text{CK}}$ )
- Bi-directional, differential data strobes (DQS and  $\overline{\text{DQS}}$ ) are transmitted / received with data. Edge aligned with read data and center-aligned with write data.
- DLL aligns DQ and DQS transitions with clock
- $\overline{\text{DQS}}$  can be disabled for single-ended data strobe operation
- Commands entered on each positive clock edge, data and data mask are referenced to both edges of DQS
- Data masks (DM) for write data
- Posted  $\overline{\text{CAS}}$  by programmable additive latency for better command and data bus efficiency
- Off-Chip-Driver impedance adjustment (OCD) and On-Die-Termination (ODT) for better signal quality.
- Auto-Precharge operation for read and write bursts
- Auto-Refresh, Self-Refresh and power saving Power-Down modes
- Average Refresh Period 7.8  $\mu\text{s}$
- Full and reduced Strength Data-Output Drivers
- 1KByte Page Size for  $\times 4$  &  $\times 8$ , 2KByte Page Size for  $\times 16$
- Packages: P-TFBGA-60 for  $\times 4$  &  $\times 8$  components, P-TFBGA-84 for  $\times 16$  components
- RoHS Compliant Products<sup>1)</sup>

**Table 1 Performance for DDR2–800**

Product Type Speed Code			–25F	–2.5	Unit
Speed Grade			DDR2–800 5–5–5	DDR2–800 6–6–6	—
max. Clock Frequency	@CL6	$f_{\text{CK6}}$	400	400	MHz
	@CL5	$f_{\text{CK5}}$	400	333	MHz
	@CL4	$f_{\text{CK4}}$	266	266	MHz
	@CL3	$f_{\text{CK3}}$	200	200	MHz
min. RAS-CAS-Delay		$t_{\text{RCD}}$	12.5	15	ns
min. Row Precharge Time		$t_{\text{RP}}$	12.5	15	ns
min. Row Active Time		$t_{\text{RAS}}$	45	45	ns
min. Row Cycle Time		$t_{\text{RC}}$	57.5	60	ns

1) RoHS Compliant Product: Restriction of the use of certain hazardous substances (RoHS) in electrical and electronic equipment as defined in the directive 2002/95/EC issued by the European Parliament and of the Council of 27 January 2003. These substances include mercury, lead, cadmium, hexavalent chromium, polybrominated biphenyls and polybrominated biphenyl ethers.

**Table 2 Performance for DDR2-667**

Product Type Speed Code			-3	-3S	Unit
Speed Grade			DDR2-667 4-4-4	DDR2-667 5-5-5	—
max. Clock Frequency	@CL5	$f_{CK5}$	333	333	MHz
	@CL4	$f_{CK4}$	333	266	MHz
	@CL3	$f_{CK3}$	200	200	MHz
min. RAS-CAS-Delay		$t_{RCD}$	12	15	ns
min. Row Precharge Time		$t_{RP}$	12	15	ns
min. Row Active Time		$t_{RAS}$	45	45	ns
min. Row Cycle Time		$t_{RC}$	57	60	ns

**Table 3 Performance for DDR2-400B and DDR2-533C**

Product Type Speed Code			-3.7	-5	Unit
Speed Grade			DDR2-533 4-4-4	DDR2-400 3-3-3	—
max. Clock Frequency	@CL5	$f_{CK5}$	266	200	MHz
	@CL4	$f_{CK4}$	266	200	MHz
	@CL3	$f_{CK3}$	200	200	MHz
min. RAS-CAS-Delay		$t_{RCD}$	15	15	ns
min. Row Precharge Time		$t_{RP}$	15	15	ns
min. Row Active Time		$t_{RAS}$	45	40	ns
min. Row Cycle Time		$t_{RC}$	60	55	ns

## 1.2 Description

The 256-Mbit DDR2 DRAM is a high-speed Double-Data-Rate-Two CMOS Synchronous DRAM device containing 268,435,456 bits and internally configured as a quad-bank DRAM. The 256-Mbit device is organized as either 16 Mbit  $\times$  4 I/O  $\times$  4 banks, 8 Mbit  $\times$  8 I/O  $\times$  4 banks or 4 Mbit  $\times$  16 I/O  $\times$  4 banks chip. These synchronous devices achieve high speed transfer rates starting at 400 Mbit/sec/pin for general applications. See [Table 1](#), [Table 2](#) and [Table 3](#) for performance figures.

The device is designed to comply with all DDR2 DRAM key features:

1. posted  $\overline{CAS}$  with additive latency,
2. write latency = read latency - 1,
3. normal and weak strength data-output driver,
4. Off-Chip Driver (OCD) impedance adjustment
5. On-Die Termination (ODT) function.

All of the control and address inputs are synchronized with a pair of externally supplied differential clocks. Inputs are latched at the cross point of differential clocks (CK rising and  $\overline{CK}$  falling). All I/Os are synchronized with a single ended DQS or differential DQS- $\overline{DQS}$  pair in a source synchronous fashion.

A 15 bit address bus is used to convey row, column and bank address information in a  $\overline{RAS}$ - $\overline{CAS}$  multiplexing style.

The DDR2 device operates with a 1.8 V  $\pm$  0.1 V power supply. An Auto-Refresh and Self-Refresh mode is provided along with various power-saving power-down modes.

The functionality described and the timing specifications included in this data sheet are for the DLL Enabled mode of operation.

The DDR2 SDRAM is available in P-TFBGA-60 and P-TFBGA-84 package.

### 1.3 Ordering Information



**Table 4 Ordering Information for RoHS compliant products**

Part Number	Org	Speed	CAS <sup>1)</sup> RCD <sup>2)</sup> RP <sup>3)</sup> Latencies	Clock (MHz)	CAS <sup>1)</sup> RCD <sup>2)</sup> RP <sup>3)</sup> Latencies	Clock (MHz)	Package
HYB18T256400AF-2.5	×4	DDR2-800	6-6-6	400	5-5-5	333	P-TFBGA-60
HYB18T256800AF-2.5	×8						P-TFBGA-84
HYB18T256160AF-2.5	×16						P-TFBGA-60
HYB18T256400AF-25F	×4		5-5-5	400	4-4-4	333	P-TFBGA-60
HYB18T256800AF-25F	×8						P-TFBGA-84
HYB18T256160AF-25F	×16						P-TFBGA-60
HYB18T256400AF-3	×4	DDR2-667	4-4-4	333	3-3-3	200	P-TFBGA-60
HYB18T256800AF-3	×8						P-TFBGA-84
HYB18T256160AF-3	×16						P-TFBGA-60
HYB18T256400AF-3S	×4		5-5-5	333	4-4-4	266	P-TFBGA-60
HYB18T256800AF-3S	×8						P-TFBGA-84
HYB18T256160AF-3S	×16						P-TFBGA-60
HYB18T256400AF-3.7	×4	DDR2-533	4-4-4	266	3-3-3	200	P-TFBGA-60
HYB18T256800AF-3.7	×8						P-TFBGA-84
HYB18T256160AF-3.7	×16						P-TFBGA-60
HYB18T256400AFL-3.7	×4		4-4-4	266	3-3-3	200	P-TFBGA-60
HYB18T256800AFL-3.7	×8						P-TFBGA-84
HYB18T256160AFL-3.7	×16						P-TFBGA-60
HYB18T256400AF-5	×4	DDR2-400	3-3-3	200	—	—	P-TFBGA-60
HYB18T256800AF-5	×8						P-TFBGA-84
HYB18T256160AF-5	×16						P-TFBGA-60

- 1) CAS: Column Address Strobe
- 2) RCD: Row Column Delay
- 3) RP: Row Precharge

Note: For product nomenclature see [Chapter 10](#) of this data sheet

## 2 Pin Configuration and Block Diagrams

The pin configuration of a DDR2 SDRAM is listed by function in [Table 5](#). The abbreviations used in the Pin# and Buffer Type columns are explained in [Table 6](#) and [Table 7](#) respectively. The pin numbering for the FBGA package is depicted in Figure 1 for ×4, Figure 2 for ×8 and Figure 3 for ×16.

**Table 5 Pin Configuration of DDR2 SDRAM**

Ball#/Pin#	Name	Pin Type	Buffer Type	Function
<b>Clock Signals ×4/×8 organizations</b>				
E8	CK	I	SSTL	<b>Clock Signal CK, Complementary Clock Signal <math>\overline{CK}</math></b> <i>Note: CK and <math>\overline{CK}</math> are differential system clock inputs. All address and control inputs are sampled on the crossing of the positive edge of CK and negative edge of <math>\overline{CK}</math>. Output (read) data is referenced to the crossing of CK and <math>\overline{CK}</math> (both direction of crossing)</i>
F8	$\overline{CK}$	I	SSTL	
F2	CKE	I	SSTL	<b>Clock Enable</b> <i>Note: CKE HIGH activates and CKE LOW deactivates internal clock signals and device input buffers and output drivers. Taking CKE LOW provides Precharge Power-Down and Self-Refresh operation (all banks idle), or Active Power-Down (row Active in any bank). CKE is synchronous for power down entry and exit and for self-refresh entry. Input buffers excluding CKE are disabled during self-refresh. CKE is used asynchronously to detect self-refresh exit condition. Self-refresh termination itself is synchronous. After <math>V_{REF}</math> has become stable during power-on and initialisation sequence, it must be maintained for proper operation of the CKE receiver. For proper self-refresh entry and exit, <math>V_{REF}</math> must be maintained to this input. CKE must be maintained HIGH throughout read and write accesses. Input buffers, excluding CK, <math>\overline{CK}</math>, ODT and CKE are disabled during power-down</i>
<b>Clock Signals ×16 organization</b>				
J8	CK	I	SSTL	<b>Clock Signal CK, Complementary Clock Signal <math>\overline{CK}</math></b> <i>Note: See functional description in x4/x8 organization</i>
K8	$\overline{CK}$	I	SSTL	
K2	CKE	I	SSTL	<b>Clock Enable</b> <i>Note: See functional description in x4/x8 organization</i>
<b>Control Signals ×4/×8 organizations</b>				
F7	$\overline{RAS}$	I	SSTL	<b>Row Address Strobe (RAS), Column Address Strobe (CAS), Write Enable (WE)</b> <i>Note: <math>\overline{RAS}</math>, <math>\overline{CAS}</math> and <math>\overline{WE}</math> (along with <math>\overline{CS}</math>) define the command being entered.</i>
G7	$\overline{CAS}$	I	SSTL	
F3	$\overline{WE}$	I	SSTL	

**Table 5 Pin Configuration of DDR2 SDRAM**

Ball#/Pin#	Name	Pin Type	Buffer Type	Function
G8	$\overline{CS}$	I	SSTL	<b>Chip Select</b> <i>Note: All command are masked when <math>\overline{CS}</math> is registered HIGH. <math>\overline{CS}</math> provides for external rank selection on systems with multiple memory ranks. <math>\overline{CS}</math> is considered part of the command.</i>
<b>Control Signals ×16 organization</b>				
K7	$\overline{RAS}$	I	SSTL	<b>Row Address Strobe (RAS), Column Address Strobe (CAS), Write Enable (WE)</b>
L7	$\overline{CAS}$	I	SSTL	
K3	$\overline{WE}$	I	SSTL	
L8	$\overline{CS}$	I	SSTL	<b>Chip Select</b>
<b>Address Signals ×4/×8 organizations</b>				
G2	BA0	I	SSTL	<b>Bank Address Bus 1:0</b> <i>Note: BA[1:0] define to which bank an Activate, Read, Write or Precharge command is being applied. BA[1:0] also determines which (extended) mode register is to be accessed during a (E)MRS cycle</i>
G3	BA1	I	SSTL	
H8	A0	I	SSTL	<b>Address Signal 12:0, Address Signal 10/Autoprecharge</b> <i>Note: Address Signal 10/Autoprecharge provides the row address for Activate commands and the column address and Auto-Precharge bit A10 (=AP) for Read/Write commands to select one location out of the memory array in the respective bank. A10 (=AP) is sampled during a Precharge command to determine whether the Precharge applies to one bank (A10=LOW) or all banks (A10=HIGH). If only one bank is to be precharged, the bank is selected by BA[1:0]. The address inputs also provide the register value during Mode Register Set commands.</i>
H3	A1	I	SSTL	
H7	A2	I	SSTL	
J2	A3	I	SSTL	
J8	A4	I	SSTL	
J3	A5	I	SSTL	
J7	A6	I	SSTL	
K2	A7	I	SSTL	
K8	A8	I	SSTL	
K3	A9	I	SSTL	
H2	A10	I	SSTL	
	AP	I	SSTL	
K7	A11	I	SSTL	
L2	A12	I	SSTL	
L8	A13	I	SSTL	<b>Address Signal 13</b> <i>Note: x4/x8 512 Mbit components</i>
	NC	–	–	<i>Note: 256 Mbit components and x16 512 Mbit components</i>
<b>Address Signals ×16 organization</b>				
L2	BA0	I	SSTL	<b>Bank Address Bus 1:0</b>
L3	BA1	I	SSTL	
L1	NC	–	–	

**Table 5 Pin Configuration of DDR2 SDRAM**

Ball#/Pin#	Name	Pin Type	Buffer Type	Function
M8	A0	I	SSTL	<b>Address Signal 12:0, Address Signal 10/Autoprecharge</b>
M3	A1	I	SSTL	
M7	A2	I	SSTL	
N2	A3	I	SSTL	
N8	A4	I	SSTL	
N3	A5	I	SSTL	
N7	A6	I	SSTL	
P2	A7	I	SSTL	
P8	A8	I	SSTL	
P3	A9	I	SSTL	
M2	A10	I	SSTL	
	AP	I	SSTL	
P7	A11	I	SSTL	
R2	A12	I	SSTL	
<b>Data Signals ×4×8 organizations</b>				
C8	DQ0	I/O	SSTL	<b>Data Signal 3:0</b> <i>Note: Bi-directional data bus. DQ[3:0] for ×4 components, DQ[7:0] for ×8 components</i>
C2	DQ1	I/O	SSTL	
D7	DQ2	I/O	SSTL	
D3	DQ3	I/O	SSTL	
<b>Data Signals ×8 organization</b>				
D1	DQ4	I/O	SSTL	<b>Data Signal 7:4</b>
D9	DQ5	I/O	SSTL	
B1	DQ6	I/O	SSTL	
B9	DQ7	I/O	SSTL	
<b>Data Signals ×16 organization</b>				

**Table 5 Pin Configuration of DDR2 SDRAM**

Ball#/Pin#	Name	Pin Type	Buffer Type	Function
G8	DQ0	I/O	SSTL	<b>Data Signal 15:0</b> <i>Note: Bi-directional data bus. DQ[15:0] for ×16 components</i>
G2	DQ1	I/O	SSTL	
H7	DQ2	I/O	SSTL	
H3	DQ3	I/O	SSTL	
H1	DQ4	I/O	SSTL	
H9	DQ5	I/O	SSTL	
F1	DQ6	I/O	SSTL	
F9	DQ7	I/O	SSTL	
C8	DQ8	I/O	SSTL	
C2	DQ9	I/O	SSTL	
D7	DQ10	I/O	SSTL	
D3	DQ11	I/O	SSTL	
D1	DQ12	I/O	SSTL	
D9	DQ13	I/O	SSTL	
B1	DQ14	I/O	SSTL	
B9	DQ15	I/O	SSTL	

**Data Strobe ×4/×8 organisations**

B7	DQS	I/O	SSTL	<b>Data Strobe</b> <i>Note: Output with read data, input with write data. Edge aligned with read data, centered with write data. LDQS corresponds to the data on DQ[7:0]; UDQS corresponds to the data on DQ[15:8]. The datastrobes DQS, LDQS, UDQS may be used in single ended mode or paired with the optional complementary signals <math>\overline{DQS}</math>, <math>\overline{LDQS}</math>, <math>\overline{UDQS}</math> to provide differential pair signaling to the system during both reads and writes. An EMRS(1) control bit enables or disables the complementary data strobe signals. For x8 components to switch from bidirectional to unidirectional is supported and selected by EMRS(1) control bit.</i>
A8	$\overline{DQS}$	I/O	SSTL	

**Data Strobe ×8 organisations**

B3	RDQS	O	SSTL	<b>Read Data Strobe</b> <i>Note: RDQS and <math>\overline{RDQS}</math> are optional to be enabled by EMRS(1) control bits. see functional description of DM and DQS pins. Although RDQS/<math>\overline{RDQS}</math> pins are output only the loading matches the DQ and DQS loading.</i>
A2	$\overline{RDQS}$	O	SSTL	

**Data Strobe ×16 organization**

B7	UDQS	I/O	SSTL	<b>Data Strobe Upper Byte</b> <i>Note: UDQS corresponds to the data on DQ[15:8]</i>
A8	$\overline{UDQS}$	I/O	SSTL	
F7	LDQS	I/O	SSTL	<b>Data Strobe Lower Byte</b> <i>Note: LDQS corresponds to the data on DQ[7:0]</i>
E8	$\overline{LDQS}$	I/O	SSTL	

**Data Mask ×4/×8 organizations**

**Table 5 Pin Configuration of DDR2 SDRAM**

Ball#/Pin#	Name	Pin Type	Buffer Type	Function
B3	DM	I	SSTL	<b>Data Mask</b> <i>Note: DM is an input mask signal for write data. Input data is masked when DM is sampled HIGH coincident with that input data during a write access. DM is sampled on both edges of DQS. Although DM pins are input only, the DM loading matches the DQ and DQS loading. For x8 components the data mask function is disabled, if RDQS/RDQS are enabled by EMRS(1) command.</i>
<b>Data Mask x16 organization</b>				
B3	UDM	I	SSTL	<b>Data Mask Upper/Lower Byte</b> <i>Note: LDM and UDM are the input mask signals for x16 components and control the lower or upper bytes.</i>
F3	LDM	I	SSTL	
<b>Power Supplies x4/x8/x16 organizations</b>				
A9,C1,C3,C7, C9	V <sub>DDQ</sub>	PWR	–	<b>I/O Driver Power Supply</b>
A1	V <sub>DD</sub>	PWR	–	<b>Power Supply</b>
A7,B2,B8,D2, D8	V <sub>SSQ</sub>	PWR	–	<b>I/O Driver Power Supply</b>
A3,E3	V <sub>SS</sub>	PWR	–	<b>Power Supply</b>
<b>Power Supplies x4/x8 organizations</b>				
E2	V <sub>REF</sub>	AI	–	<b>I/O Reference Voltage</b>
E1	V <sub>DDL</sub>	PWR	–	<b>Power Supply</b>
E9,H9,L1	V <sub>DD</sub>	PWR	–	<b>Power Supply</b>
E7	V <sub>SSDL</sub>	PWR	–	<b>Power Supply</b>
J1,K9	V <sub>SS</sub>	PWR	–	<b>Power Supply</b>
<b>Power Supplies x16 organization</b>				
J2	V <sub>REF</sub>	AI	–	<b>I/O Reference Voltage</b>
E9, G1, G3, G7, G9	V <sub>DDQ</sub>	PWR	–	<b>I/O Driver Power Supply</b>
J1	V <sub>DDL</sub>	PWR	–	<b>Power Supply</b>
E1, J9, M9, R1	V <sub>DD</sub>	PWR	–	<b>Power Supply</b>
E7, F2, F8, H2, H8	V <sub>SSQ</sub>	PWR	–	<b>I/O Driver Power Supply</b>
J7	V <sub>SSDL</sub>	PWR	–	<b>Power Supply</b>
J3,N1,P9	V <sub>SS</sub>	PWR	–	<b>Power Supply</b>
<b>Not Connected x4/x8 organizations</b>				
G1, L3,L7, L8	NC	NC	–	<b>Not Connected</b> <i>Note: No internal electrical connection is present</i>
<b>Not Connected x4 organization</b>				
A2, B1, B9, D1, D9	NC	NC	–	<b>Not Connected</b>
<b>Not Connected x16 organization</b>				

**Table 5 Pin Configuration of DDR2 SDRAM**

Ball#/Pin#	Name	Pin Type	Buffer Type	Function
A2, E2, L1, R3, R7, R8	NC	NC	–	Not Connected
<b>Other Pins ×4/×8 organizations</b>				
F9	ODT	I	SSTL	<b>On-Die Termination Control</b> <i>Note: ODT (registered HIGH) enables termination resistance internal to the DDR2 SDRAM. When enabled, ODT is applied to each DQ, DQS, <math>\overline{DQS}</math> and DM signal for ×4 and DQ, DQS, <math>\overline{DQS}</math>, RDQS, <math>\overline{RDQS}</math> and DM for ×8 configurations. For ×16 configuration ODT is applied to each DQ, UDQS, <math>\overline{UDQS}</math>, LDQS, <math>\overline{LDQS}</math>, UDM and LDM signal. An EMRS(1) control bit enables or disables the ODT functionality.</i>
<b>Other Pins ×16 organization</b>				
K9	ODT	I	SSTL	<b>On-Die Termination Control</b>

**Table 6 Abbreviations for Pin Type**

Abbreviation	Description
I	Standard input-only pin. Digital levels.
O	Output. Digital levels.
I/O	I/O is a bidirectional input/output signal.
AI	Input. Analog levels.
PWR	Power
GND	Ground
NC	Not Connected

**Table 7 Abbreviations for Buffer Type**

Abbreviation	Description
SSTL	Serial Stub Terminated Logic (SSTL_18)
LV-CMOS	Low Voltage CMOS
CMOS	CMOS Levels
OD	Open Drain. The corresponding pin has 2 operational states, active low and tristate, and allows multiple devices to share as a wire-OR.

## 2.1 TFBGA Ball Out Diagrams

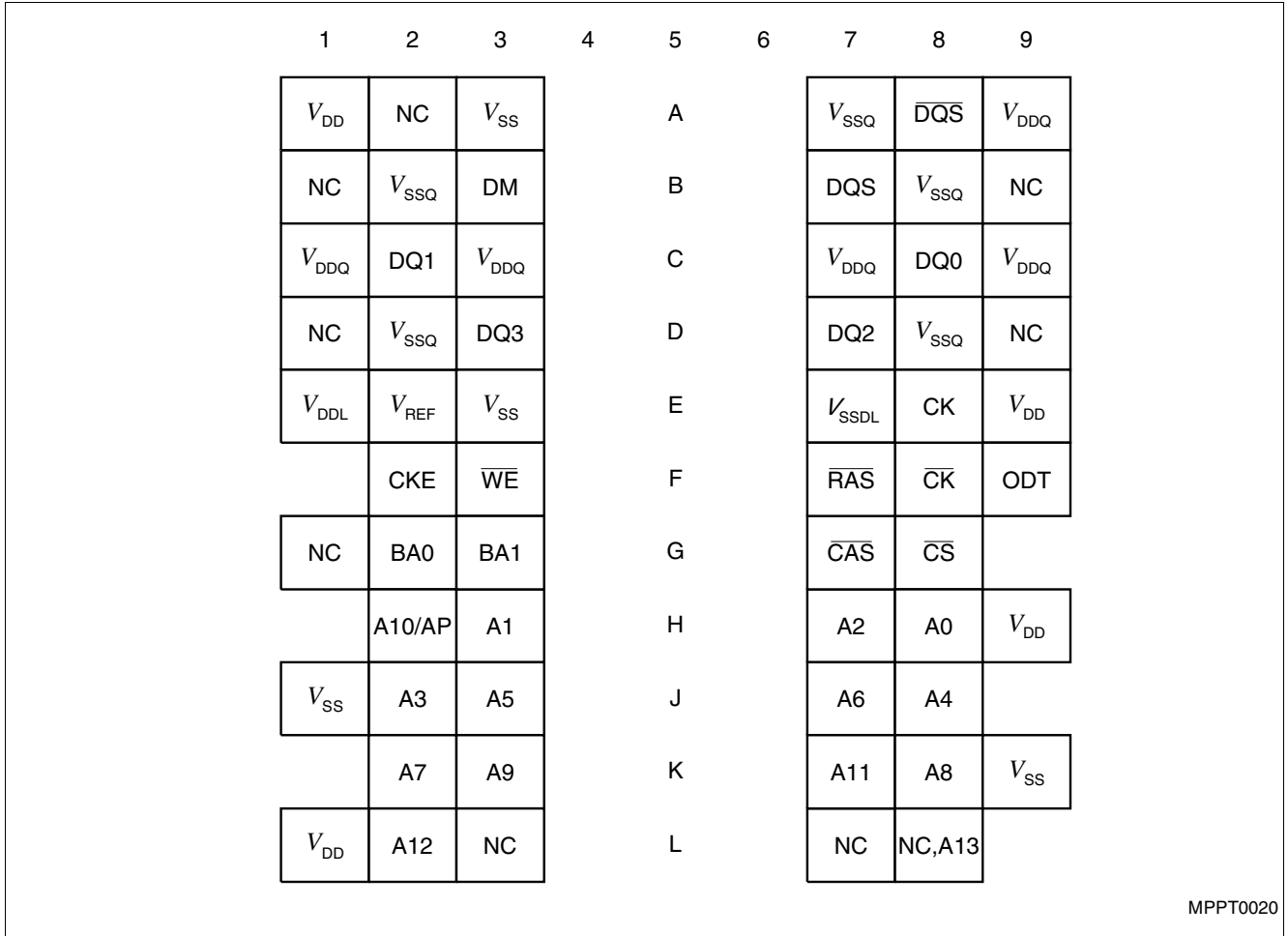


Figure 1 Pin Configuration for  $\times 4$  components, P-TFBGA-60 (top view)

### Notes

- $V_{DDL}$  and  $V_{SSDL}$  are power and ground for the DLL. They are isolated on the device from  $V_{DD}$ ,  $V_{DDQ}$ ,  $V_{SS}$ , and  $V_{SSQ}$
- Ball position L8 is A13 for 512-Mbit and is Not Connected on 256-Mbit

Pin Configuration and Block Diagrams

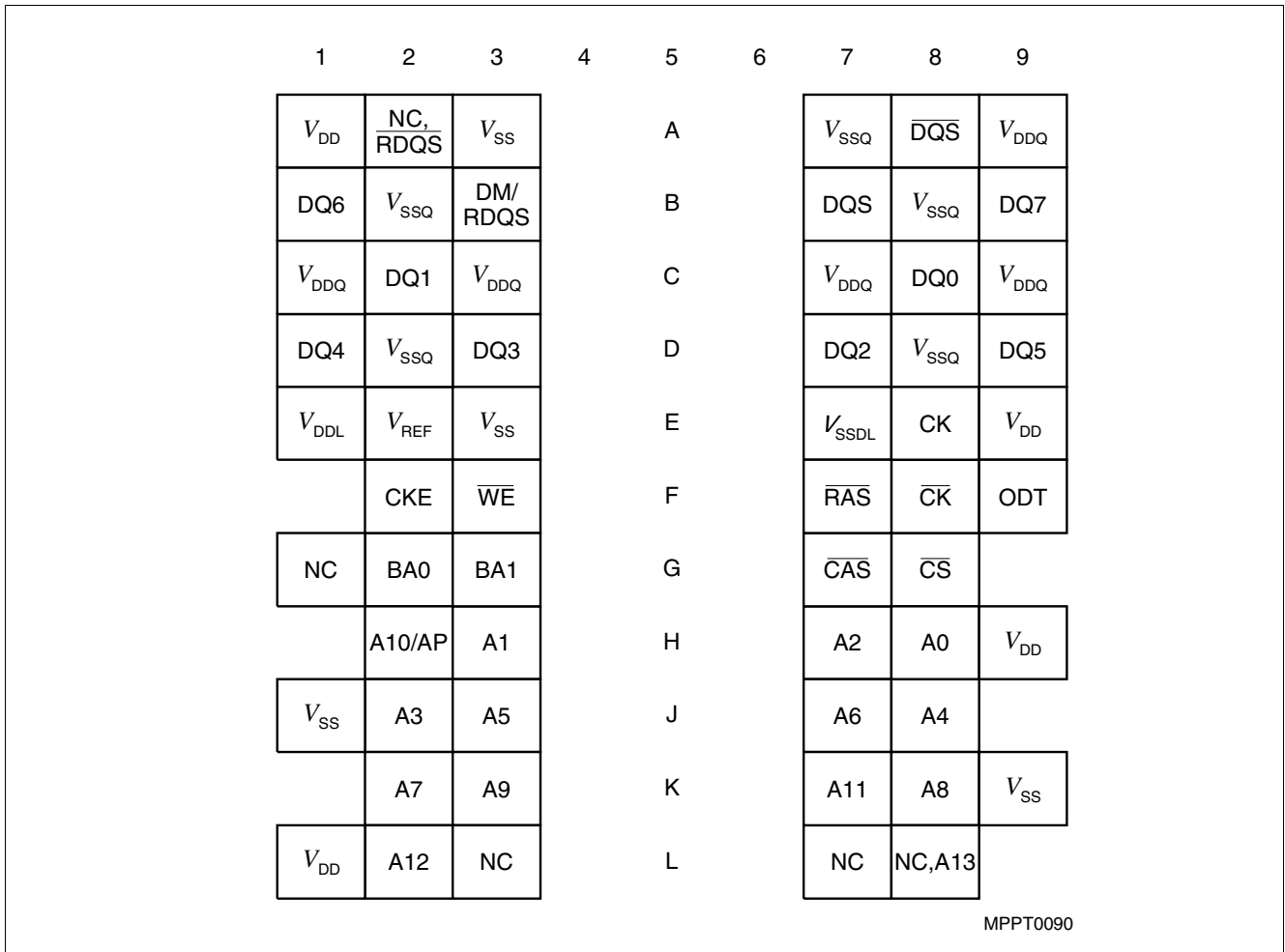


Figure 2 Pin Configuration for ×8 components, P-TFBGA-60 (top view)

**Notes**

1.  $\overline{RDQS}$  /  $\overline{RDQS}$  are enabled by EMRS(1) command.
2. If  $\overline{RDQS}$  /  $\overline{RDQS}$  is enabled, the DM function is disabled
3. When enabled,  $\overline{RDQS}$  &  $\overline{RDQS}$  are used as strobe signals during reads.
4.  $V_{DDL}$  and  $V_{SSDL}$  are power and ground for the DLL. They are isolated on the device from  $V_{DD}$ ,  $V_{DDQ}$ ,  $V_{SS}$  and  $V_{SSQ}$ .
5. Ball position L8 is A13 for 512-Mbit and is Not Connected on 256-Mbit.

Pin Configuration and Block Diagrams

1	2	3	4	5	6	7	8	9
$V_{DD}$	NC	$V_{SS}$		A		$V_{SSQ}$	$\overline{UDQS}$	$V_{DDQ}$
DQ14	$V_{SSQ}$	UDM		B		UDQS	$V_{SSQ}$	DQ15
$V_{DDQ}$	DQ9	$V_{DDQ}$		C		$V_{DDQ}$	DQ8	$V_{DDQ}$
DQ12	$V_{SSQ}$	DQ11		D		DQ10	$V_{SSQ}$	DQ13
$V_{DD}$	NC	$V_{SS}$		E		$V_{SSQ}$	$\overline{LDQS}$	$V_{DDQ}$
DQ6	$V_{SSQ}$	LDM		F		LDQS	$V_{SSQ}$	DQ7
$V_{DDQ}$	DQ1	$V_{DDQ}$		G		$V_{DDQ}$	DQ0	$V_{DDQ}$
DQ4	$V_{SSQ}$	DQ3		H		DQ2	$V_{SSQ}$	DQ5
$V_{DDL}$	$V_{REF}$	$V_{SS}$		J		VSSDL	CK	$V_{DD}$
	CKE	$\overline{WE}$		K		$\overline{RAS}$	$\overline{CK}$	ODT
NC	BA0	BA1		L		$\overline{CAS}$	$\overline{CS}$	
	A10/AP	A1		M		A2	A0	$V_{DD}$
$V_{SS}$	A3	A5		N		A6	A4	
	A7	A9		P		A11	A8	$V_{SS}$
$V_{DD}$	A12	NC		R		NC	NC	

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Figure 3 Pin Configuration for  $\times 16$  components, P-TFBGA-84 (top view)

Notes

1.  $\overline{UDQS}/UDQS$  is data strobe for DQ[15:8],  
 $\overline{LDQS}/LDQS$  is data strobe for DQ[7:0]
2. LDM is the data mask signal for DQ[7:0], UDM is the data mask signal for DQ[15:8]
3.  $V_{DDL}$  and  $V_{DDSL}$  are power and ground for the DLL. They are isolated on the device from  $V_{DD}$ ,  $V_{DDQ}$ ,  $V_{SS}$  and  $V_{SSQ}$ .

## 2.2 256 Mbit DDR2 Addressing

**Table 8 256-Mbit DDR2 Addressing**

Configuration	64-Mbit x 4	32-Mbit x 8	16-Mbit x 16	Notes
Bank Address	BA[1:0]	BA[1:0]	BA[1:0]	
Number of Banks	4	4	4	
Auto-Precharge	A10 / AP	A10 / AP	A10 / AP	
Row Address	A[12:0]	A[12:0]	A[12:0]	
Column Address	A11, A[9:0]	A[9:0]	A[8:0]	
Number of Column Address Bits	11	10	9	1)
Number of I/Os	4	8	16	2)
Page Size [Bytes]	1024 (1K)	1024 (1K)	1024 (1K)	3)

1) Referred to as 'colbits'

2) Referred to as 'org'

3) PageSize =  $2^{\text{colbits}} \times \text{org} / 8$  [Bytes]

### 2.3 Block Diagrams

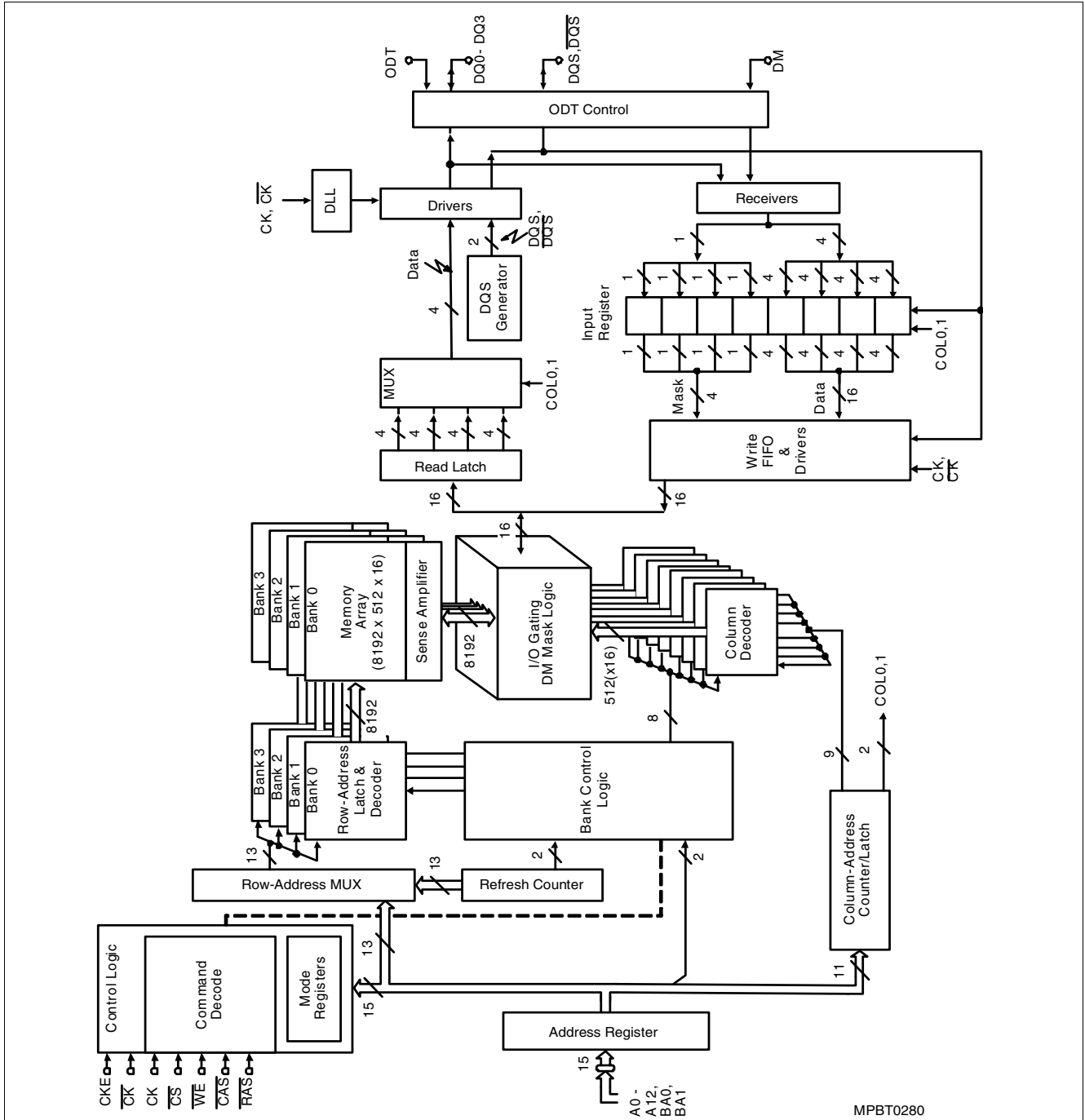


Figure 4 Block Diagram 16 Mbit  $\times 4$  I/O  $\times 4$  Internal Memory Banks

**Notes**

1. 64Mb  $\times 4$  Organisation with 13 Row, 2 Bank and 11 Column External Addresses
2. This Functional Block Diagram is intended to facilitate user understanding of the operation of the

device; it does not represent an actual circuit implementation.

3. LDM, UDM is a unidirectional signal (input only), but is internally loaded to match the load of the bidirectional LDQS and UDQS signals.

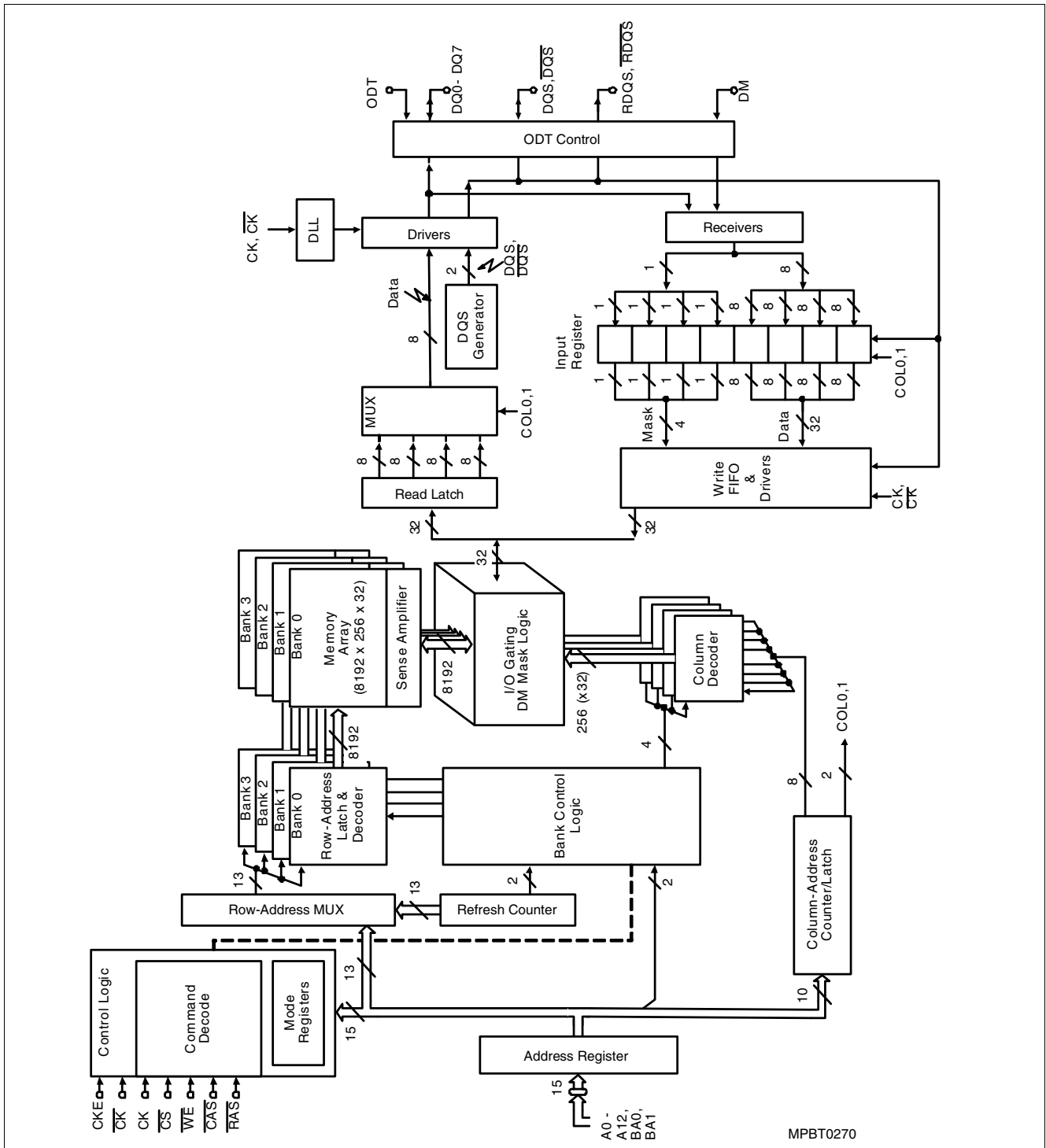


Figure 5 Block Diagram 8 Mbit  $\times$  8 I/O  $\times$  4 Internal Memory Banks

**Notes**

1. 32Mb  $\times$  8 Organisation with 13 Row, 2 Bank and 10 Column External Addresses
2. This Functional Block Diagram is intended to facilitate user understanding of the operation of the

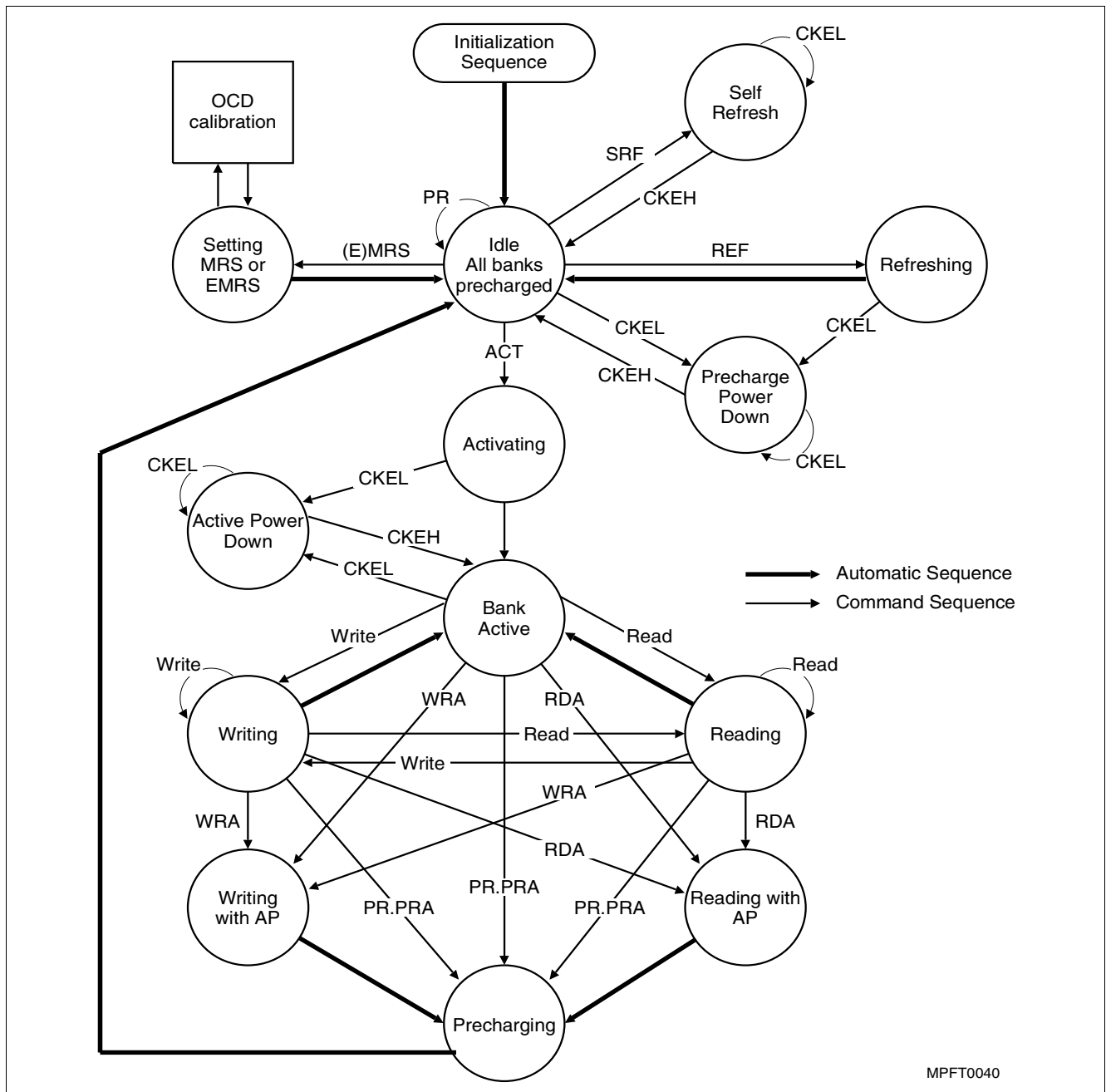
device; it does not represent an actual circuit implementation.

3. LDM, UDM is a unidirectional signal (input only), but is internally loaded to match the load of the bidirectional LDQS and UDQS signals.



### 3 Functional Description

#### 3.1 Simplified State Diagram



**Figure 7 Simplified State Diagram**

Note: This Simplified State Diagram is intended to provide a floorplan of the possible state transitions and the commands to control them. In particular situations involving more than one

bank, enabling / disabling on-die termination, Power-Down entry / exit, timing restrictions during state transitions - among other things - are not captured in full detail.

### 3.2 Basic Functionality

Read and write accesses to the DDR2 SDRAM are burst oriented; accesses start at a selected location and continue for the burst length of four or eight in a programmed sequence. Accesses begin with the registration of an Activate command, which is followed by a Read or Write command. The address bits registered coincident with the activate command are used to select the bank and row to be accessed. The

address bits registered coincident with the Read or Write command are used to select the starting column location for the burst access and to determine if the Auto-Precharge command is to be issued. Prior to normal operation, the DDR2 SDRAM must be initialized. The following sections provide detailed information covering device initialization, register definition, command description and device operation.

### 3.3 Power On and Initialization

DDR2 SDRAM's must be powered up and initialized in a predefined manner. Operational procedures other than those specified may result in undefined operation.

#### Power-up and Initialization Sequence

The following sequence is required for POWER UP and Initialization.

1. Apply power and attempt to maintain CKE below  $0.2 \times V_{DDQ}$  and ODT at a low state (all other inputs may be undefined). To guarantee ODT off,  $V_{REF}$  must be valid and a low-level must be applied to the ODT pin. Maximum power up interval for  $V_{DD} / V_{DDQ}$  is specified as 20.0 ms. The power interval is defined as the amount of time it takes for  $V_{DD} / V_{DDQ}$  to power-up from 0 V to  $1.8 V \pm 100 mV$ . At least one of these two sets of conditions must be met:
  - $V_{DD}$ ,  $V_{DDL}$  and  $V_{DDQ}$  are driven from a single power converter output, AND
  - $V_{TT}$  is limited to 0.95 V max, AND
  - $V_{REF}$  tracks  $V_{DDQ}/2$
 or
  - Apply  $V_{DD}$  before or at the same time as  $V_{DDL}$ .
  - Apply  $V_{DDL}$  before or at the same time as  $V_{DDQ}$ .
  - Apply  $V_{DDQ}$  before or at the same time as  $V_{TT}$  &  $V_{REF}$ .
2. Start clock (CK,  $\overline{CK}$ ) and maintain stable power and clock condition for a minimum of 200  $\mu s$ .
3. Apply NOP or Deselect commands and take CKE high.
4. Continue NOP or Deselect Commands for 400 ns, then issue a Precharge All command.
5. Issue EMRS(2) command.
6. Issue EMRS(3) command.
7. Issue EMRS(1) command to enable DLL.
8. Issue a MRS command for "DLL reset".
9. Issue Precharge-all command.
10. Issue 2 or more Auto-refresh commands.
11. Issue the final MRS command to turn the DLL on and to set the necessary operating parameter.
12. At least 200 clocks after step 8, issue EMRS(1) commands to either execute the OCD calibration or select the OCD default. Issue the final EMRS(1) command to exit OCD calibration mode and set the necessary operating parameters.
13. The DDR2 SDRAM is now ready for normal operation.

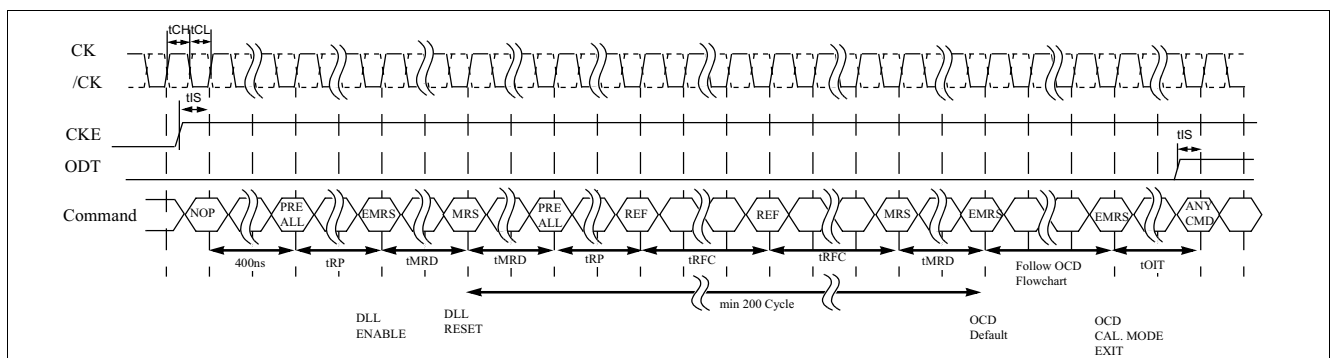


Figure 8 Initialization Sequence after Power up

### 3.4 Programming the Mode Register and Extended Mode Registers

For application flexibility, burst length, burst type,  $\overline{\text{CAS}}$  latency, DLL reset function, write recovery time (WR) are user defined variables and must be programmed with a Mode Register Set (MRS) command. Additionally, DLL disable function, additive  $\overline{\text{CAS}}$  latency, driver impedance, On Die Termination (ODT), single-ended strobe and Off Chip Driver impedance adjustment (OCD) are also user defined variables and must be programmed with an Extended Mode Register Set (EMRS) command. Contents of the Mode Register (MR) or Extended Mode Registers (EMR(1, 2, 3)) can be altered by re-executing the MRS and EMRS Commands. If the user chooses to modify only a subset of the MR or EMR variables, all variables must be redefined when the MRS or EMRS commands are issued. After initial power up, all MRS and EMRS Commands must be issued before read or write cycles

may begin. All banks must be in a precharged state and CKE must be high at least one cycle before the Mode Register Set Command can be issued. Either MRS or EMRS Commands are activated by the low signals of  $\overline{\text{CS}}$ ,  $\overline{\text{RAS}}$ ,  $\overline{\text{CAS}}$  and  $\overline{\text{WE}}$  at the positive edge of the clock. When both bank addresses BA[1:0] are 0, the DDR2 SDRAM enables the MRS command. When the bank addresses BA0 is 1 and BA1 is 0, the DDR2 SDRAM enables the EMRS(1) command. The address input data during this cycle defines the parameters to be set as shown in the MRS and EMRS tables. A new command may be issued after the mode register set command cycle time ( $t_{\text{MRD}}$ ). MRS, EMRS and DLL Reset do not affect array contents, which means reinitialization including those can be executed any time after power-up without affecting array contents.

### 3.5 DDR2 SDRAM Mode Register Set (MRS)

The mode register stores the data for controlling the various operating modes of DDR2 SDRAM. It programs CAS latency, burst length, burst sequence, test mode, DLL reset, Write Recovery (WR) and various vendor specific options to make DDR2 SDRAM useful for various applications. The default value of the mode register is not defined, therefore the mode register must be written after power-up for proper operation. The mode register is written by asserting low on  $\overline{CS}$ ,  $\overline{RAS}$ ,  $\overline{CAS}$ ,  $\overline{WE}$ , BA[1:0], while controlling the state of address pins A[12:0]. The DDR2 SDRAM should be in all bank precharged (idle) mode with CKE already high prior to writing into the mode register. The mode register set command cycle time ( $t_{MRD}$ ) is required to complete the write operation to the mode register. The mode register contents can be changed using the same

command and clock cycle requirements during normal operation as long as all banks are in the precharged state. The mode register is divided into various fields depending on functionality. Burst length is defined by A[2:0] with options of 4 and 8 bit burst length. Burst address sequence type is defined by A3 and CAS latency is defined by A[6:4]. A7 is used for test mode and must be set to 0 for normal DRAM operation. A8 is used for DLL reset. A[11:9] are used for write recovery time (WR) definition for Auto-Precharge mode. With address bit A12 two Power-Down modes can be selected, a “standard mode” and a “low-power” Power-Down mode, where the DLL is disabled. Address bit A13 and all “higher” address bits have to be set to 0 for compatibility with other DDR2 memory products with higher memory densities.

BA2	BA1	BA0	A13	A12	A11	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0
0	0	0	0	PD		WR		DLL	TM		CL		BT		BL	
reg. addr				w		w		w	w		w		w		w	

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**Table 9 Mode Register Definition (BA[2:0] = 000B)**

Field	Bits	Type <sup>1)</sup>	Description
BA2	16	reg. addr.	<b>Bank Address [2]</b> <i>Note: BA2 not available on 256 Mbit and 512 Mbit components</i> $0_B$ <b>BA2</b> , Bank Address
BA1	15		<b>Bank Address [1]</b> $0_B$ <b>BA1</b> , Bank Address
BA0	14		<b>Bank Address [0]</b> $0_B$ <b>BA0</b> , Bank Address
A13	13		<b>Address Bus[13]</b> <i>Note: A13 is not available for 256 Mbit and x16 512 Mbit configuration</i> $0_B$ <b>A13</b> , Address bit 13
PD	12	w	<b>Active Power-Down Mode Select</b> $0_B$ <b>PD</b> , Fast exit $1_B$ <b>PD</b> , Slow exit

**Table 9 Mode Register Definition (BA[2:0] = 000B) (cont'd)**

Field	Bits	Type <sup>1)</sup>	Description
WR	[11:9]	w	<b>Write Recovery<sup>2)</sup></b> <i>Note: All other bit combinations are illegal.</i> 001 <sub>B</sub> <b>WR</b> , 2 010 <sub>B</sub> <b>WR</b> , 3 011 <sub>B</sub> <b>WR</b> , 4 100 <sub>B</sub> <b>WR</b> , 5 101 <sub>B</sub> <b>WR</b> , 6
DLL	8	w	<b>DLL Reset</b> 0 <sub>B</sub> <b>DLL</b> , No 1 <sub>B</sub> <b>DLL</b> , Yes
TM	7	w	<b>Test Mode</b> 0 <sub>B</sub> <b>TM</b> , Normal Mode 1 <sub>B</sub> <b>TM</b> , Vendor specific test mode
CL	[6:4]	w	<b>CAS Latency</b> <i>Note: All other bit combinations are illegal.</i> 010 <sub>B</sub> <b>CL</b> , 2 <sup>3)</sup> 011 <sub>B</sub> <b>CL</b> , 3 100 <sub>B</sub> <b>CL</b> , 4 101 <sub>B</sub> <b>CL</b> , 5 110 <sub>B</sub> <b>CL</b> , 6
BT	3	w	<b>Burst Type</b> 0 <sub>B</sub> <b>BT</b> , Sequential 1 <sub>B</sub> <b>BT</b> , Interleaved
BL	[2:0]	w	<b>Burst Length</b> <i>Note: All other bit combinations are illegal.</i> 010 <sub>B</sub> <b>BL</b> , 4 011 <sub>B</sub> <b>BL</b> , 8

1) w = write only register bits

2) Number of clock cycles for write recovery during auto-precharge. WR in clock cycles is calculated by dividing  $t_{WR}$  (in ns) by  $t_{CK}$  (in ns) and rounding up to the next integer:  $WR [cycles] \geq t_{WR} (ns) / t_{CK} (ns)$ . The mode register must be programmed to fulfill the minimum requirement for the analogue  $t_{WR}$  timing  $WR_{MIN}$  is determined by  $t_{CK,MAX}$  and  $WR_{MAX}$  is determined by  $t_{CK,MIN}$ .

3) Implemented but not tested

### 3.6 DDR2 SDRAM Extended Mode Register Set EMR(1)

The Extended Mode Register EMR(1) stores the data for enabling or disabling the DLL, output driver strength, additive latency, OCD program, ODT, DQS and output buffers disable, RQDS and RDQS enable. The default value of the extended mode register

EMR(1) is not defined, therefore the extended mode register must be written after power-up for proper operation. The extended mode register is written by asserting low on CS, RAS, CAS, WE, BA1 and high on BA0, while controlling the state of the address pins

BA2	BA1	BA0	A13	A12	A11	A10	A9	A8	A7	A6	A5	A4	A3	A2	A1	A0
0	0	1	0	Q <sub>off</sub>	RDQS	$\overline{\text{DQS}}$	OCD Program			R <sub>#</sub>		AL		R <sub>#</sub>	DIC	DLL
reg. addr					W	W		W		W		W		W	W	W

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**Table 10 Extended Mode Register Definition (BA[2:0] = 001B)**

Field	Bits	Type <sup>1)</sup>	Description
BA2	16	reg. addr.	<b>Bank Address [2]</b> <i>Note: BA2 not available on 256 Mbit and 512 Mbit components</i> 0 <sub>B</sub> <b>BA2</b> , Bank Address
BA1	15		<b>Bank Address [1]</b> 0 <sub>B</sub> <b>BA1</b> , Bank Address
BA0	14		<b>Bank Address [0]</b> 0 <sub>B</sub> <b>BA0</b> , Bank Address
A13	13	w	<b>Address Bus[13]</b> <i>Note: A13 is not available for 256 Mbit and x16 512 Mbit configuration</i> 0 <sub>B</sub> <b>A13</b> , Address bit 13
Qoff	12		<b>Output Disable</b> 0 <sub>B</sub> <b>QOff</b> , Output buffers enabled 1 <sub>B</sub> <b>QOff</b> , Output buffers disabled
RDQS	11		<b>Read Data Strobe Output (RDQS, RDQS)</b> 0 <sub>B</sub> <b>RDQS</b> , Disable 1 <sub>B</sub> <b>RDQS</b> , Enable
$\overline{\text{DQS}}$	10		<b>Complement Data Strobe (DQS Output)</b> 0 <sub>B</sub> <b><math>\overline{\text{DQS}}</math></b> , Enable 1 <sub>B</sub> <b>DQS</b> , Disable
OCD Program	[9:7]		<b>Off-Chip Driver Calibration Program</b> 000 <sub>B</sub> <b>OCD</b> , OCD calibration mode exit, maintain setting 001 <sub>B</sub> <b>OCD</b> , Drive (1) 010 <sub>B</sub> <b>OCD</b> , Drive (0) 100 <sub>B</sub> <b>OCD</b> , Adjust mode 111 <sub>B</sub> <b>OCD</b> , OCD calibration default

**Table 10** Extended Mode Register Definition (BA[2:0] = 001B) (cont'd)

Field	Bits	Type <sup>1)</sup>	Description
AL	[5:3]		<b>Additive Latency</b> <i>Note: All other bit combinations are illegal.</i> 000 <sub>B</sub> AL, 0 001 <sub>B</sub> AL, 1 010 <sub>B</sub> AL, 2 011 <sub>B</sub> AL, 3 100 <sub>B</sub> AL, 4 101 <sub>B</sub> AL, 5
R <sub>TT</sub>	6,2		<b>Nominal Termination Resistance of ODT</b> <i>Note: See <a href="#">Table 27 “ODT DC Electrical Characteristics” on Page 77</a></i> 00 <sub>B</sub> R <sub>TT</sub> , ∞ (ODT disabled) 01 <sub>B</sub> R <sub>TT</sub> , 75 Ohm 10 <sub>B</sub> R <sub>TT</sub> , 150 Ohm 11 <sub>B</sub> R <sub>TT</sub> , 50 Ohm
DIC	1		<b>Off-chip Driver Impedance Control</b> 0 <sub>B</sub> DIC, Full (Driver Size = 100%) 1 <sub>B</sub> DIC, Reduced
DLL	0		<b>DLL Enable</b> 0 <sub>B</sub> DLL, Enable 1 <sub>B</sub> DLL, Disable

1) w = write only register bits

A0 is used for DLL enable or disable. A1 is used for enabling half-strength data-output driver. A2 and A6 enables On-Die termination (ODT) and sets the R<sub>tt</sub> value. A[5:3] are used for additive latency settings and A[9:7] enables the OCD impedance adjustment mode. A10 enables or disables the differential DQS and RDQS signals, A11 disables or enables RDQS.

Address bit A12 have to be set to 0 for normal operation. With A12 set to 1 the SDRAM outputs are disabled and in Hi-Z. 1 on BA0 and 0 for BA1 have to be set to access the EMRS(1). A13 and all “higher” address bits have to be set to 0 for compatibility with other DDR2 memory products with higher memory densities. Refer to Extended Mode Register Definition.

### 3.7 DLL Enable/Disable

The DLL must be enabled for normal operation. DLL enable is required during power up initialization, and upon returning to normal operation after having the DLL disabled. The DLL is automatically disabled when entering Self-Refresh operation and is automatically re-enabled and reset upon exit of Self-Refresh operation.

Any time the DLL is reset, 200 clock cycles must occur before a Read command can be issued to allow time for the internal clock to be synchronized with the external clock. Failing to wait for synchronization to occur may result in a violation of the  $t_{AC}$  or  $t_{DQSCK}$  parameters.

### 3.8 Output Disable (Qoff)

Under normal operation, the DRAM outputs are enabled during Read operation for driving data (Qoff bit in the EMR(1) is set to 0). When the Qoff bit is set to 1, the DRAM outputs will be disabled. Disabling the

DRAM outputs allows users to measure  $I_{DD}$  currents during Read operations, without including the output buffer current and external load currents.

### 3.9 Single-ended and Differential Data Strobe Signals

**Table 11** lists all possible combinations for DQS,  $\overline{\text{DQS}}$ , RDQS,  $\overline{\text{RDQS}}$  which can be programmed by A[11:10] address bits in EMRS. RDQS and  $\overline{\text{RDQS}}$  are available in  $\times 8$  components only. If RDQS is enabled in  $\times 8$  components, the DM function is disabled. RDQS is active for reads and don't care for writes.

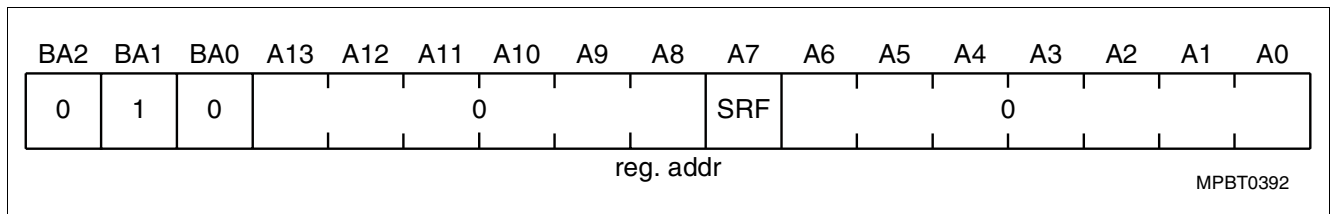
**Table 11 Single-ended and Differential Data Strobe Signals**

EMRS(1)		Strobe Function Matrix				Signaling
A11 (RDQS Enable)	A10 (DQS Enable)	RDQS/DM	RDQS	DQS	$\overline{\text{DQS}}$	
0 (Disable)	0 (Enable)	DM	Hi-Z	DQS	$\overline{\text{DQS}}$	differential DQS signals
0 (Disable)	1 (Disable)	DM	Hi-Z	DQS	Hi-Z	single-ended DQS signals
1 (Enable)	0 (Enable)	RDQS	$\overline{\text{RDQS}}$	DQS	$\overline{\text{DQS}}$	differential DQS signals
1 (Enable)	1 (Disable)	RDQS	Hi-Z	DQS	Hi-Z	single-ended DQS signals

### 3.10 Extended Mode Register EMR(2)

The Extended Mode Registers EMR(2) and EMR(3) are reserved for future use and must be programmed when setting the mode register during initialization. The extended mode register EMR(2) is written by asserting LOW on CS, RAS, CAS, WE, BA0 and HIGH on BA1, while controlling the states of the address pins. The DDR2 SDRAM should be in all bank precharge with

CKE already high prior to writing into the extended mode register. The mode register set command cycle time ( $t_{MRD}$ ) must be satisfied to complete the write operation to the EMR(2). Mode register contents can be changed using the same command and clock cycle requirements during normal operation as long as all banks are in precharge state.



**Table 12 EMRS(2) Programming Extended Mode register Definition (BA[2:0]=010<sub>B</sub>)**

Field	Bits	Type <sup>1)</sup>	Description
BA2	16	reg.addr	<b>Bank Address[2]</b> <i>Note: BA2 is not available on 256Mbit and 512Mbit components</i> 0 <sub>B</sub> BA2, Bank Address
BA1	15		<b>Bank Address[1]</b> 1 <sub>B</sub> BA1, Bank Address
BA0	14		<b>Bank Address[0]</b> 0 <sub>B</sub> BA0, Bank Address
A	[13:8]	w	<b>Address Bus[13:8]</b> <i>Note: A13 is not available for 256 Mbit and x16 512 Mbit configuration</i> 0 <sub>B</sub> A[13:8], Address bits

**Table 12 EMRS(2) Programming Extended Mode register Definition (BA[2:0]=010<sub>B</sub>) (cont'd)**

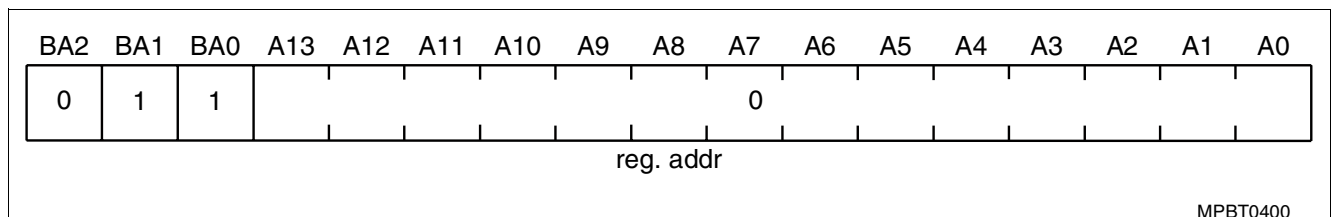
Field	Bits	Type <sup>1)</sup>	Description
SRF	[7]	w	<b>Address Bus[7]</b> <i>Note: When DRAM is operated at 85 °C ≤ T<sub>CASE</sub> &lt; 95 °C the extended self refresh rate must be enabled by setting bit A7 to "1" before the self refresh mode can be entered.</i>  0 <sub>B</sub> <b>A7</b> , disable 1 <sub>B</sub> <b>A7</b> , enable, adapted self refresh rate for T <sub>CASE</sub> > 85 °C
A	[6:0]	w	<b>Address Bus[6:0]</b> 0 <sub>B</sub> <b>A[6:0]</b> , Address bits

1) w = write only

### 3.11 Extended Mode Register EMR(3)

The Extended Mode Register EMR(3) is reserved for future use and all bits except BA0 and BA1 must be programmed to 0 when setting the mode register during

initialization. The EMRS(3) is written by asserting low on CS, RAS, CAS, WE, BA2 and high on BA0 and BA1, while controlling the state of the address pins.



**Table 13 EMR(3) Programming Extended Mode Register Definition (BA[2:0]=010<sub>B</sub>)**

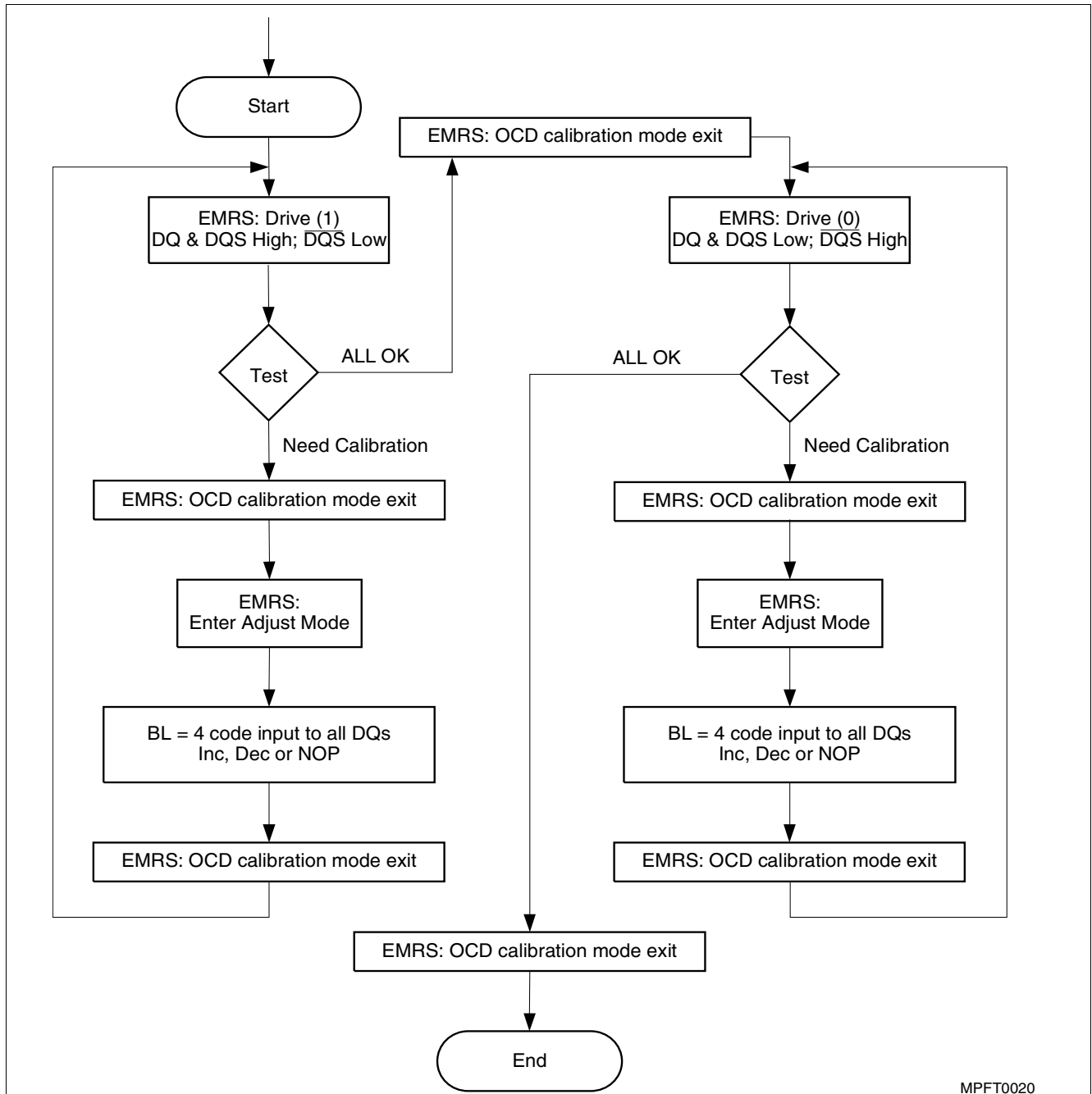
Field	Bits	Type <sup>1)</sup>	Description
BA2	16	reg.addr	<b>Bank Address[2]</b> <i>Note: BA2 is not available on 256Mbit and 512Mbit components</i>  0 <sub>B</sub> <b>BA2</b> , Bank Address
BA1	15		<b>Bank Address[1]</b> 1 <sub>B</sub> <b>BA1</b> , Bank Address
BA0	14		<b>Bank Address[0]</b> 1 <sub>B</sub> <b>BA0</b> , Bank Address
A	[13:0]	w	<b>Address Bus[13:0]</b> <i>Note: A13 is not available for 256 Mbit and x16 512 Mbit configuration</i>  0 <sub>B</sub> <b>A[13:0]</b> , Address bits

1) w = write only

### 3.12 Off-Chip Driver (OCD) Impedance Adjustment

DDR2 SDRAM supports driver calibration feature and the flow chart below is an example of the sequence. Every calibration mode command should be followed by "OCD calibration mode exit" before any other

command being issued. MRS should be set before entering OCD impedance adjustment and On Die Termination (ODT) should be carefully controlled depending on system environment.



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**Figure 9** OCD Impedance Adjustment Flow Chart

*Note: MR should be set before entering OCD impedance adjustment and ODT should be carefully controlled depending on system environment*

**Extended Mode Register Set for OCD impedance adjustment**

OCD impedance adjustment can be done using the following EMRS(1) mode. In drive mode all outputs are driven out by DDR2 SDRAM and drive of RDQS is dependent on EMR(1) bit enabling RDQS operation. In Drive(1) mode, all DQ, DQS (and RDQS) signals are driven HIGH and all DQS (and RDQS) signals are driven LOW. In Drive(0) mode, all DQ, DQS (and RDQS) signals are driven LOW and all DQS (and RDQS) signals are driven HIGH. In adjust mode, BL = 4 of operation code data must be used. In case of OCD calibration default, output driver characteristics have a nominal impedance value of 18 Ohms during nominal

temperature and voltage conditions. Output driver characteristics for OCD calibration default are specified in the following table. OCD applies only to normal full strength output drive setting defined by EMR(1) and if half strength is set, OCD default driver characteristics are not applicable. When OCD calibration adjust mode is used, OCD default output driver characteristics are not applicable. After OCD calibration is completed or driver strength is set to default, subsequent EMRS(1) commands not intended to adjust OCD characteristics must specify A[9:7] as '000' in order to maintain the default or calibrated value.

**Table 14 Off Chip Driver Program**

A9	A8	A7	Operation
0	0	0	OCD calibration mode exit
0	0	1	Drive(1) DQ, DQS, (RDQS) high and <u>DQS</u> ( <u>RDQS</u> ) low
0	1	0	Drive(0) DQ, DQS, (RDQS) low and <u>DQS</u> ( <u>RDQS</u> ) high
1	0	0	Adjust mode
1	1	1	OCD calibration default

**OCD impedance adjust**

To adjust output driver impedance, controllers must issue the ADJUST EMRS(1) command along with a 4 bit burst code to DDR2 SDRAM as in the following table. For this operation, Burst Length has to be set to BL = 4 via MRS command before activating OCD and controllers must drive the burst code to all DQs at the same time. DT0 in the table means all DQ bits at bit time 0, DT1 at bit time 1, and so forth. The driver output impedance is adjusted for all DDR2 SDRAM DQs

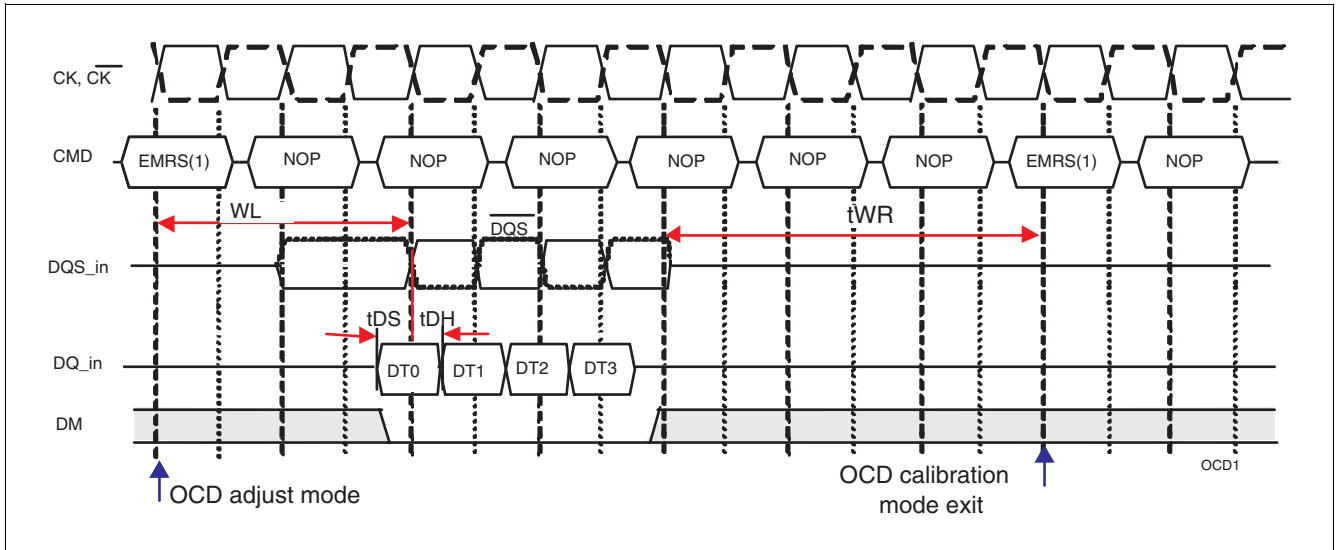
simultaneously and after OCD calibration, all DQs of a given DDR2 SDRAM will be adjusted to the same driver strength setting. The maximum step count for adjustment is 16 and when the limit is reached, further increment or decrement code has no effect. The default setting may be any step within the maximum step count range. When Adjust mode command is issued, AL from previously set value must be applied.

**Table 15 Off-Chip-Driver Adjust Program**

4 bit burst code inputs to all DQs				Operation	
DT0	DT1	DT2	DT3	Pull-up driver strength	Pull-down driver strength
0	0	0	0	NOP (no operation)	NOP (no operation)
0	0	0	1	Increase by 1 step	NOP
0	0	1	0	Decrease by 1 step	NOP
0	1	0	0	NOP	Increase by 1 step
1	0	0	0	NOP	Decrease by 1 step
0	1	0	1	Increase by 1 step	Increase by 1 step
0	1	1	0	Decrease by 1 step	Increase by 1 step
1	0	0	1	Increase by 1 step	Decrease by 1 step
1	0	1	0	Decrease by 1 step	Decrease by 1 step
Other Combinations				Illegal	

For proper operation of adjust mode,  $WL = RL - 1 = AL + CL - 1$  clocks and  $t_{DS} / t_{DH}$  should be met as shown in **Figure 10**. Input data pattern for adjustment, DT[0:3] is fixed and not affected by MRS addressing mode (i.e.

sequential or interleave). Burst length of 4 have to be programmed in the MRS for OCD impedance adjustment.

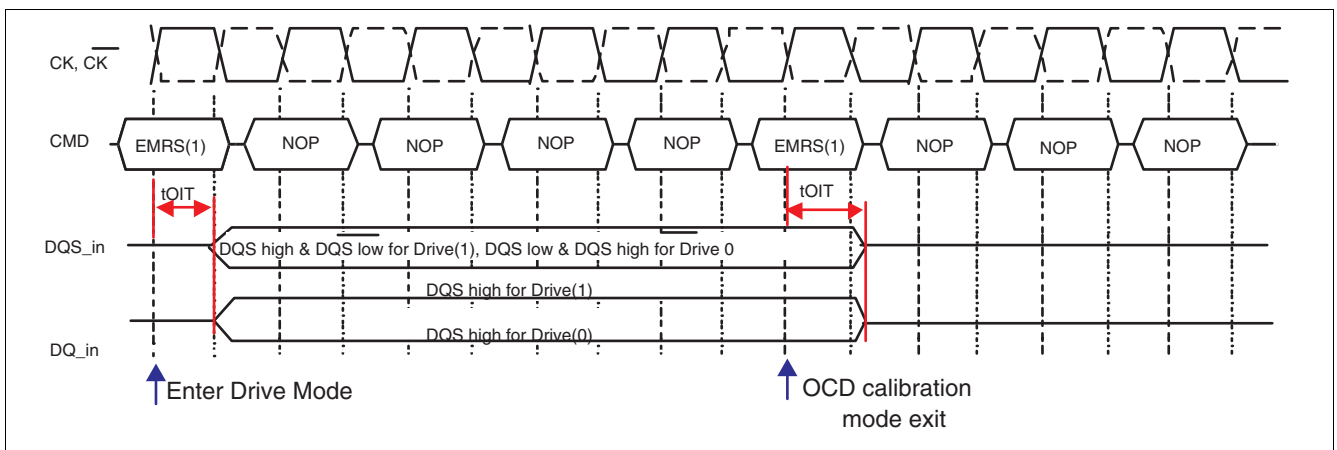


**Figure 10 Timing Diagram Adjust Mode**

**Drive Mode**

Both Drive(1) and Drive(0) are used for controllers to measure DDR2 SDRAM Driver impedance before OCD impedance adjustment. In this mode, all outputs are

driven out  $t_{OIT}$  after “enter drive mode” command and all output drivers are turned-off  $t_{OIT}$  after “OCD calibration mode exit” command. See **Figure 11**.



**Figure 11 Timing Diagram Drive Mode**

### 3.13 On-Die Termination (ODT)

On-Die Termination (ODT) is a new feature on DDR2 components that allows a DRAM to turn on/off termination resistance for each DQ, DQS,  $\overline{DQS}$ , DM for  $\times 4$  and DQ, DQS,  $\overline{DQS}$ , DM, RDQS (DM/RDQS share the same pin) and  $\overline{RDQS}$  for  $\times 8$  configuration via the ODT control pin. DQS and RDQS are only terminated when enabled by EMR(1).

For  $\times 16$  configuration ODT is applied to each DQ, UDQS,  $\overline{UDQS}$ , LDQS,  $\overline{LDQS}$ , UDM and LDM signal via

the ODT control pin.  $\overline{UDQS}$  and LDQS are terminated only when enabled in the EMRS(1) by address bit A10 = 0.

The ODT feature is designed to improve signal integrity of the memory channel by allowing the DRAM controller to independently turn on/off termination resistance for any or all DRAM devices. The ODT function can be used for all active and standby modes. ODT is turned off and not supported in Self-Refresh mode.

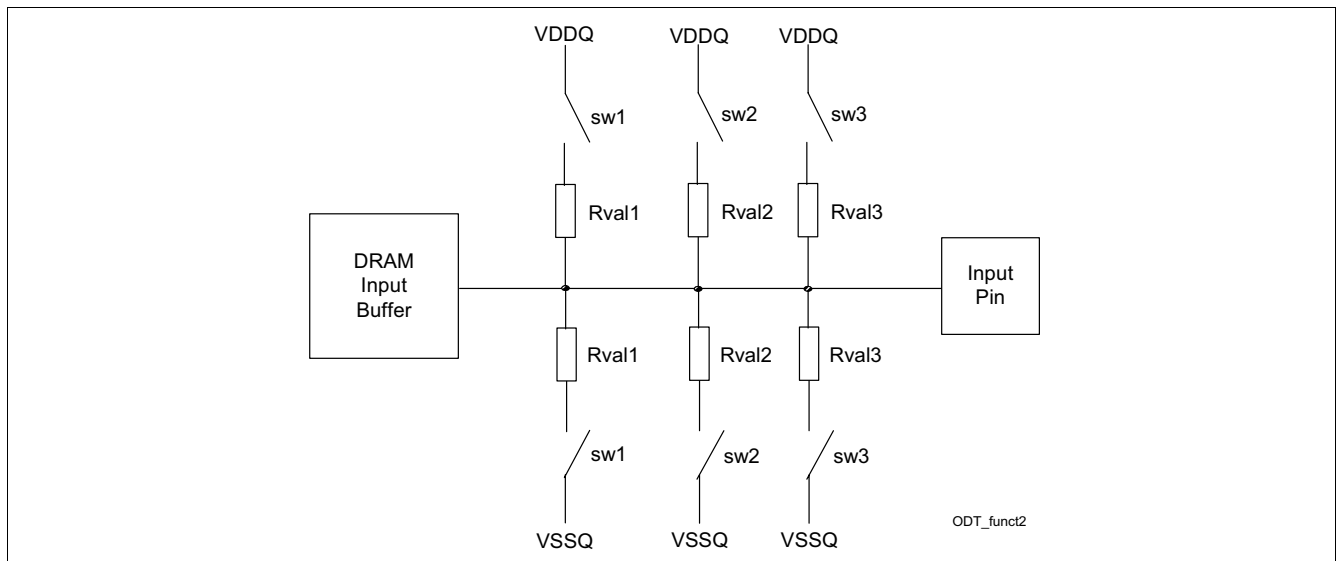


Figure 12 Functional Representation of ODT

Switch sw1, sw2 or sw3 are enabled by the ODT pin. Selection between sw1, sw2 or sw3 is determined by "Rtt (nominal)" in EMRS(1) address bits A6 & A2.

Target:  $Rval1 = Rval2 = Rval3 = 2 \times R_{tt}$

The ODT pin will be ignored if the Extended Mode Register (EMRS(1)) is programmed to disable ODT.

**ODT Truth Tables**

The ODT Truth Table shows which of the input pins are terminated depending on the state of address bit A10 and A11 in the EMRS(1) for all three device organisations (×4, ×8 and ×16). To activate termination of any of these pins, the ODT function has to be enabled in the EMRS(1) by address bits A6 and A2.

**Table 16 ODT Truth Table**

Input Pin	EMRS(1) Address Bit A10	EMRS(1) Address Bit A11
<b>x4 components</b>		
DQ[3:0]	X	
DQS	X	
$\overline{\text{DQS}}$	0	X
DM	X	
<b>x8 components</b>		
DQ[7:0]	X	
DQS	X	
$\overline{\text{DQS}}$	0	X
RDQS	X	1
$\overline{\text{RDQS}}$	0	1
DM	X	0
<b>x16 components</b>		
DQ[7:0]	X	
DQ[15:8]	X	
LDQS	X	
$\overline{\text{LDQS}}$	0	X
UDQS	X	
$\overline{\text{UDQS}}$	0	X
LDM	X	
UDM	X	

*Note: X = don't care; 0 = bit set to low; 1 = bit set to high*

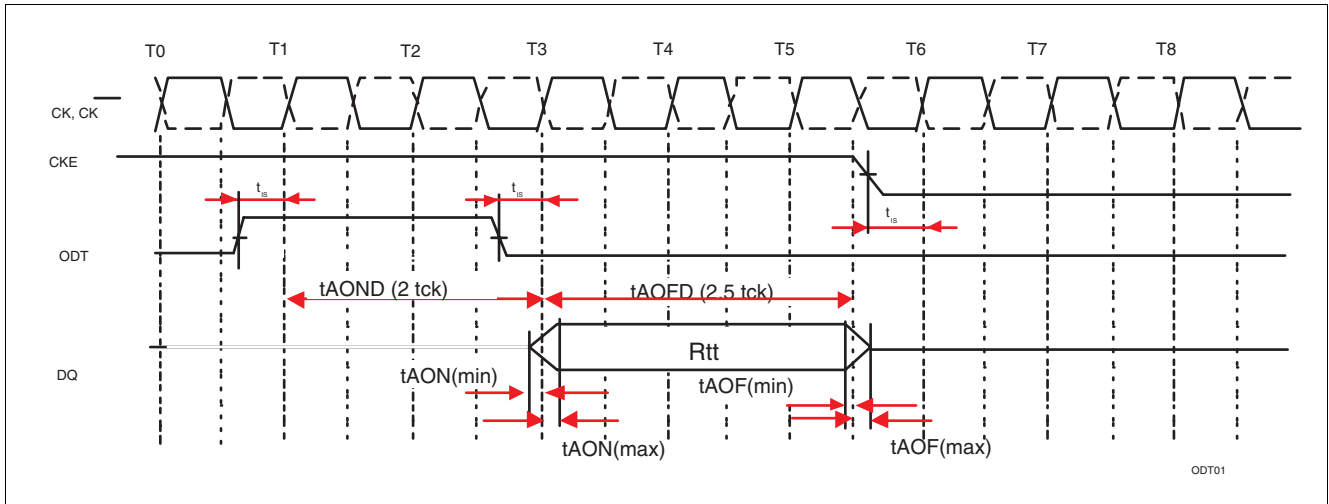
**ODT timing modes**

Depending on the operating mode asynchronous or synchronous ODT timings apply.

Asynchronous ODT timings ( $t_{AOFPD}$ ,  $t_{AONPD}$ ) apply when the on-die DLL is disabled.

These modes are:

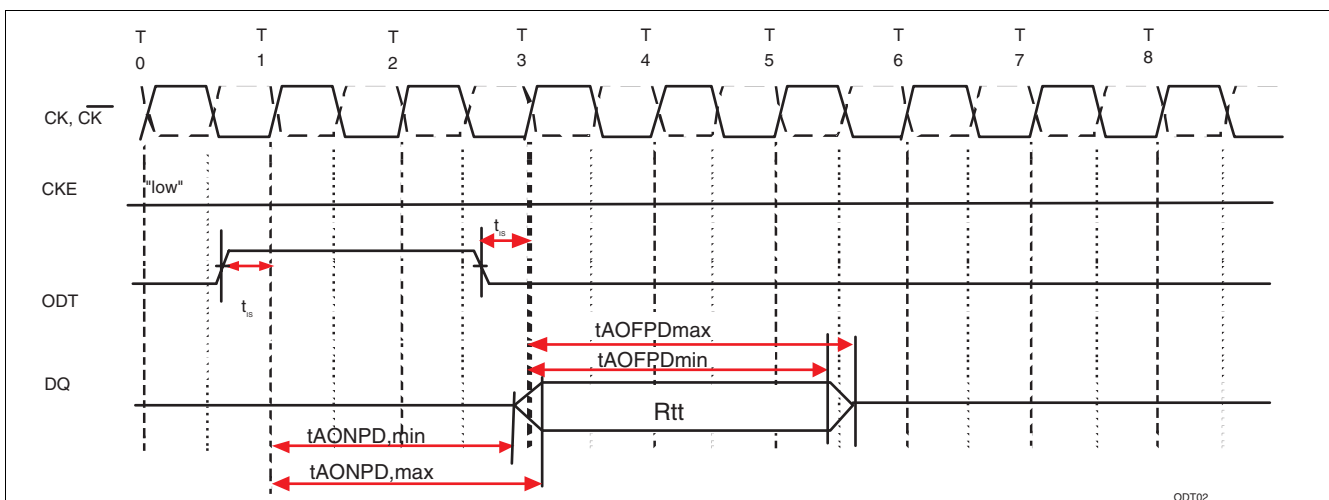
- Slow Exit Active Power Down Mode (with MRS bit A12 is set to 1)
  - Precharge Power Down Mode
- Synchronous ODT timings ( $t_{AOND}$ ,  $t_{AOFD}$ ,  $t_{AON}$ ,  $t_{AOF}$ ) apply for all other modes.



**Figure 13 ODT Timing for Active and Standby (Idle) Modes (Synchronous ODT timings)**

**Notes**

1. Synchronous ODT timings apply for Active Mode and Standby Mode with CKE HIGH and for the "Fast Exit" Active Power Down Mode (MRS bit A12 set to 0). In all these modes the on-die DLL is enabled.
2. ODT turn-on time ( $t_{AON.MIN}$ ) is when the device leaves high impedance and ODT resistance begins to turn on. ODT turn on time max. ( $t_{AON.MAX}$ ) is when the ODT resistance is fully on. Both are measured from  $t_{AOND}$ .
3. ODT turn off time min. ( $t_{AOF.MIN}$ ) is when the device starts to turn off the ODT resistance. ODT turn off time max. ( $t_{AOF.MAX}$ ) is when the bus is in high impedance. Both are measured from  $t_{AOFD}$ .



**Figure 14 ODT Timing for Precharge Power-Down and Active Power-Down Mode**

Note: Asynchronous ODT timings apply for Precharge Power-Down Mode and "Slow Exit" Active Power Down Mode (MRS bit A12 set to 1), where the on-die DLL is disabled in this mode of operation.

**ODT timing mode switch**

When entering the Power Down Modes “Slow Exit” Active Power Down and Precharge Power Down two additional timing parameters ( $t_{ANPD}$  and  $t_{AXPD}$ ) define if synchronous or asynchronous ODT timings have to be applied.

**Mode entry**

As long as the timing parameter  $t_{ANPD.MIN}$  is satisfied when ODT is turned on or off before entering these power-down modes, synchronous timing parameters can be applied. If  $t_{ANPD.MIN}$  is not satisfied, asynchronous timing parameters apply.

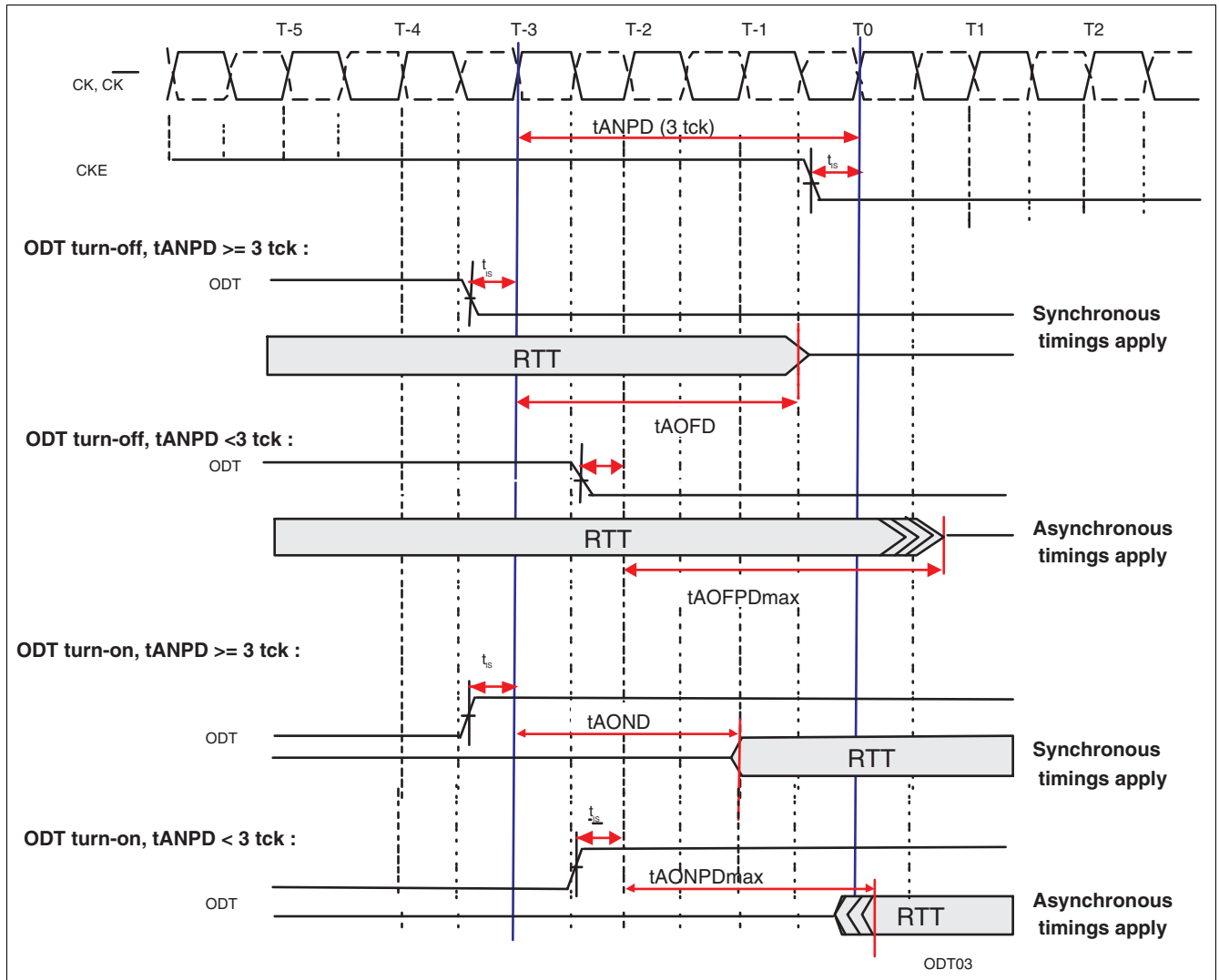


Figure 15 ODT Mode Entry Timing Diagram

**Mode exit**

As long as the timing parameter  $t_{AXPD,MIN}$  is satisfied when ODT is turned on or off after exiting these power-down modes, synchronous timing parameters can be

applied. If  $t_{AXPD,MIN}$  is not satisfied, asynchronous timing parameters apply.

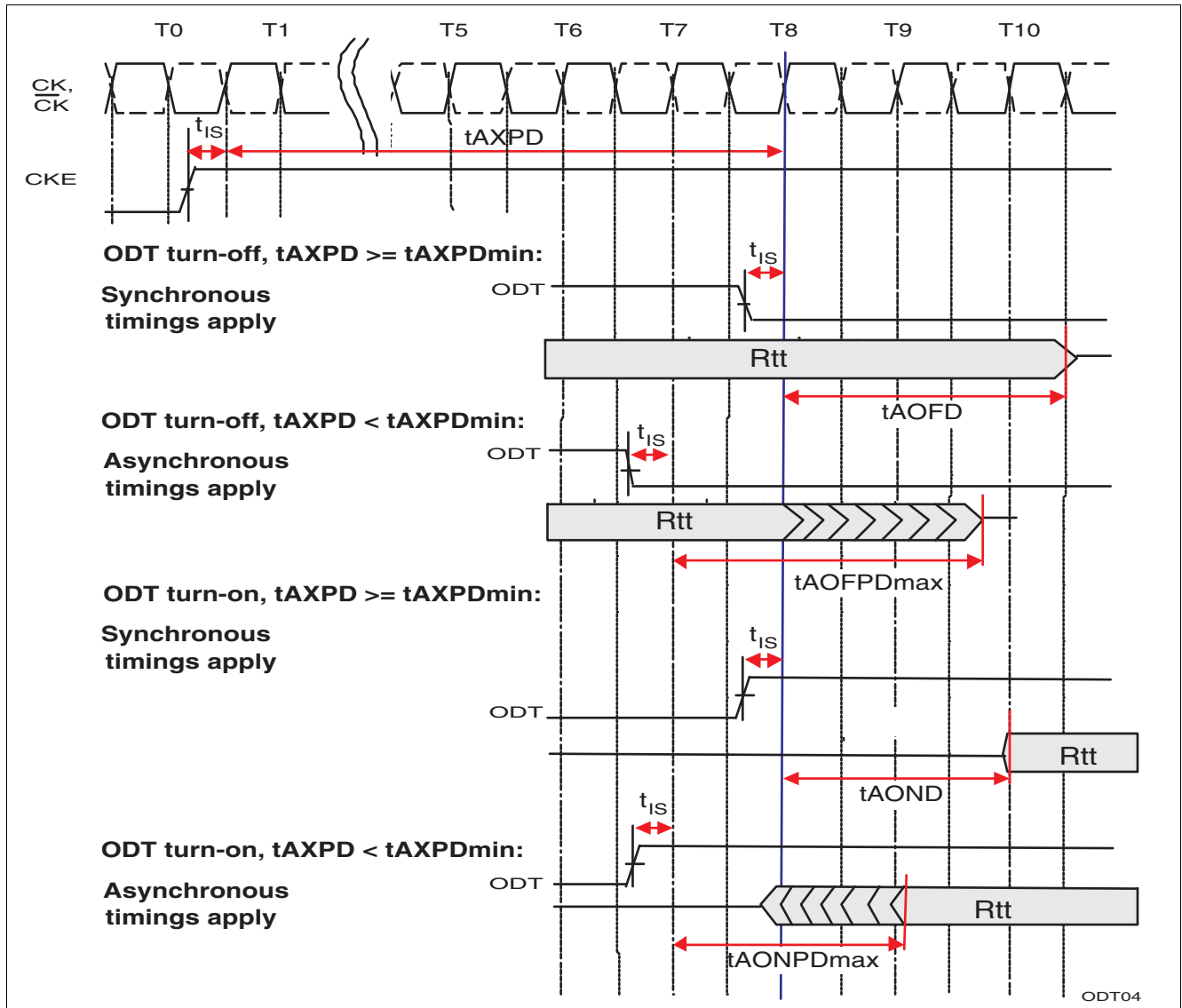


Figure 16 ODT Mode Exit Timing Diagram

### 3.14 Bank Activate Command

The Bank Activate command is issued by holding  $\overline{\text{CAS}}$  and  $\overline{\text{WE}}$  HIGH with  $\overline{\text{CS}}$  and  $\overline{\text{RAS}}$  LOW at the rising edge of the clock. The bank addresses BA[1:0] are used to select the desired bank. The row addresses A0 through A12 are used to determine which row to activate in the selected bank for  $\times 4$  and  $\times 8$  organized components. For  $\times 16$  components row addresses A0 through A12 have to be applied. The Bank Activate command must be applied before any Read or Write operation can be executed. Immediately after the bank active command, the DDR2 SDRAM can accept a read or write command (with or without Auto-Precharge) on the following clock cycle. If a R/W command is issued to a bank that has not satisfied the  $t_{\text{RCD,MIN}}$  specification, then additive

latency must be programmed into the device to delay the R/W command which is internally issued to the device. The additive latency value must be chosen to assure  $t_{\text{RCD,MIN}}$  is satisfied. Additive latencies of 0, 1, 2, 3, 4 and 5 are supported. Once a bank has been activated it must be precharged before another Bank Activate command can be applied to the same bank. The bank active and precharge times are defined as  $t_{\text{RAS}}$  and  $t_{\text{RP}}$ , respectively. The minimum time interval between successive Bank Activate commands to the same bank is determined by  $t_{\text{RC}}$ . The minimum time interval between Bank Active commands to different banks is  $t_{\text{RRD}}$ .

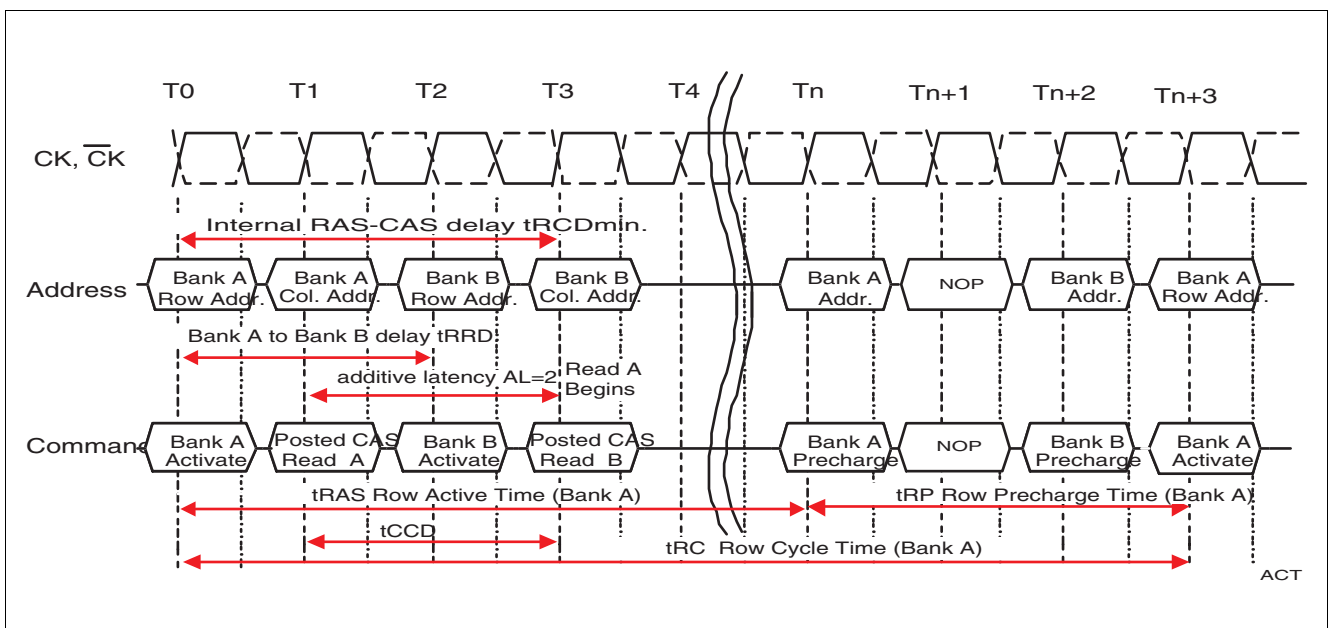


Figure 17 Bank Activate Command Cycle

$$t_{\text{RCD}} = 3, AL = 2, t_{\text{RP}} = 3, t_{\text{RRD}} = 2$$

### 3.15 Read and Write Commands and Access Modes

After a bank has been activated, a read or write cycle can be executed. This is accomplished by setting RAS HIGH, CS and CAS LOW at the clock's rising edge. WE must also be defined at this time to determine whether the access cycle is a read operation (WE HIGH) or a write operation (WE LOW). The DDR2 SDRAM provides a wide variety of fast access modes. A single Read or Write Command will initiate a serial read or write operation on successive clock cycles at data rates of up to 533 Mb/sec/pin for main memory. The boundary of the burst cycle is restricted to specific segments of the page length. For example, the 16 Mbit x 4 I/O x 4 Bank chip has a page length of 512 bits (defined by CA[11, 9:0]). In case of a 4-bit burst operation (burst length = 4) the page length of 512 is divided into 128 uniquely addressable segments (4 bits x 4 I/O each). The 4-bit burst operation will occur entirely within one of the 128 segments (defined by CA[8:0]) starting with the column address supplied to

the device during the Read or Write Command (CA[11, 9:0]). The second, third and fourth access will also occur within this segment, however, the burst order is a function of the starting address, and the burst sequence. In case of a 8-bit burst operation (burst length = 8) the page length of 512 is divided into 64 uniquely addressable segments (8 bits x 4 I/O each). The 8-bit burst operation will occur entirely within one of the 64 segments (defined by CA[7:0]) beginning with the column address supplied to the device during the Read or Write Command (CA[11, 9:0]). A new burst access must not interrupt the previous 4 bit burst operation in case of BL = 4 setting. Therefore the minimum CAS to CAS delay ( $t_{CCD}$ ) is a minimum of 2 clocks for read or write cycles. For 8 bit burst operation (BL = 8) the minimum CAS to CAS delay ( $t_{CCD}$ ) is 4 clocks for read or write cycles. Burst interruption is allowed with 8 bit burst operation. For details see Chapter 3.20.

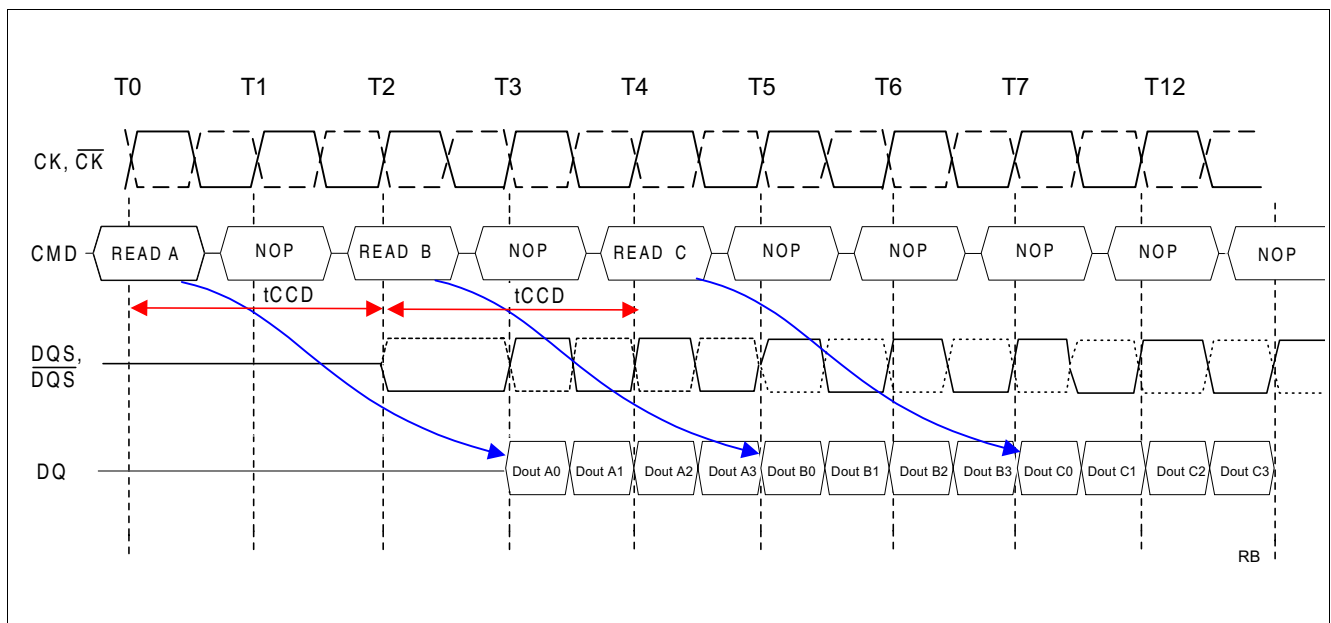


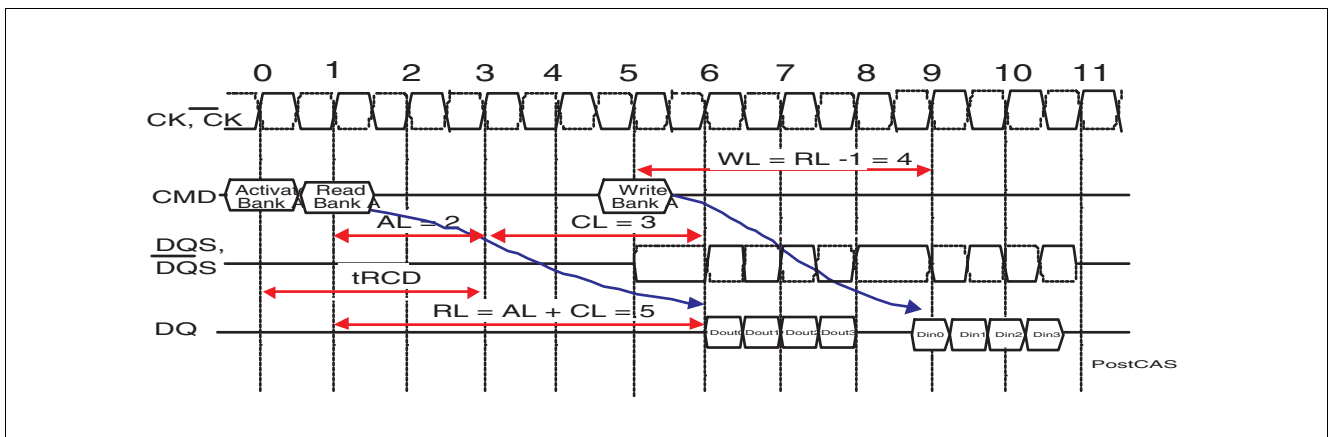
Figure 18 Read Timing Example

CL = 3, AL = 0, RL = 3, BL = 4

### 3.16 Posted CAS

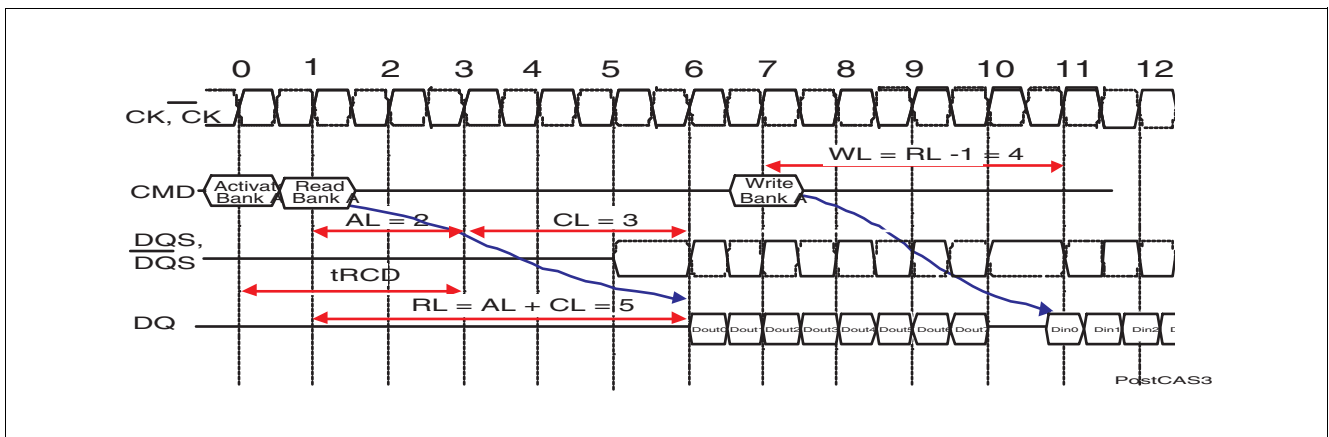
Posted CAS operation is supported to make command and data bus efficient for sustainable bandwidths in DDR2 SDRAM. In this operation, the DDR2 SDRAM allows a Read or Write command to be issued immediately after the bank activate command (or any time during the  $\overline{\text{RAS}}$  to  $\overline{\text{CAS}}$  delay time,  $t_{\text{RCD}}$  period). The command is held for the time of the Additive Latency (AL) before it is issued inside the device. The Read Latency (RL) is the sum of AL and the CAS

latency (CL). Therefore if a user chooses to issue a Read/Write command before the  $t_{\text{RCD,MIN}}$ , then AL greater than 0 must be written into the EMR(1). The Write Latency (WL) is always defined as  $\text{RL} - 1$  (Read Latency - 1) where Read Latency is defined as the sum of Additive Latency plus CAS latency ( $\text{RL} = \text{AL} + \text{CL}$ ). If a user chooses to issue a Read command after the  $t_{\text{RCD,MIN}}$  period, the Read Latency is also defined as  $\text{RL} = \text{AL} + \text{CL}$ .



**Figure 19 Activate to Read Timing Example: Read followed by a write to the same bank**

Activate to Read delay  $< t_{\text{RCD,MIN}}$ :  $\text{AL} = 2$  and  $\text{CL} = 3$ ,  $\text{RL} = (\text{AL} + \text{CL}) = 5$ ,  $\text{WL} = (\text{RL} - 1) = 4$ ,  $\text{BL} = 4$



**Figure 20 Read to Write Timing Example: Read followed by a write to the same bank**

Activate to Read delay  $< t_{\text{RCD,MIN}}$ :  $\text{AL} = 2$  and  $\text{CL} = 3$ ,  $\text{RL} = (\text{AL} + \text{CL}) = 5$ ,  $\text{WL} = (\text{RL} - 1) = 4$ ,  $\text{BL} = 8$



### 3.17 Burst Mode Operation

Burst mode operation is used to provide a constant flow of data to memory locations (write cycle), or from memory locations (read cycle). The parameters that define how the burst mode will operate are burst sequence and burst length. The DDR2 SDRAM supports 4 bit and 8 bit burst modes only. For 8 bit burst mode, full interleave address ordering is supported, however, sequential address ordering is nibble based for ease of implementation. The burst length is programmable and defined by the addresses A[2:0] of

the MR. The burst type, either sequential or interleaved, is programmable and defined by the address bit 3 (A3) of the MR. Seamless burst read or write operations are supported. Interruption of a burst read or write operation is prohibited, when burst length = 4 is programmed. For burst interruption of a read or write burst when burst length = 8 is used, see [Chapter 3.19](#). A Burst Stop command is not supported on DDR2 SDRAM devices.

**Table 17 Burst Length and Sequence**

Burst Length	Starting Address (A2 A1 A0)	Sequential Addressing (decimal)	Interleave Addressing (decimal)
4	x 0 0	0, 1, 2, 3	0, 1, 2, 3
	x 0 1	1, 2, 3, 0	1, 0, 3, 2
	x 1 0	2, 3, 0, 1	2, 3, 0, 1
	x 1 1	3, 0, 1, 2	3, 2, 1, 0
8	0 0 0	0, 1, 2, 3, 4, 5, 6, 7	0, 1, 2, 3, 4, 5, 6, 7
	0 0 1	1, 2, 3, 0, 5, 6, 7, 4	1, 0, 3, 2, 5, 4, 7, 6
	0 1 0	2, 3, 0, 1, 6, 7, 4, 5	2, 3, 0, 1, 6, 7, 4, 5
	0 1 1	3, 0, 1, 2, 7, 4, 5, 6	3, 2, 1, 0, 7, 6, 5, 4
	1 0 0	4, 5, 6, 7, 0, 1, 2, 3	4, 5, 6, 7, 0, 1, 2, 3
	1 0 1	5, 6, 7, 4, 1, 2, 3, 0	5, 4, 7, 6, 1, 0, 3, 2
	1 1 0	6, 7, 4, 5, 2, 3, 0, 1	6, 7, 4, 5, 2, 3, 0, 1
	1 1 1	7, 4, 5, 6, 3, 0, 1, 2	7, 6, 5, 4, 3, 2, 1, 0

**Notes**

1. Page size for all 256 Mbit components is 1 KByte
2. Order of burst access for sequential addressing is “nibble-based” and therefore different from SDR or DDR components

### 3.18 Read Command

The Read command is initiated by having  $\overline{CS}$  and  $\overline{CAS}$  LOW while holding  $\overline{RAS}$  and  $\overline{WE}$  HIGH at the rising edge of the clock. The address inputs determine the starting column address for the burst. The delay from the start of the command until the data from the first cell appears on the outputs is equal to the value of the read latency (RL). The data strobe output (DQS) is driven LOW one clock cycle before valid data (DQ) is driven

onto the data bus. The first bit of the burst is synchronized with the rising edge of the data strobe (DQS). Each subsequent data-out appears on the DQ pin in phase with the DQS signal in a source synchronous manner. The RL is equal to an additive latency (AL) plus  $\overline{CAS}$  latency (CL). The CL is defined by the Mode Register Set (MRS). The AL is defined by the Extended Mode Register Set (EMRS(1)).

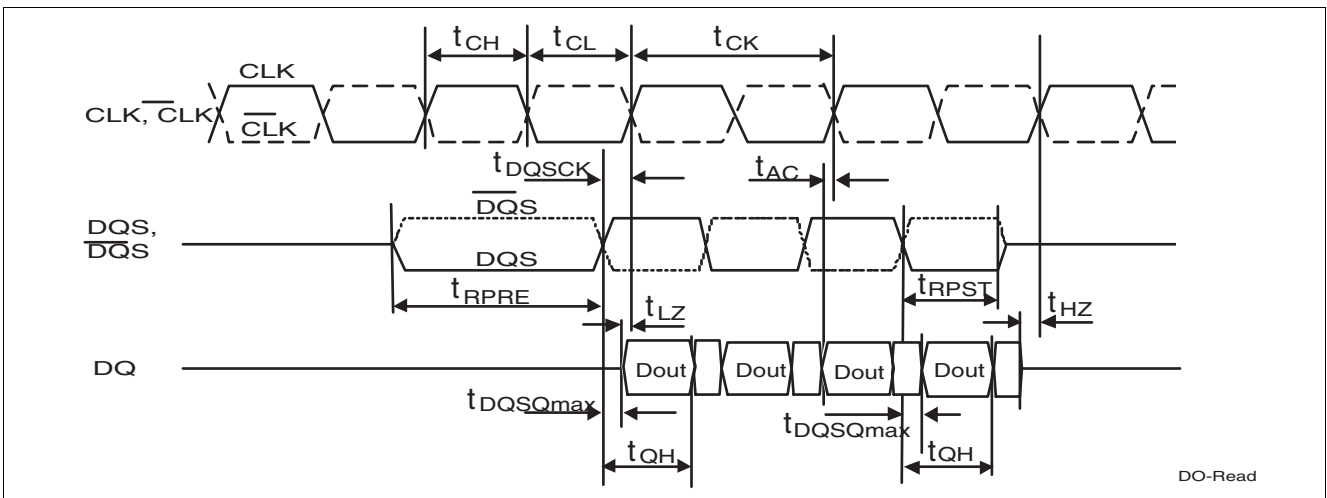


Figure 24 Basic Read Timing Diagram

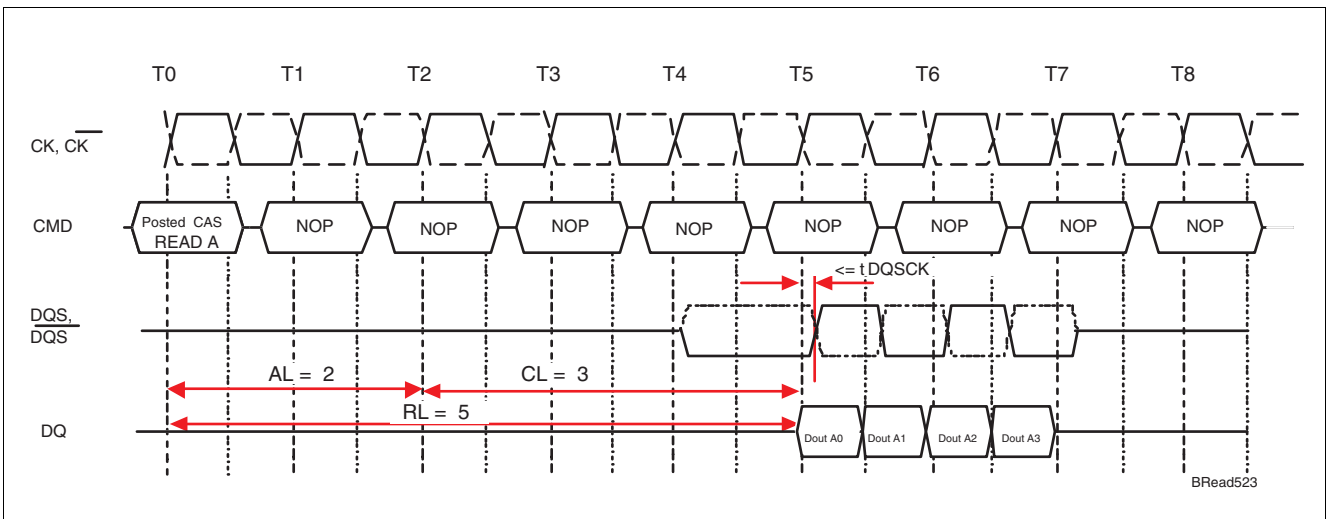


Figure 25 Read Operation Example 1

RL = 5 (AL = 2, CL = 3, BL = 4)

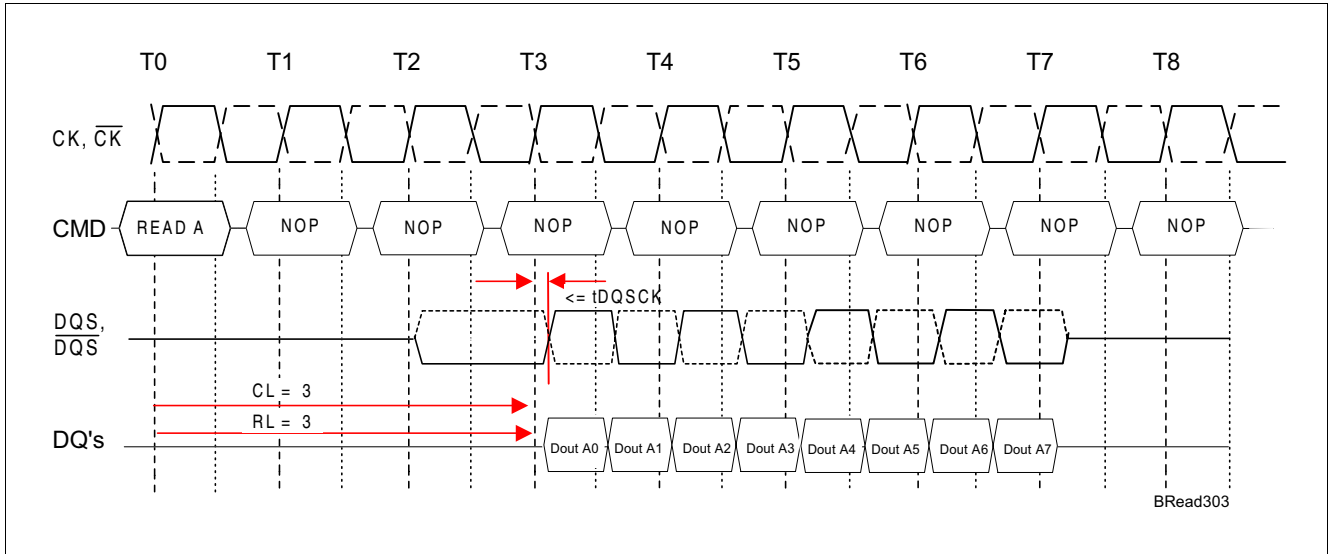


Figure 26 Read Operation Example 2

RL = 3 (AL = 0, CL = 3, BL = 8)

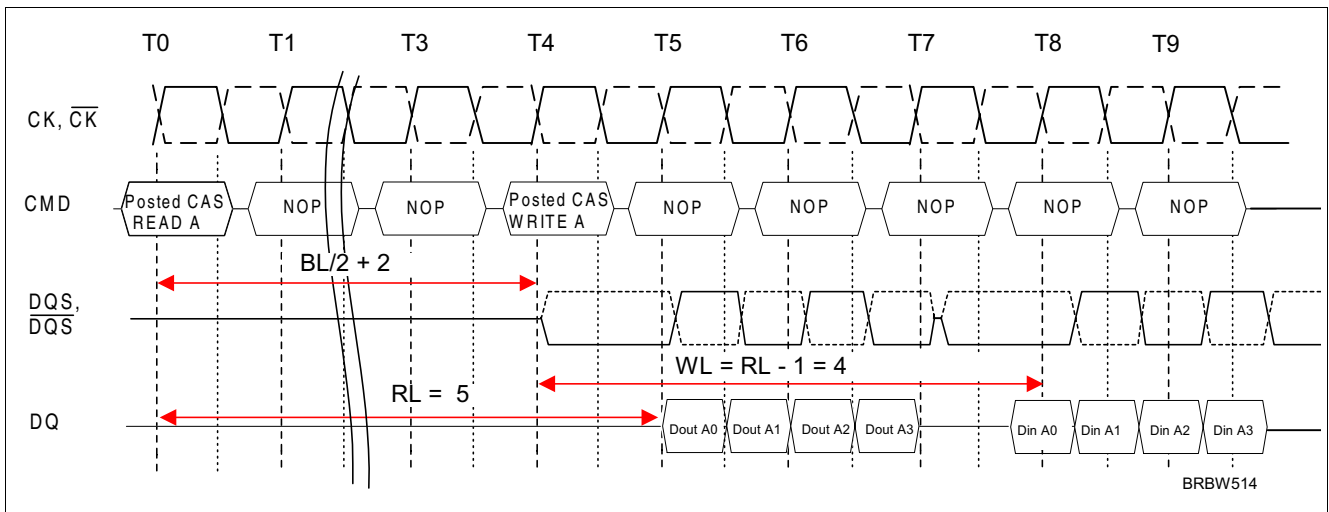
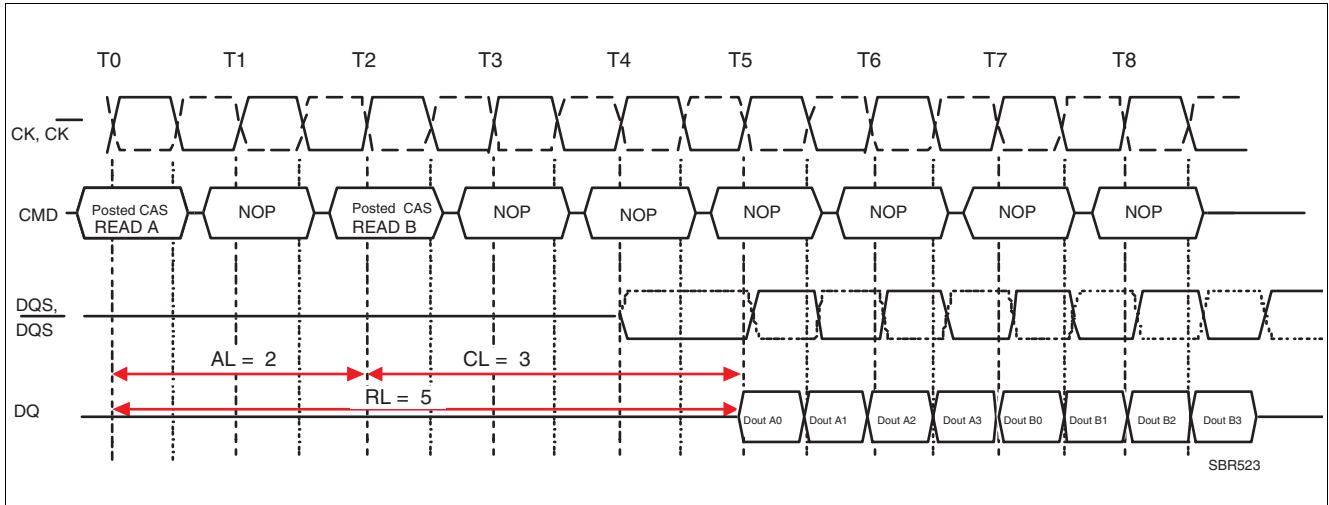


Figure 27 Read followed by Write Example

RL = 5, WL = (RL-1) = 4, BL = 4

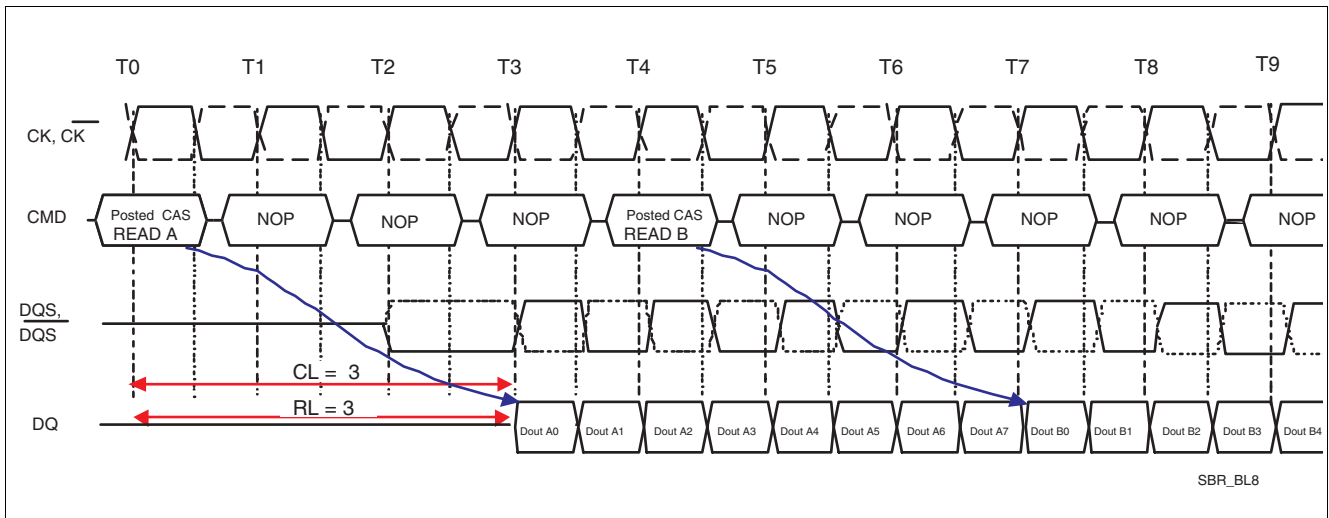
The minimum time from the read command to the write command is defined by a read-to-write turn-around time, which is  $BL/2 + 2$  clocks.



**Figure 28 Seamless Read Operation Example 1**

RL = 5, AL = 2, CL = 3, BL = 4

The seamless read operation is supported by enabling a read command at every BL / 2 number of clocks. This operation is allowed regardless of same or different banks as long as the banks are activated.



**Figure 29 Seamless Read Operation Example 2**

RL = 3, AL = 0, CL = 3, BL = 8 (non interrupting)

The seamless, non interrupting 8-bit read operation is supported by enabling a read command at every BL/2 number of clocks. This operation is allowed regardless of same or different banks as long as the banks are activated.

### 3.19 Write Command

The Write command is initiated by having  $\overline{CS}$ ,  $\overline{CAS}$  and  $\overline{WE}$  LOW while holding  $\overline{RAS}$  HIGH at the rising edge of the clock. The address inputs determine the starting column address. Write latency (WL) is defined by a read latency (RL) minus one and is equal to  $(AL + CL - 1)$ . A data strobe signal (DQS) has to be driven LOW (preamble) a time  $t_{WPRE}$  prior to the WL. The first data bit of the burst cycle must be applied to the DQ pins at the first rising edge of the DQS following the preamble. The  $t_{DQSS}$  specification must be satisfied for write cycles. The subsequent burst bit data are issued on

successive edges of the DQS until the burst length is completed. When the burst has finished, any additional data supplied to the DQ pins will be ignored. The DQ signal is ignored after the burst write operation is complete. The time from the completion of the burst write to bank precharge is named "write recovery time" ( $t_{WR}$ ) and is the time needed to store the write data into the memory array.  $t_{WR}$  is an analog timing parameter (see Chapter 5) and is not the programmed value for WR in the MRS.

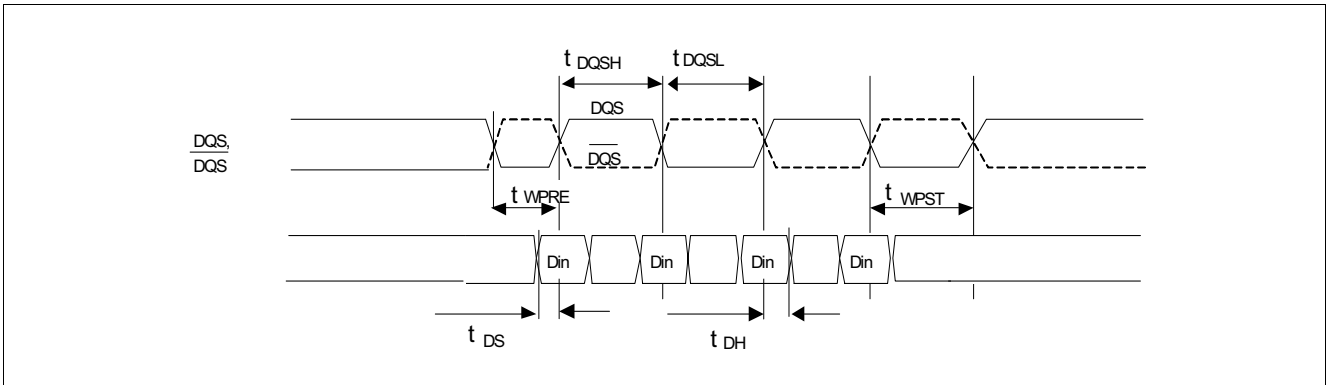


Figure 30 Basic Write Timing

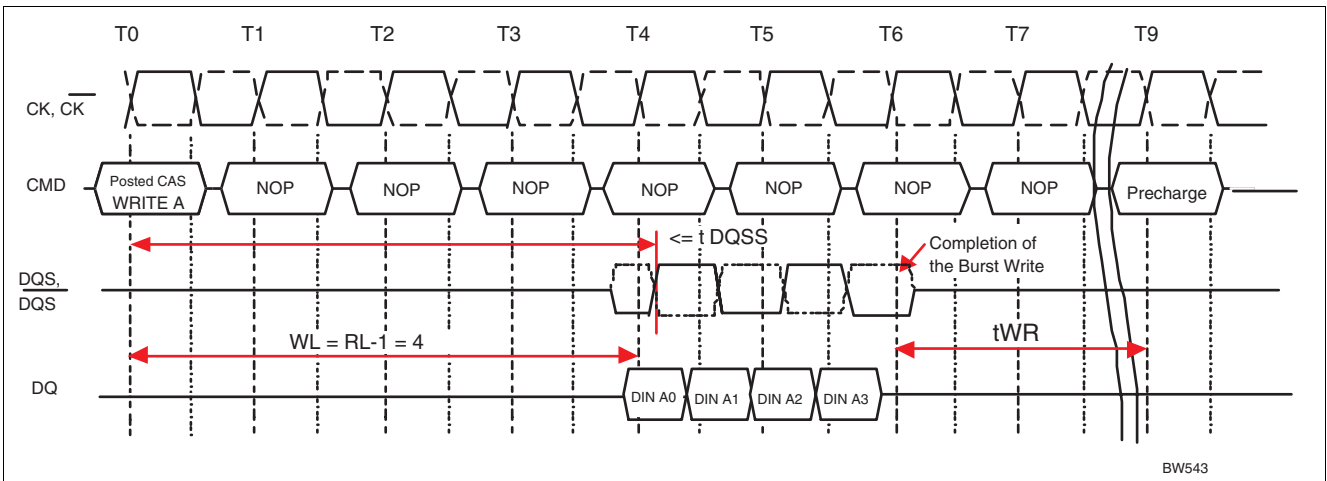
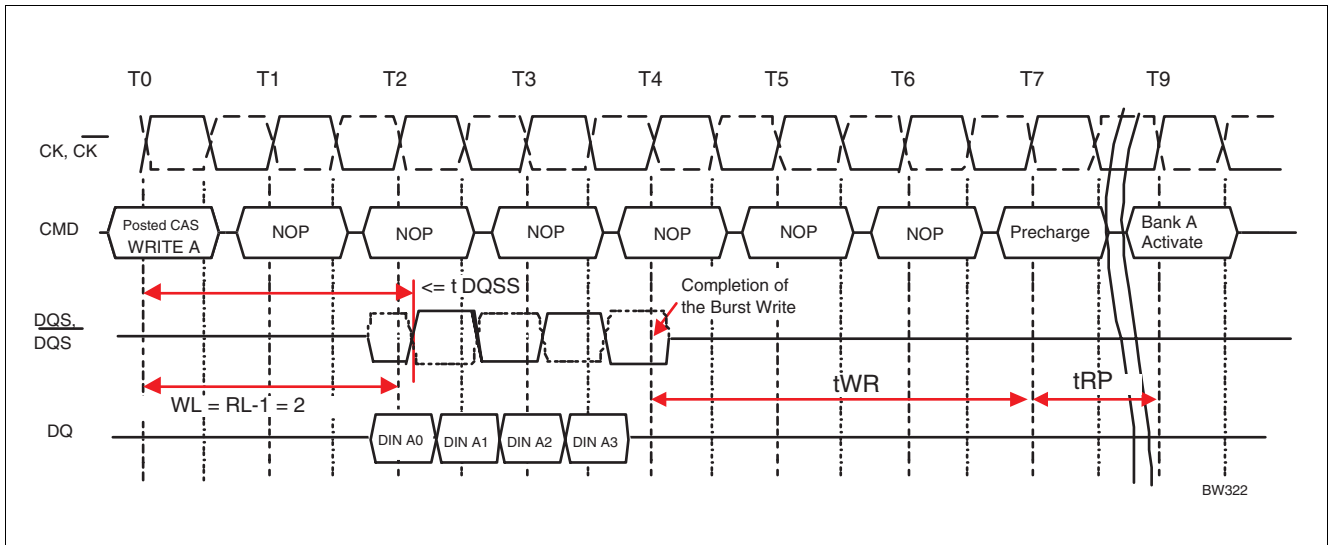


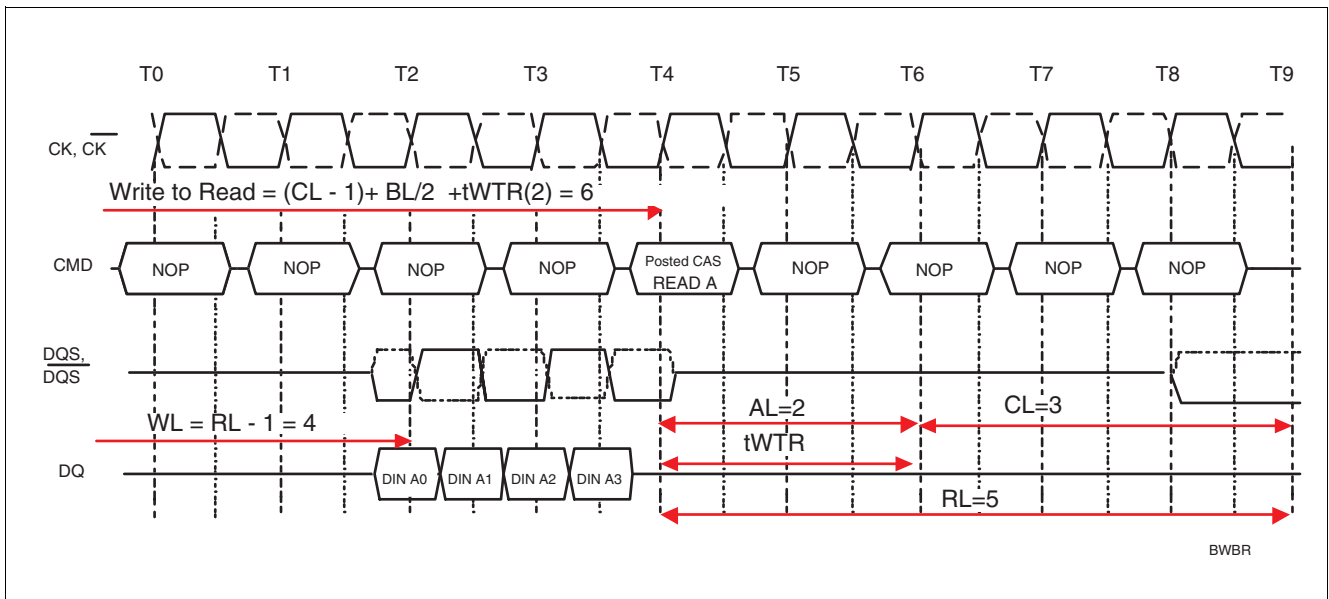
Figure 31 Write Operation Example 1

RL = 5 (AL = 2, CL = 3), WL = 4, BL = 4



**Figure 32 Write Operation Example 2**

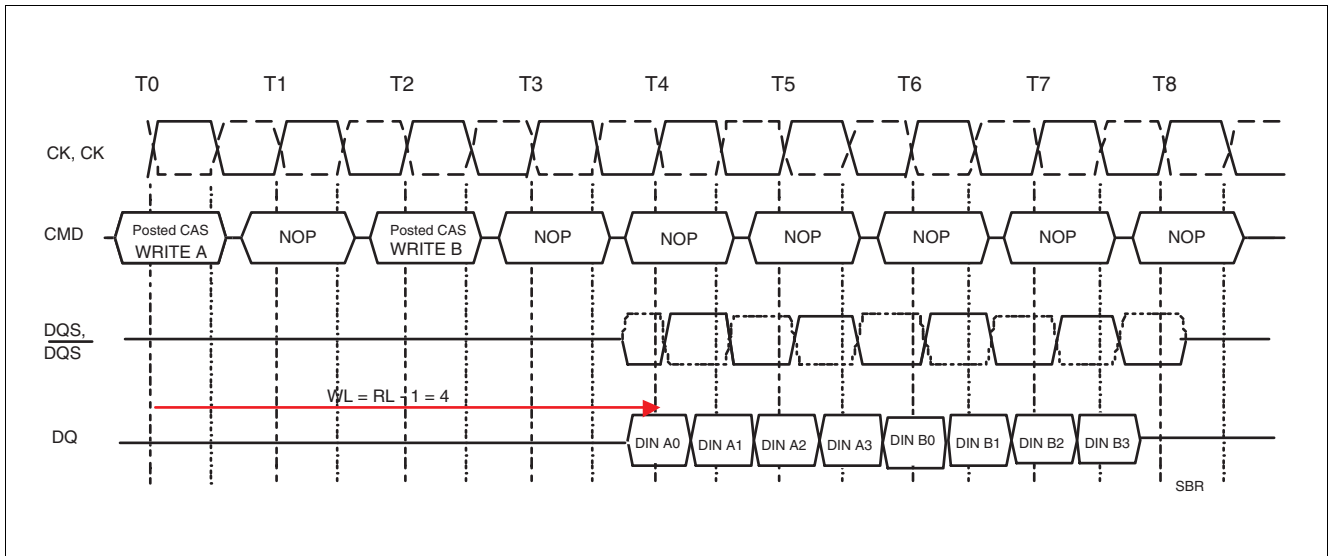
RL = 3 (AL = 0, CL = 3), WL = 2, BL = 4



**Figure 33 Write followed by Read Example**

RL = 5 (AL = 2, CL = 3), WL = 4,  $t_{WTR} = 2$ , BL = 4

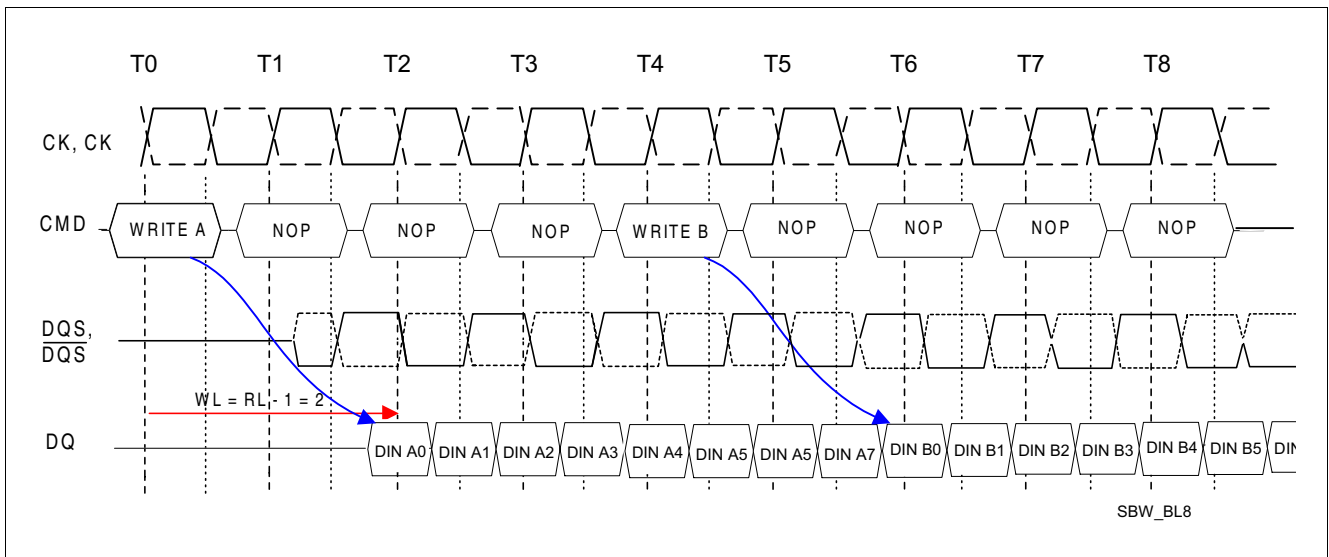
The minimum number of clocks from the write command to the read command is  $(CL - 1) + BL/2 + t_{WTR}$ , where  $t_{WTR}$  is the write-to-read turn-around time  $t_{WTR}$  expressed in clock cycles. The  $t_{WTR}$  is not a write recovery time ( $t_{WR}$ ) but the time required to transfer 4 bit write data from the input buffer into sense amplifiers in the array.



**Figure 34 Seamless Write Operation Example 1**

RL = 5, WL = 4, BL = 4

The seamless write operation is supported by enabling a write command every BL/2 number of clocks. This operation is allowed regardless of same or different banks as long as the banks are activated.



**Figure 35 Seamless Write Operation Example 2**

RL = 3, WL = 2, BL = 8, non interrupting

The seamless write operation is supported by enabling a write command at every BL/2 number of clocks. This operation is allowed regardless of same or different banks as long as the banks are activated.

### 3.20 Write Data Mask

One write data mask input (DM) for  $\times 4$  and  $\times 8$  components and two write data mask inputs (LDM, UDM) for  $\times 16$  components are supported on DDR2 SDRAM's, consistent with the implementation on DDR SDRAM's. It has identical timings on write operations as the data bits, and though used in a uni-directional manner, is internally loaded identically to data bits to

insure matched system timing. Data mask is not used during read cycles. If DM is HIGH during a write burst coincident with the write data, the write data bit is not written to the memory. For  $\times 8$  components the DM function is disabled, when RDQS /  $\overline{\text{RDQS}}$  are enabled by EMRS(1).

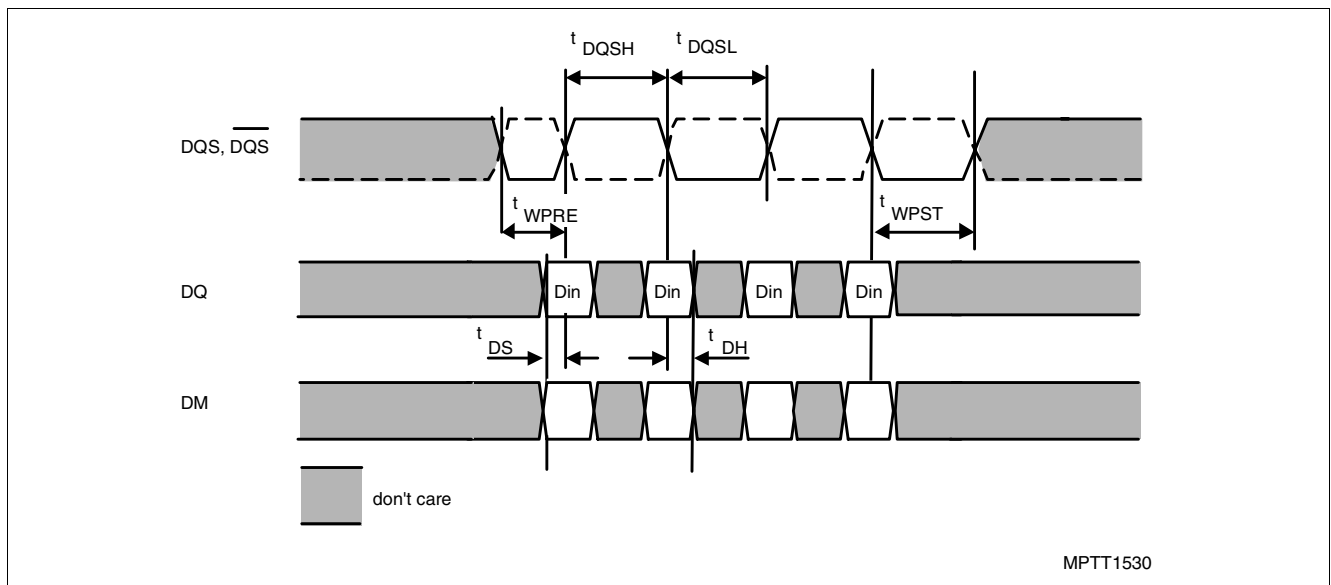


Figure 36 Write Data Mask Timing

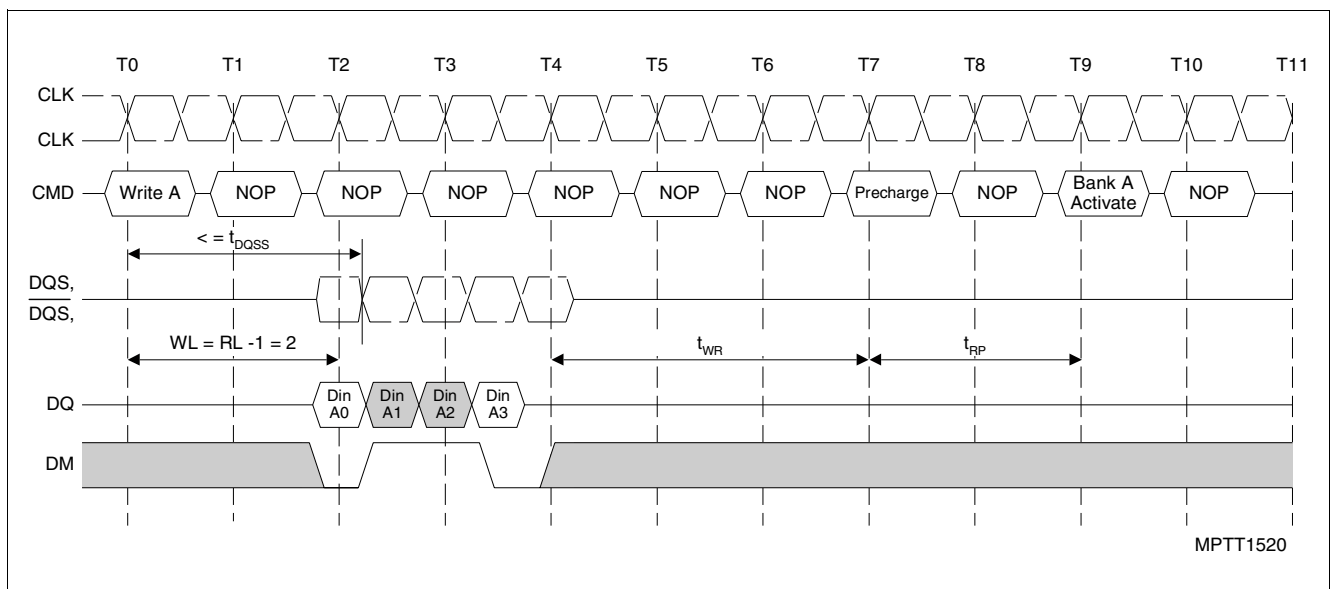


Figure 37 Write Operation with Data Mask Example

RL = 3 (AL = 0, CL = 3), WL = 2,  $t_{WR}$  = 3, BL = 4

### 3.21 Burst Interruption

Interruption of a read or write burst is prohibited for burst length of 4 and only allowed for burst length of 8 under the following conditions:

1. A Read Burst can only be interrupted by another Read command. Read burst interruption by a Write or Precharge Command is prohibited.
2. A Write Burst can only be interrupted by another Write command. Write burst interruption by a Read or Precharge Command is prohibited.
3. Read burst interrupt must occur exactly two clocks after the previous Read command. Any other Read burst interrupt timings are prohibited.
4. Write burst interrupt must occur exactly two clocks after the previous Write command. Any other Read burst interrupt timings are prohibited.
5. Read or Write burst interruption is allowed to any bank inside the DDR2 SDRAM.
6. Read or Write burst with Auto-Precharge enabled is not allowed to be interrupted.
7. Read burst interruption is allowed by a Read with Auto-Precharge command.
8. Write burst interruption is allowed by a Write with Auto-Precharge command.
9. All command timings are referenced to burst length set in the mode register. They are not referenced to the actual burst. For example, Minimum Read to Precharge timing is  $AL + BL/2$  where  $BL$  is the burst length set in the mode register and not the actual burst (which is shorter because of interrupt). Minimum Write to Precharge timing is  $WL + BL/2 + t_{WR}$ , where  $t_{WR}$  starts with the rising clock after the un-interrupted burst end and not from the end of the actual burst end.

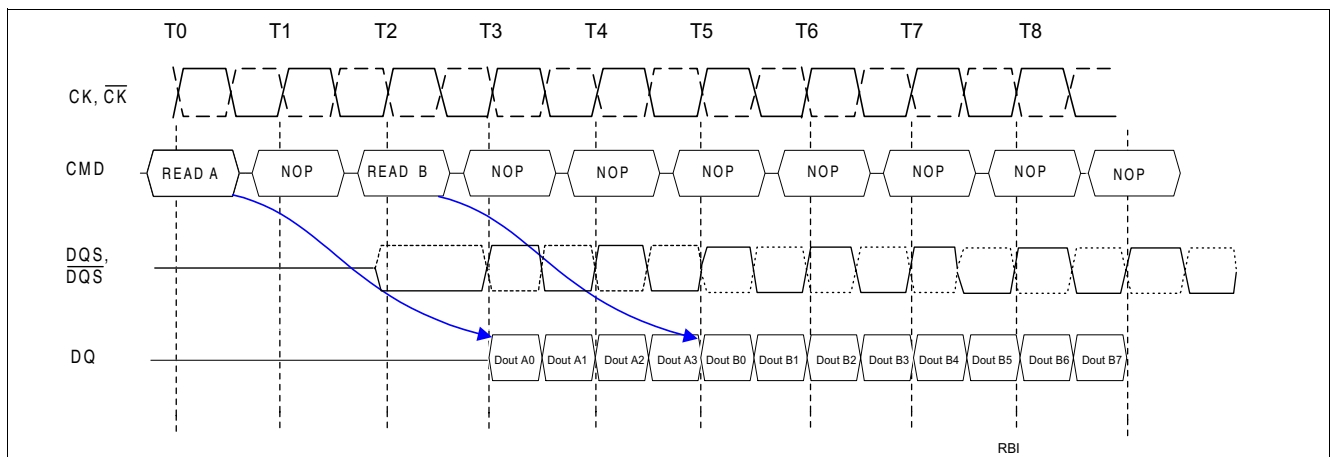


Figure 38 Read Interrupt Timing Example 1

CL = 3, AL = 0, RL = 3, BL = 8

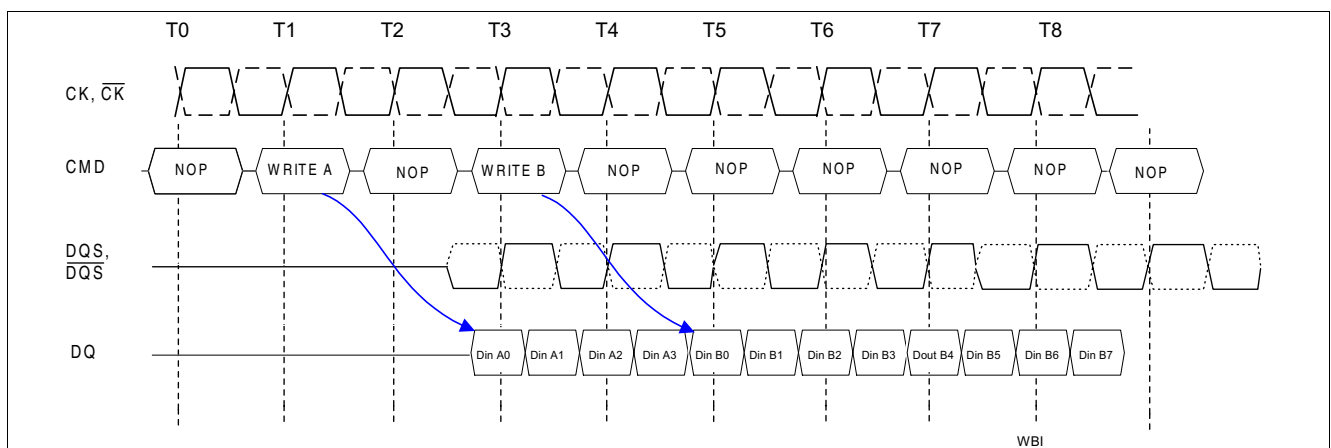


Figure 39 Write Interrupt Timing Example 2

CL = 3, AL = 0, WL = 2, BL = 8

### 3.22 Precharge Command

The Precharge Command is used to precharge or close a bank that has been activated. The Precharge Command is triggered when  $\overline{CS}$ ,  $\overline{RAS}$  and  $\overline{WE}$  are LOW and  $\overline{CAS}$  is HIGH at the rising edge of the clock.

The Pre-charge Command can be used to precharge each bank independently or all banks simultaneously. 3 address bits A10, BA[1:0] are used to define which bank to precharge when the command is issued.

**Table 18 Bank Selection for Precharge by Address Bits**

A10	BA1	BA0	Precharge Bank(s)
0	0	0	Bank 0 only
0	0	1	Bank 1 only
0	1	0	Bank 2 only
0	1	1	Bank 3 only
1	Don't Care	Don't Care	All banks

Note: The bank address assignment is the same for activating and precharging a specific bank.

#### 3.22.1 Read Followed by a Precharge

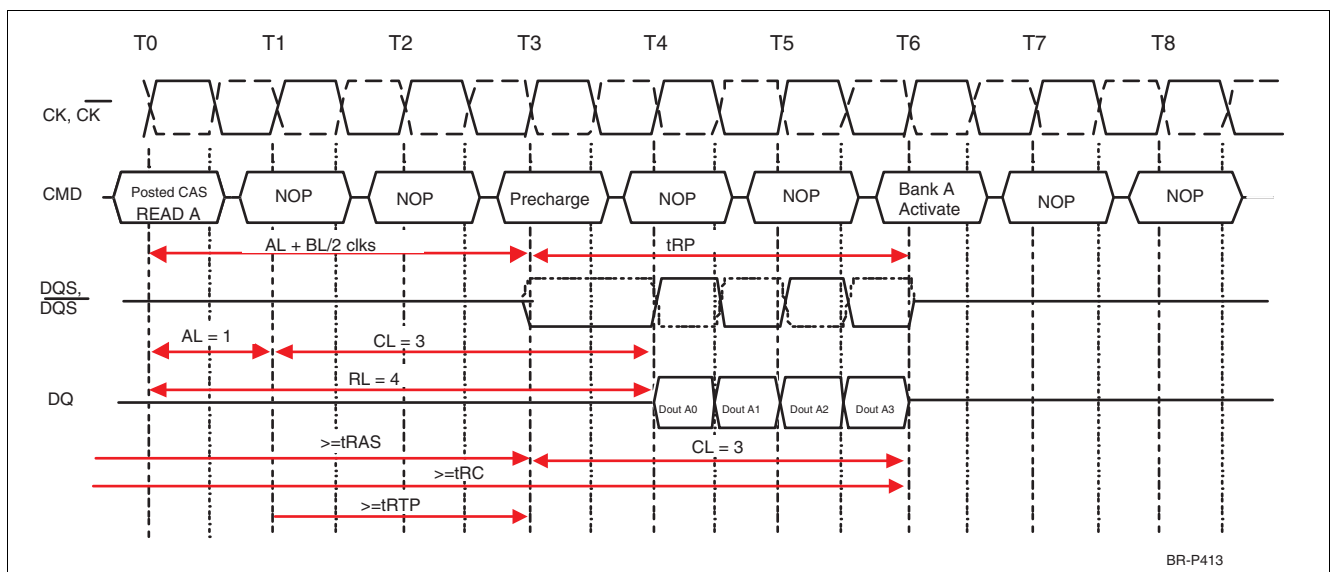
The following rules apply as long as the  $t_{RTP}$  timing parameter - Internal Read to Precharge Command delay time - is less or equal two clocks, which is the case for operating frequencies less or equal 266 MHz (DDR2 400 and 533 speed sorts).

Minimum Read to Precharge command spacing to the same bank = AL + BL/2 clocks. For the earliest possible precharge, the Precharge command may be issued on the rising edge which is "Additive Latency (AL) + BL/2 clocks" after a Read Command, as long as the minimum  $t_{RAS}$  timing is satisfied.

The term  $(t_{RTP} - 2 \times t_{CK})$  is 0 clocks for operating frequencies less or equal 266 MHz (DDR2-400 and DDR2-533 product speed sorts). The term  $(t_{RTP} - 2 \times t_{CK})$  is one clock for frequencies higher than 266 MHz (DDR2-667 and DDR2-800 speed sorts).

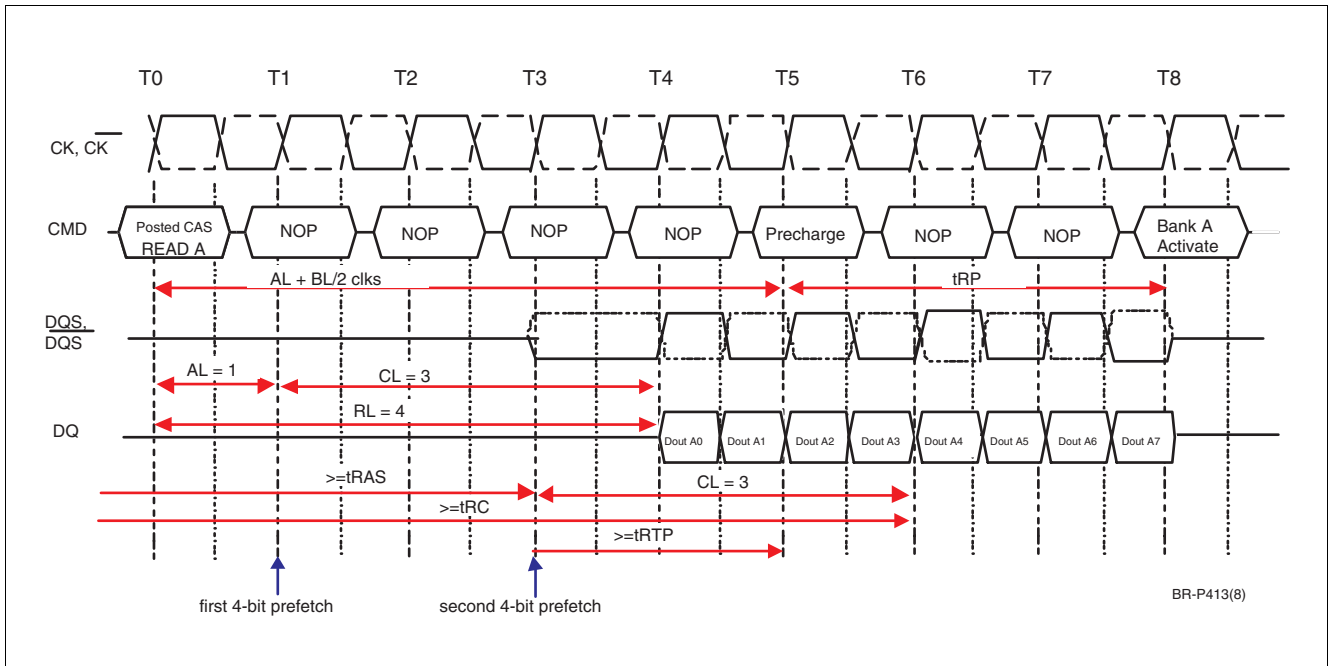
A new bank active command may be issued to the same bank if the following two conditions are satisfied simultaneously:

1. The RAS precharge time ( $t_{RP}$ ) has been satisfied from the clock at which the precharge begins.
2. The RAS cycle time ( $t_{RC.MIN}$ ) from the previous bank activation has been satisfied.



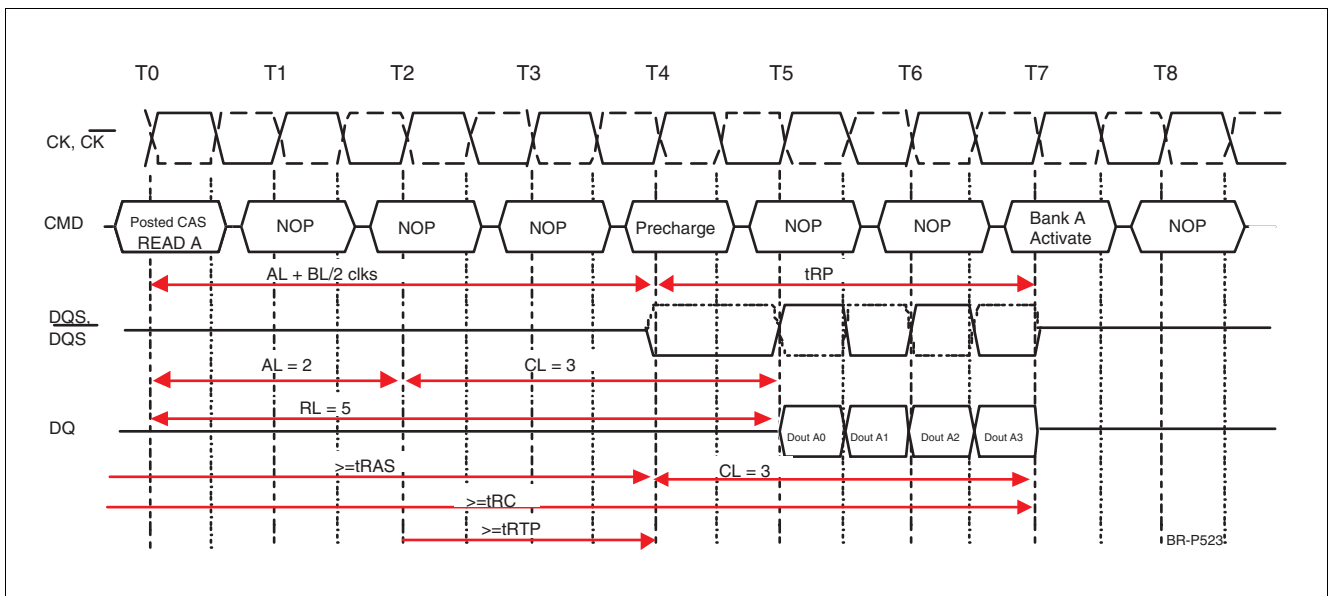
**Figure 40 Read Operation Followed by Precharge Example 1**

RL = 4 (AL = 1, CL = 3), BL = 4,  $t_{RTP} \leq 2$  CKs



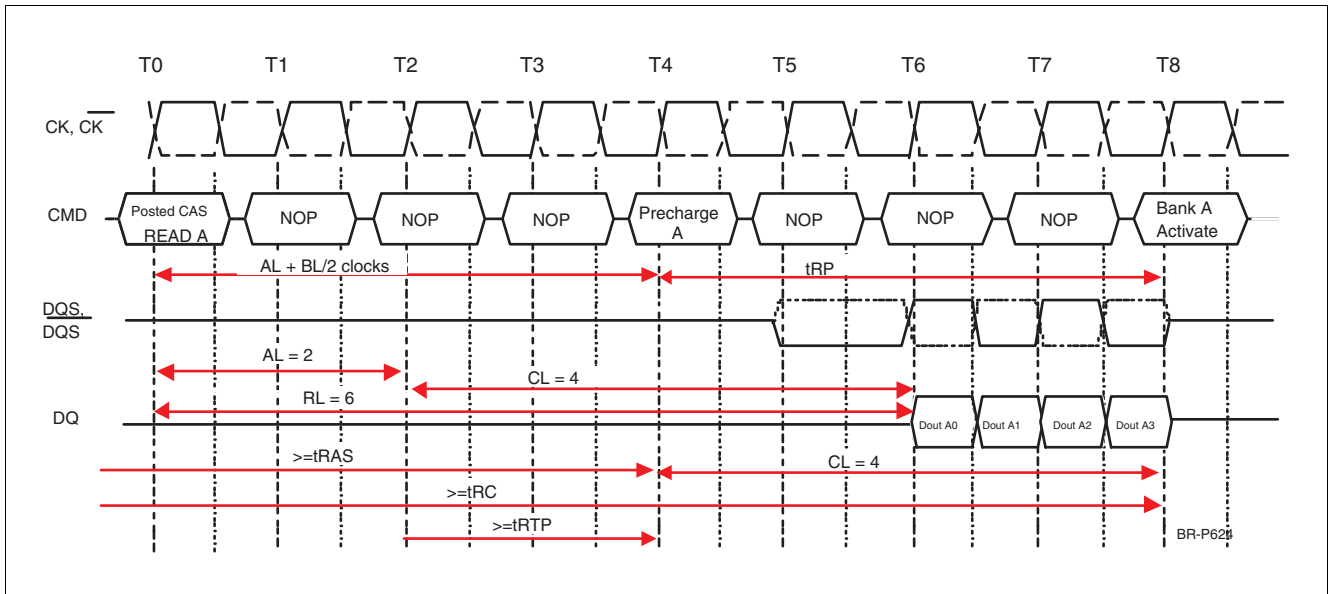
**Figure 41 Read Operation Followed by Precharge Example 2**

RL = 4 (AL = 1, CL = 3), BL = 8,  $t_{RTP} \leq 2$  CKs



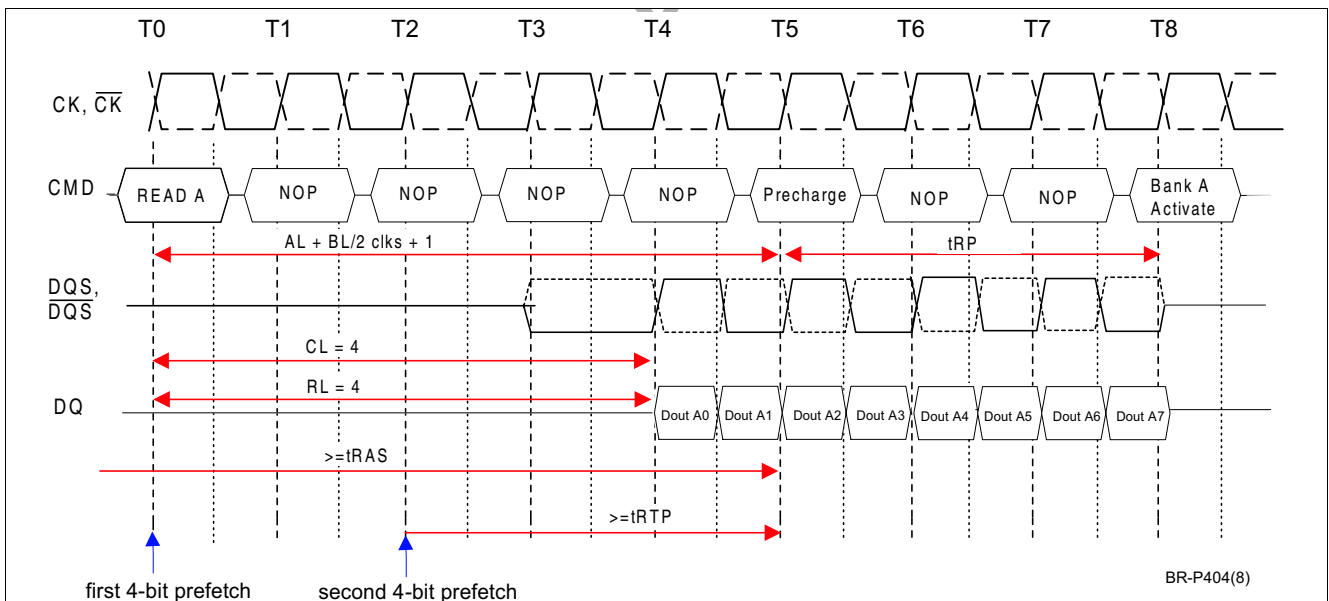
**Figure 42 Read Operation Followed by Precharge Example 3**

RL = 5 (AL = 2, CL = 3), BL = 4,  $t_{RTP} \leq 2$  CKs



**Figure 43 Read Operation Followed by Precharge Example 4**

RL = 6, (AL = 2, CL = 4), BL = 4,  $t_{RTP} \leq 2$  CKs



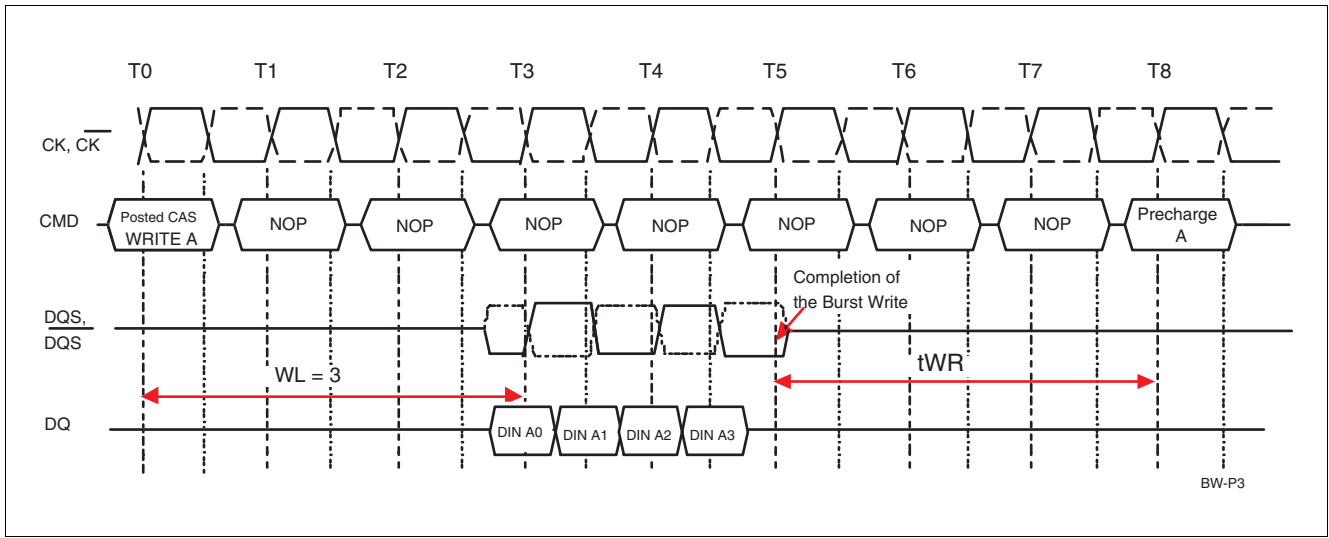
**Figure 44 Read Operation Followed by Precharge Example 5**

RL = 4, (AL = 0, CL = 4), BL = 8,  $t_{RTP} > 2$  CKs

### 3.22.2 Write followed by Precharge

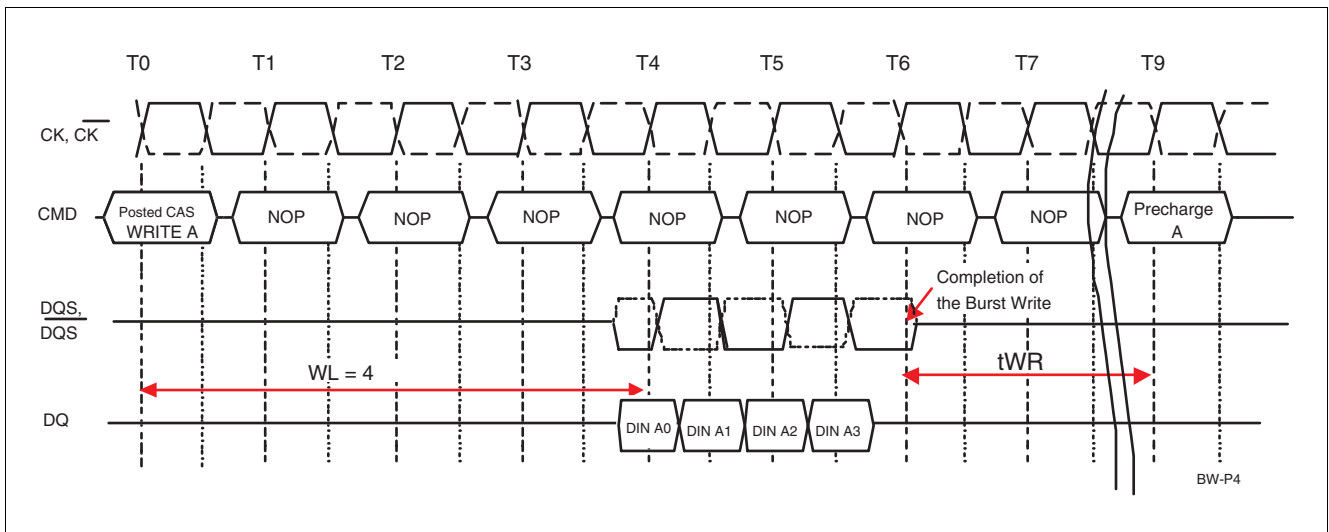
Minimum Write to Precharge command spacing to the same bank =  $WL + BL/2 + t_{WR}$ . For write cycles, a delay must be satisfied from the completion of the last burst write cycle until the Precharge command can be issued. This delay is known as a write recovery time ( $t_{WR}$ ) referenced from the completion of the burst write

to the Precharge command. No Precharge command should be issued prior to the  $t_{WR}$  delay, as DDR2 SDRAM does not support any burst interrupt by a Precharge command.  $t_{WR}$  is an analog timing parameter (see [Chapter 7](#)) and is not the programmed value WR in the MR.



**Figure 45 Write followed by Precharge Example 1**

$WL = (RL - 1) = 3, BL = 4, t_{WR} = 3$



**Figure 46 Write followed by Precharge Example 2**

$WL = (RL - 1) = 4, BL = 4, t_{WR} = 3$

### 3.23 Auto-Precharge Operation

Before a new row in an active bank can be opened, the active bank must be precharged using either the Precharge Command or the Auto-Precharge function. When a Read or a Write Command is given to the DDR2 SDRAM, the  $\overline{\text{CAS}}$  timing accepts one extra address, column address A10, to allow the active bank to automatically begin precharge at the earliest possible moment during the burst read or write cycle. If A10 is LOW when the Read or Write Command is issued, then normal Read or Write burst operation is executed and the bank remains active at the completion of the burst sequence. If A10 is HIGH when the Read or Write Command is issued, then the Auto-Precharge function is enabled. During Auto-Precharge, a Read Command will execute as normal with the exception that the active bank will begin to precharge

internally on the rising edge which is  $\overline{\text{CAS}}$  Latency (CL) clock cycles before the end of the read burst. Auto-Precharge is also implemented for Write Commands. The Precharge operation engaged by the Auto-Precharge command will not begin until the last data of the write burst sequence is properly stored in the memory array. This feature allows the precharge operation to be partially or completely hidden during burst read cycles (dependent upon  $\overline{\text{CAS}}$  Latency) thus improving system performance for random data access. The RAS lockout circuit internally delays the Precharge operation until the array restore operation has been completed so that the Auto-Precharge command may be issued with any read or write command.

#### 3.23.1 Read with Auto-Precharge

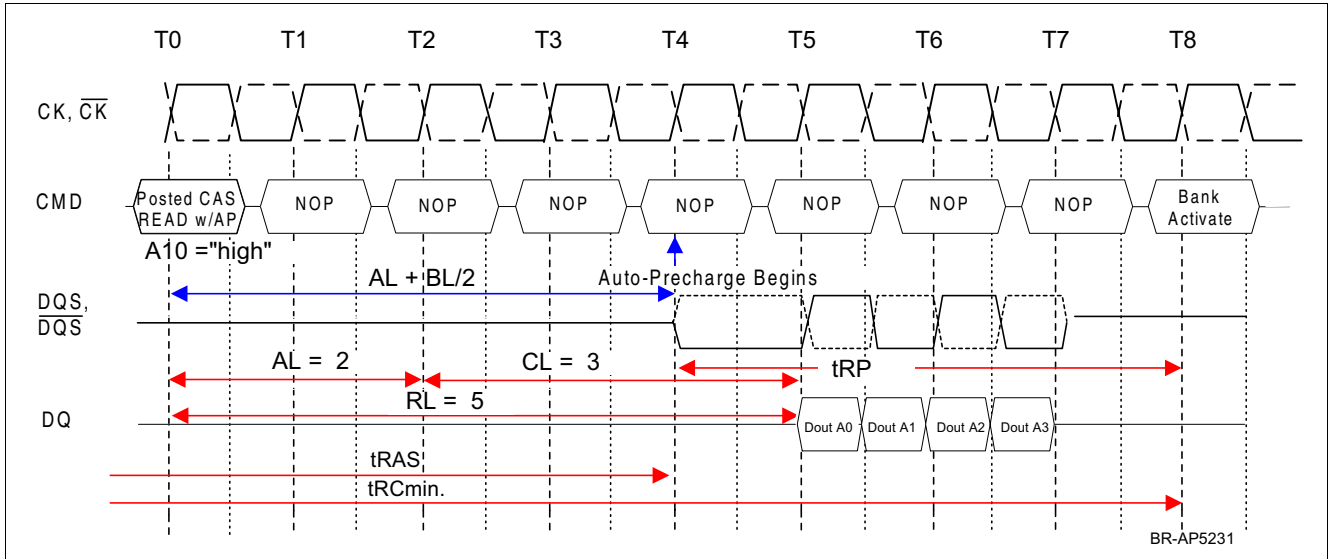
If A10 is 1 when a Read Command is issued, the Read with Auto-Precharge function is engaged. The DDR2 SDRAM starts an Auto-Precharge operation on the rising edge which is  $(AL + BL/2)$  cycles later from the Read with AP command if  $t_{\text{RAS,MIN}}$  and  $t_{\text{RTP}}$  are satisfied. If  $t_{\text{RAS,MIN}}$  is not satisfied at the edge, the start point of Auto-Precharge operation will be delayed until  $t_{\text{RAS,MIN}}$  is satisfied. If  $t_{\text{RTP,MIN}}$  is not satisfied at the edge, the start point of Auto-Precharge operation will be delayed until  $t_{\text{RTP,MIN}}$  is satisfied.

In case the internal precharge is pushed out by  $t_{\text{RTP}}$ ,  $t_{\text{RP}}$  starts at the point where the internal precharge happens (not at the next rising clock edge after this event). So for BL = 4 the minimum time from Read with

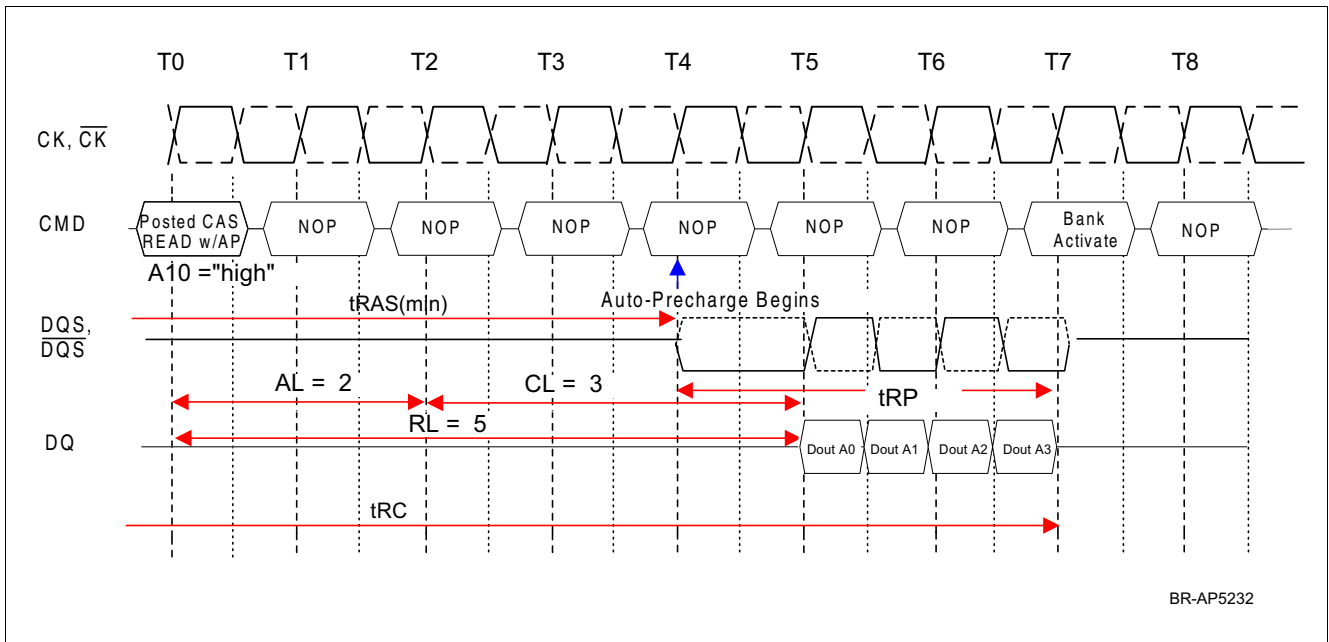
Auto-Precharge to the next Activate command becomes  $AL + t_{\text{RTP}} + t_{\text{RP}}$ . For BL = 8 the time from Read with Auto-Precharge to the next Activate command is  $AL + 2 + t_{\text{RTP}} + t_{\text{RP}}$ . Note that  $(t_{\text{RTP}} + t_{\text{RP}})$  has to be rounded up to the next integer value. In any event internal precharge does not start earlier than two clocks after the last 4-bit prefetch.

A new bank active command may be issued to the same bank if the following two conditions are satisfied simultaneously:

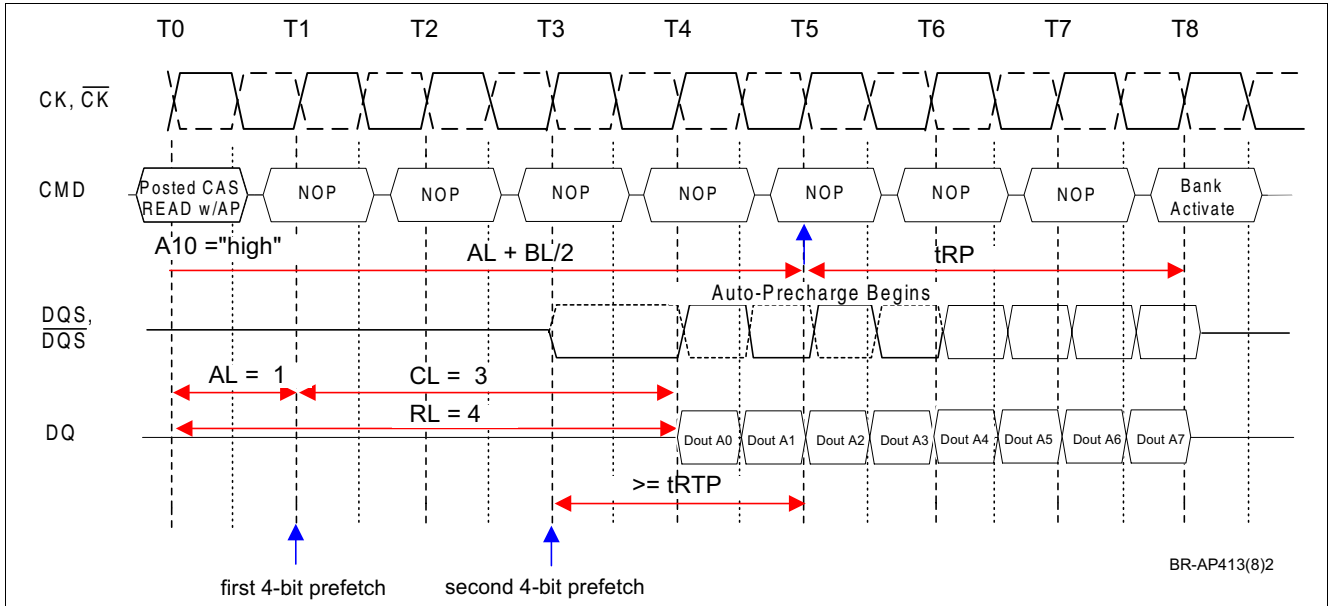
1. The  $\overline{\text{RAS}}$  precharge time ( $t_{\text{RP}}$ ) has been satisfied from the clock at which the Auto-Precharge begins.
2. The  $\overline{\text{RAS}}$  cycle time ( $t_{\text{RC}}$ ) from the previous bank activation has been satisfied.



**Figure 47 Read with Auto-Precharge Example 1, followed by an Activation to the Same Bank ( $t_{RC}$  Limit)**  
 $RL = 5$  ( $AL = 2$ ,  $CL = 3$ ),  $BL = 4$ ,  $t_{RTP} \leq 2$  CKs

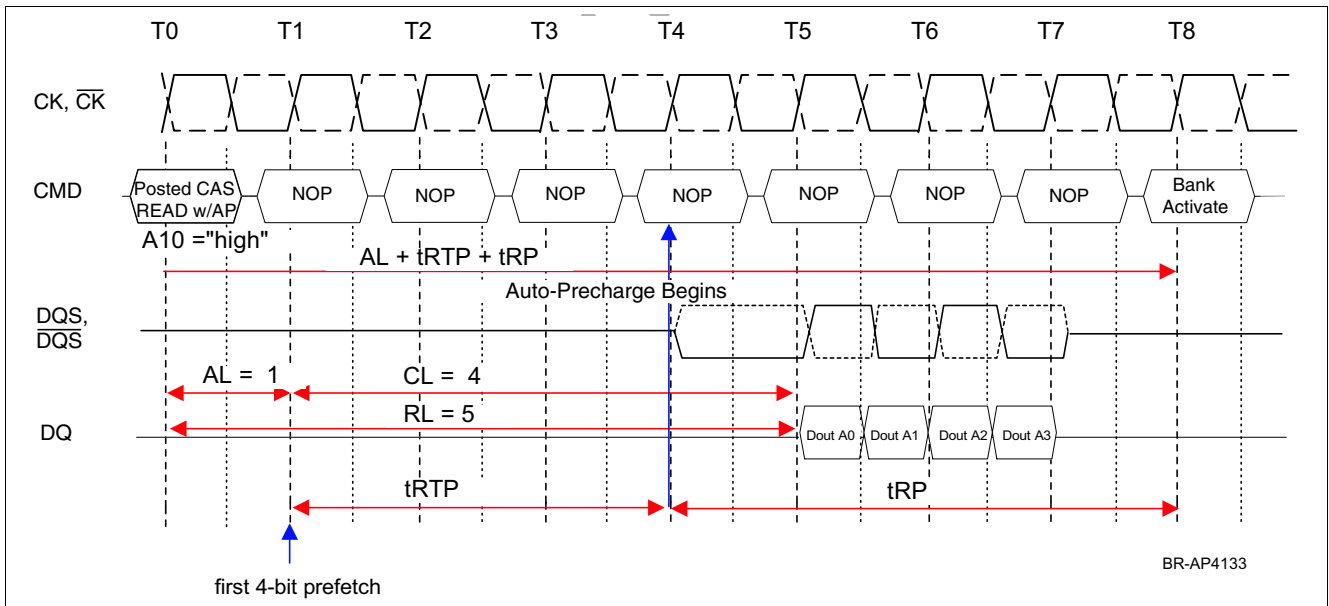


**Figure 48 Read with Auto-Precharge Example 2, followed by an Activation to the Same Bank ( $t_{RAS}$  Limit)**  
 $RL = 5$  ( $AL = 2$ ,  $CL = 3$ ),  $BL = 4$ ,  $t_{RTP} \leq 2$  CKs



**Figure 49 Read with Auto-Precharge Example 3, followed by an Activation to the Same Bank**

RL = 4 (AL = 1, CL = 3), BL = 8,  $t_{RTP} \leq 2$  CKs



**Figure 50 Read with Auto-Precharge Example 4, followed by an Activation to the Same Bank,**

RL = 5 (AL = 1, CL = 4), BL = 4,  $t_{RTP} = 3$  CKs

### 3.23.2 Write with Auto-Precharge

If A10 is HIGH when a Write Command is issued, the Write with Auto-Precharge function is engaged. The DDR2 SDRAM automatically begins precharge after the completion of the write burst plus the write recovery time delay (WR), programmed in the MRS register, as long as  $t_{RAS}$  is satisfied. The bank undergoing Auto-Precharge from the completion of the write burst may be reactivated if the following two conditions are satisfied.

1. The last data-in to bank activate delay time ( $t_{DAL} = WR + t_{RP}$ ) has been satisfied.
2. The RAS cycle time ( $t_{RC}$ ) from the previous bank activation has been satisfied.

In DDR2 SDRAM's the write recovery time delay (WR) has to be programmed into the MRS mode register. As long as the analog  $t_{WR}$  timing parameter is not violated, WR can be programmed between 2 and 6 clock cycles. Minimum Write to Activate command spacing to the same bank =  $WL + BL/2 + t_{DAL}$ .

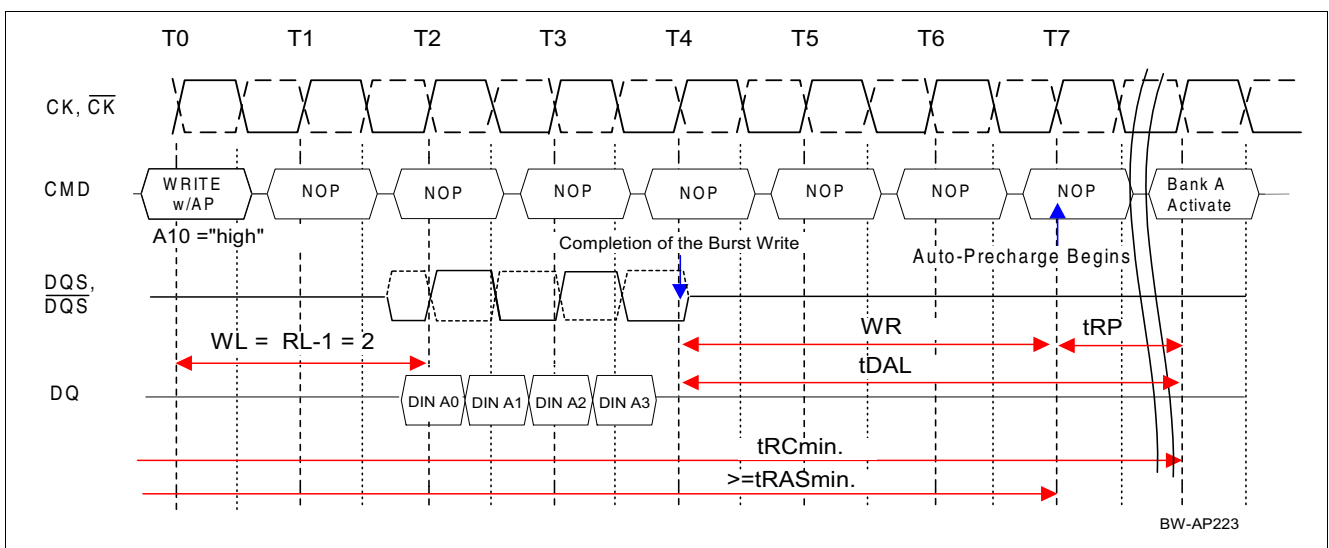


Figure 51 Write with Auto-Precharge Example 1 ( $t_{RC}$  Limit)

WL = 2,  $t_{DAL} = 6$  (WR = 3,  $t_{RP} = 3$ ), BL = 4

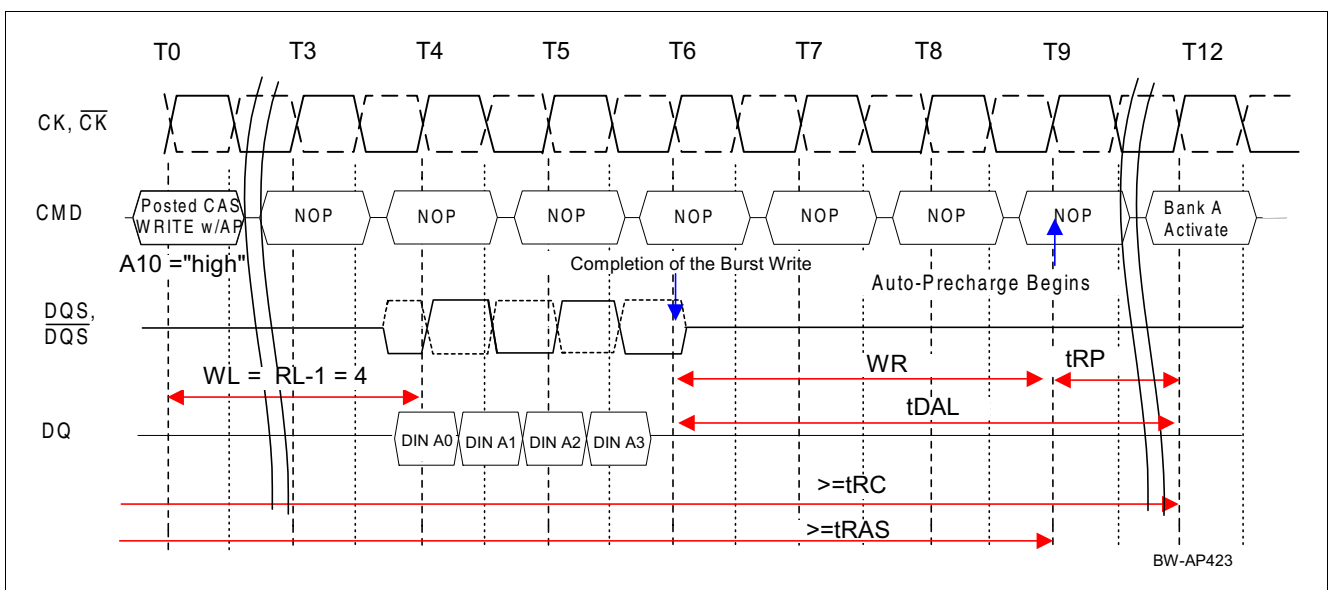


Figure 52 Write with Auto-Precharge Example 2 (WR +  $t_{RP}$  Limit)

WL = 4,  $t_{DAL} = 6$  (WR = 3,  $t_{RP} = 3$ ), BL = 4

### 3.23.3 Read or Write to Precharge Command Spacing Summary

The following table summarizes the minimum command delays between Read, Read w/AP, Write, Write w/AP to the Precharge commands to the same banks and Precharge-All commands.

**Table 19 Minimum Command Delays**

From Command	To Command	Minimum Delay between “From Command” to “To Command”	Unit	Note
READ	PRECHARGE (to same banks as READ)	$AL + BL/2 + \max(t_{RTP}, 2) - 2 \times t_{CK}$	$t_{CK}$	1)2)
	PRECHARGE-ALL	$AL + BL/2 + \max(t_{RTP}, 2) - 2 \times t_{CK}$	$t_{CK}$	1)2)
READ w/AP	PRECHARGE (to same banks as READ w/AP)	$AL + BL/2 + \max(t_{RTP}, 2) - 2 \times t_{CK}$	$t_{CK}$	1)2)
	PRECHARGE-ALL	$AL + BL/2 + \max(t_{RTP}, 2) - 2 \times t_{CK}$	$t_{CK}$	1)2)
WRITE	PRECHARGE (to same banks as WRITE)	$WL + BL/2 + t_{WR}$	$t_{CK}$	2)
	PRECHARGE-ALL	$WL + BL/2 + t_{WR}$	$t_{CK}$	2)
WRITE w/AP	PRECHARGE (to same banks as WRITE w/AP)	$WL + BL/2 + WR$	$t_{CK}$	2)
	PRECHARGE-ALL	$WL + BL/2 + WR$	$t_{CK}$	2)
PRECHARGE	PRECHARGE (to same banks as PRECHARGE)	1	$t_{CK}$	2)
	PRECHARGE-ALL	1	$t_{CK}$	2)
PRECHARGE-ALL	PRECHARGE	1	$t_{CK}$	2)
	PRECHARGE-ALL	1	$t_{CK}$	2)

1)  $RU\{t_{RTP}(ns) / t_{CK}(ns)\}$  must be used, where RU stands for “Round Up”

2) For a given bank, the precharge period should be counted from the latest precharge command, either one bank precharge or precharge-all, issued to that bank. The precharge period is satisfied after  $t_{RP,all}$  depending on the latest precharge command issued to that bank

### 3.23.4 Concurrent Auto-Precharge

DDR2 devices support the “Concurrent Auto-Precharge” feature. A Read with Auto-Precharge enabled, or a Write with Auto-Precharge enabled, may be followed by any command to the other bank, as long as that command does not interrupt the read or write data transfer, and all other related limitations (e.g. contention between Read data and Write data must be avoided externally and on the internal data bus).

The minimum delay from a Read or Write command with Auto-Precharge enabled, to a command to a different bank, is summarized in the Command Delay Table. As defined, the  $WL = RL - 1$  for DDR2 devices which allows the command gap and corresponding data gaps to be minimized.

**Table 20 Command Delay Table**

From Command	To Command (different bank, non-interrupting command)	Minimum Delay with Concurrent Auto-Precharge Support	Unit	Note
WRITE w/AP	Read or Read w/AP	$(CL - 1) + (BL/2) + t_{WTR}$	$t_{CK}$	
	Write or Write w/AP	$BL/2$	$t_{CK}$	
	Precharge or Activate	1	$t_{CK}$	<sup>1)</sup>
Read w/AP	Read or Read w/AP	$BL/2$	$t_{CK}$	
	Write or Write w/AP	$BL/2 + 2$	$t_{CK}$	
	Precharge or Activate	1	$t_{CK}$	<sup>1)</sup>

1) This rule only applies to a selective Precharge command to another bank, a Precharge-All command is illegal

### 3.24 Refresh

DDR2 SDRAM requires a refresh of all rows in any rolling 64 ms interval. The necessary refresh can be generated in one of two ways: by explicit Auto-Refresh commands or by an internally timed Self-Refresh mode.

#### 3.24.1 Auto-Refresh Command

Auto-Refresh is used during normal operation of the DDR2 SDRAM's. This command is non persistent, so it must be issued each time a refresh is required. The refresh addressing is generated by the internal refresh controller. This makes the address bits “don't care” during an Auto-Refresh command. The DDR2 SDRAM requires Auto-Refresh cycles at an average periodic interval of  $t_{REFI.MAX}$ .

When  $\overline{CS}$ ,  $\overline{RAS}$  and  $\overline{CAS}$  are held LOW and  $\overline{WE}$  HIGH at the rising edge of the clock, the chip enters the Auto-Refresh mode. All banks of the SDRAM must be precharged and idle for a minimum of the precharge time ( $t_{RP}$ ) before the Auto-Refresh Command can be applied. An internal address counter supplies the addresses during the refresh cycle. No control of the

external address bus is required once this cycle has started.

When the refresh cycle has completed, all banks of the SDRAM will be in the precharged (idle) state. A delay between the Auto-Refresh Command and the next Activate Command or subsequent Auto-Refresh Command must be greater than or equal to the Auto-Refresh cycle time ( $t_{RFC}$ ).

To allow for improved efficiency in scheduling and switching between tasks, some flexibility in the absolute refresh interval is provided. A maximum of eight Auto-Refresh commands can be posted to any given DDR2 SDRAM, meaning that the maximum absolute interval between any Auto-Refresh command and the next Auto-Refresh command is  $9 \times t_{REFI}$ .

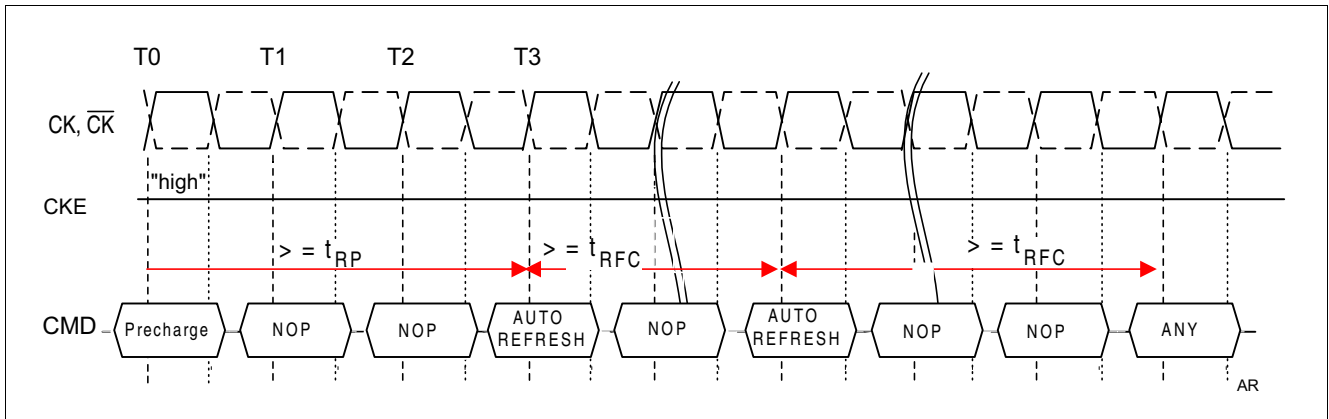


Figure 53 Auto Refresh Timing

### 3.24.2 Self-Refresh Command

The Self-Refresh command can be used to retain data, even if the rest of the system is powered down. When in the Self-Refresh mode, the DDR2 SDRAM retains data without external clocking. The DDR2 SDRAM device has a built-in timer to accommodate Self-Refresh operation. The Self-Refresh Command is defined by having  $\overline{CS}$ ,  $\overline{RAS}$ ,  $\overline{CAS}$  and CKE held LOW with  $\overline{WE}$  HIGH at the rising edge of the clock. The device must be in idle state and ODT must be turned off before issuing Self Refresh command, by either driving ODT pin LOW or using EMRS(1) command. Once the command is registered, CKE must be held LOW to keep the device in Self-Refresh mode. The DLL is automatically disabled upon entering Self Refresh and is automatically enabled upon exiting Self Refresh. When the DDR2 SDRAM has entered Self-Refresh mode all of the external control signals, except CKE, are “don’t care”. The DRAM initiates a minimum of one Auto Refresh command internally within  $t_{CKE}$  period once it enters Self Refresh mode. The clock is internally disabled during Self-Refresh Operation to save power. The minimum time that the DDR2 SDRAM must remain in Self Refresh mode is  $t_{CKE}$ . The user may change the external clock frequency or halt the external clock one

clock after Self-Refresh entry is registered, however, the clock must be restarted and stable before the device can exit Self-Refresh operation.

The procedure for exiting Self Refresh requires a sequence of commands. First, the clock must be stable prior to CKE going back HIGH. Once Self-Refresh Exit command is registered, a delay of at least  $t_{XSNR}$  must be satisfied before a valid command can be issued to the device to allow for any internal refresh in progress. CKE must remain HIGH for the entire Self-Refresh exit period  $t_{XSRD}$  for proper operation. Upon exit from Self Refresh, the DDR2 SDRAM can be put back into Self Refresh mode after  $t_{XSNR}$  expires. NOP or deselect commands must be registered on each positive clock edge during the Self-Refresh exit interval  $t_{XSNR}$ . ODT should be turned off during  $t_{XSNR}$ .

The use of Self Refresh mode introduces the possibility that an internally timed refresh event can be missed when CKE is raised for exit from Self Refresh mode. Upon exit from Self Refresh, the DDR2 SDRAM requires a minimum of one extra auto refresh command before it is put back into Self Refresh Mode.

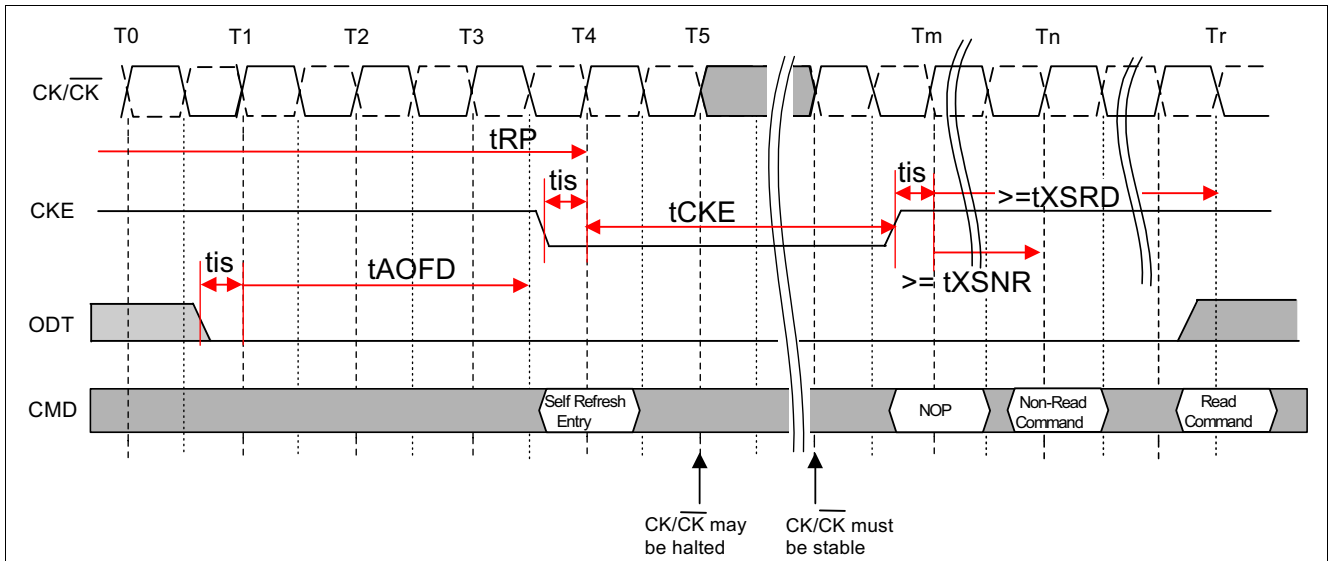


Figure 54 Self Refresh Timing

#### Notes

1. Device must be in the "All banks idle" state before entering Self Refresh mode.
2.  $t_{XSRD} (\geq 200 t_{CK})$  has to be satisfied for a Read or a Read with Auto-Precharge command.
3.  $t_{XSNR}$  has to be satisfied for any command except a Read or a Read with Auto-Precharge command
4. Since CKE is an SSTL input,  $V_{REF}$  must be maintained during Self Refresh.

### 3.25 Power-Down

Power-down is synchronously entered when CKE is registered LOW, along with NOP or Deselect command. CKE is not allowed to go LOW while mode register or extended mode register command time, or read or write operation is in progress. CKE is allowed to go LOW while any other operation such as row activation, Precharge, Auto-Precharge or Auto-Refresh is in progress, but power-down  $I_{DD}$  specification will not be applied until finishing those operations.

The DLL should be in a locked state when power-down is entered. Otherwise DLL should be reset after exiting power-down mode for proper read operation. DRAM design guarantees it's DLL in a locked state with any CKE intensive operations as long as DRAM controller complies with DRAM specifications.

If power-down occurs when all banks are precharged, this mode is referred to as Precharge Power-down; if power-down occurs when there is a row active in any bank, this mode is referred to as Active Power-down.

For Active Power-down two different power saving modes can be selected within the MRS register, address bit A12. When A12 is set to LOW this mode is referred as "standard active power-down mode" and a fast power-down exit timing defined by the  $t_{XARD}$  timing parameter can be used. When A12 is set to HIGH this mode is referred as a power saving "low power active power-down mode". This mode takes longer to exit from the power-down mode and the  $t_{XARDS}$  timing parameter has to be satisfied.

Entering power-down deactivates the input and output buffers, excluding CK,  $\overline{CK}$ , ODT and CKE. Also the DLL is disabled upon entering Precharge Power-down or slow exit active power-down, but the DLL is kept enabled during fast exit active power-down. In power-down mode, CKE LOW and a stable clock signal must be maintained at the inputs of the DDR2 SDRAM, and all other input signals are "Don't Care". Power-down duration is limited by 9 times  $t_{REF1}$  of the device.

### Power-Down Entry

Active Power-down mode can be entered after an Activate command. Precharge Power-down mode can be entered after a Precharge, Precharge-All or internal precharge command. It is also allowed to enter power-mode after an Auto-Refresh command or MRS / EMRS(1) command when  $t_{MRD}$  is satisfied.

Active Power-down mode entry is prohibited as long as a Read Burst is in progress, meaning CKE should be kept HIGH until the burst operation is finished. Therefore Active Power-Down mode entry after a Read or Read with Auto-Precharge command is allowed after  $RL + BL/2$  is satisfied.

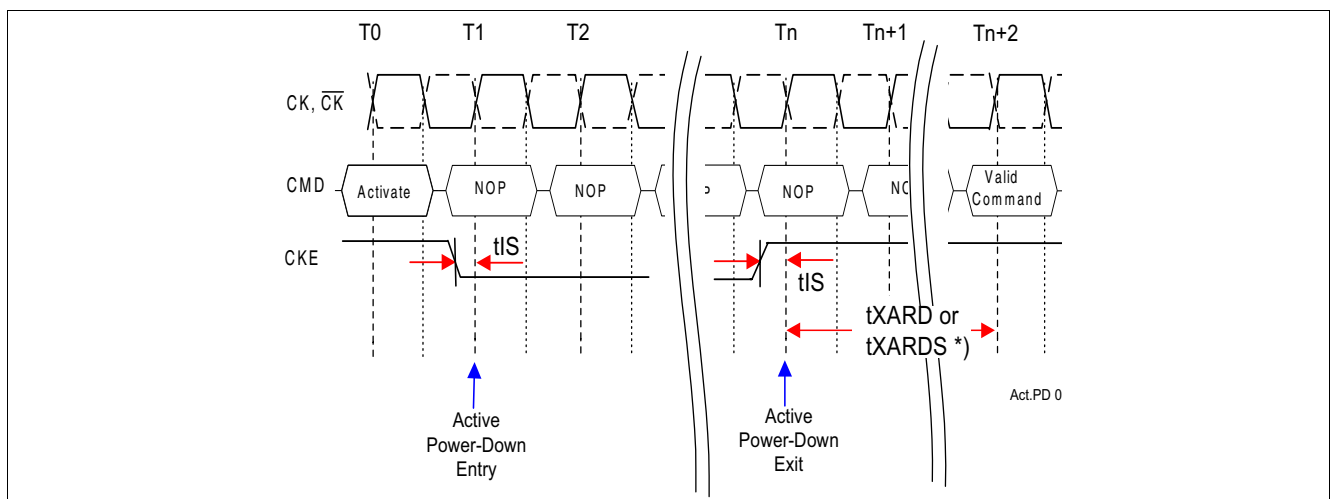
Active Power-down mode entry is prohibited as long as a Write Burst and the internal write recovery is in progress. In case of a write command, active power-down mode entry is allowed when  $WL + BL/2 + t_{WTR}$  is satisfied.

In case of a write command with Auto-Precharge, Power-down mode entry is allowed after the internal precharge command has been executed, which is  $WL + BL/2 + WR$  starting from the write with Auto-Precharge command. In this case the DDR2 SDRAM enters the Precharge Power-down mode.

### Power-Down Exit

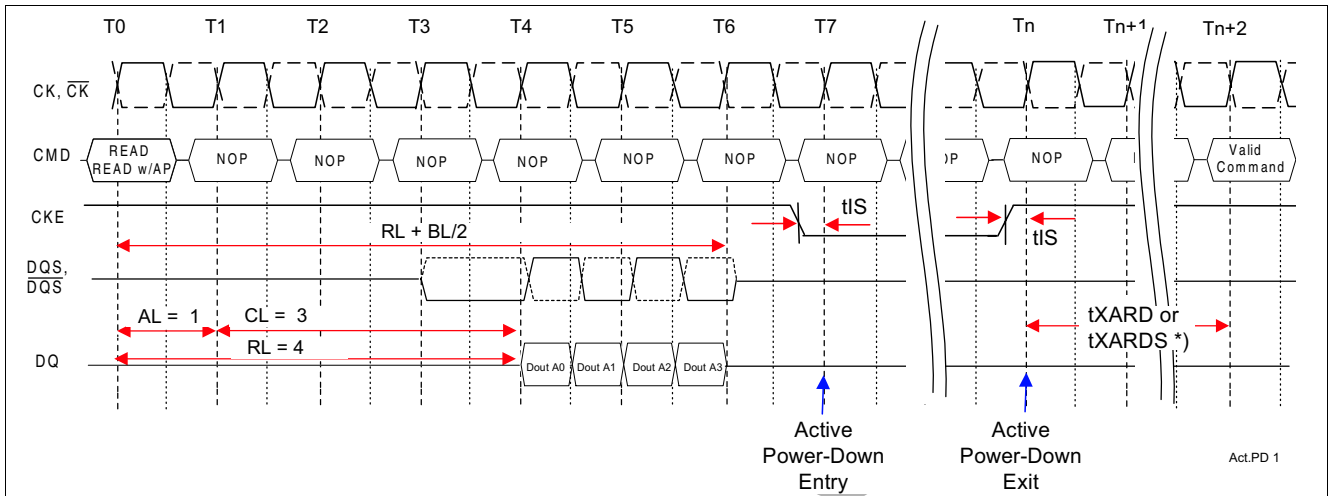
The power-down state is synchronously exited when CKE is registered HIGH (along with a NOP or Deselect command). A valid, executable command can be

applied with power-down exit latency,  $t_{XP}$ ,  $t_{XARD}$  or  $t_{XARDS}$ , after CKE goes HIGH. Power-down exit latencies are defined in [Chapter 7.2](#).



**Figure 55 Active Power-Down Mode Entry and Exit after an Activate Command**

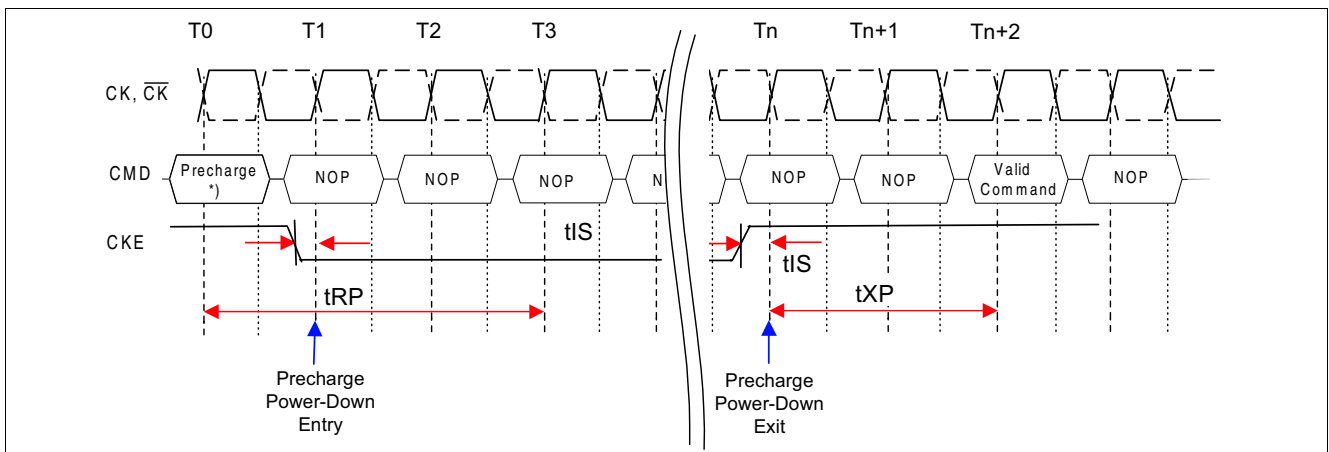
Note: Active Power-Down mode exit timing  $t_{XARD}$  ("fast exit") or  $t_{XARDS}$  ("slow exit") depends on the programmed state in the MR, address bit A12.



**Figure 56 Active Power-Down Mode Entry and Exit Example after a Read Command**

Note: Active Power-Down mode exit timing  $t_{XARD}$  ("fast exit") or  $t_{XARDS}$  ("slow exit") depends on the programmed state in the MR, address bit A12.

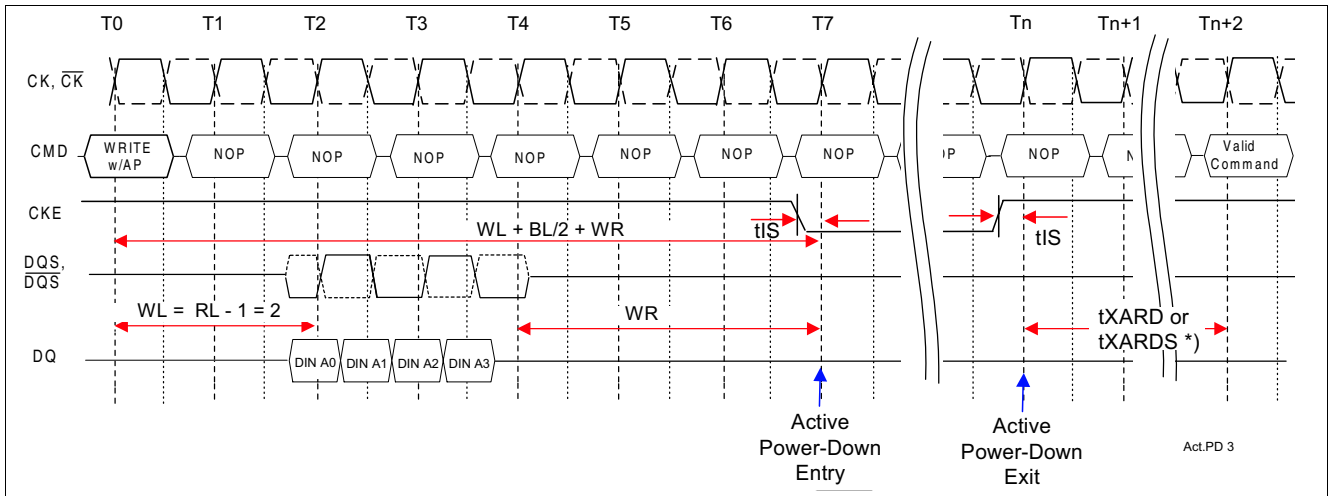
RL = 4 (AL = 1, CL = 3), BL = 4



**Figure 57 Active Power-Down Mode Entry and Exit Example after a Write Command**

WL = 2,  $t_{WTR} = 2$ , BL = 4

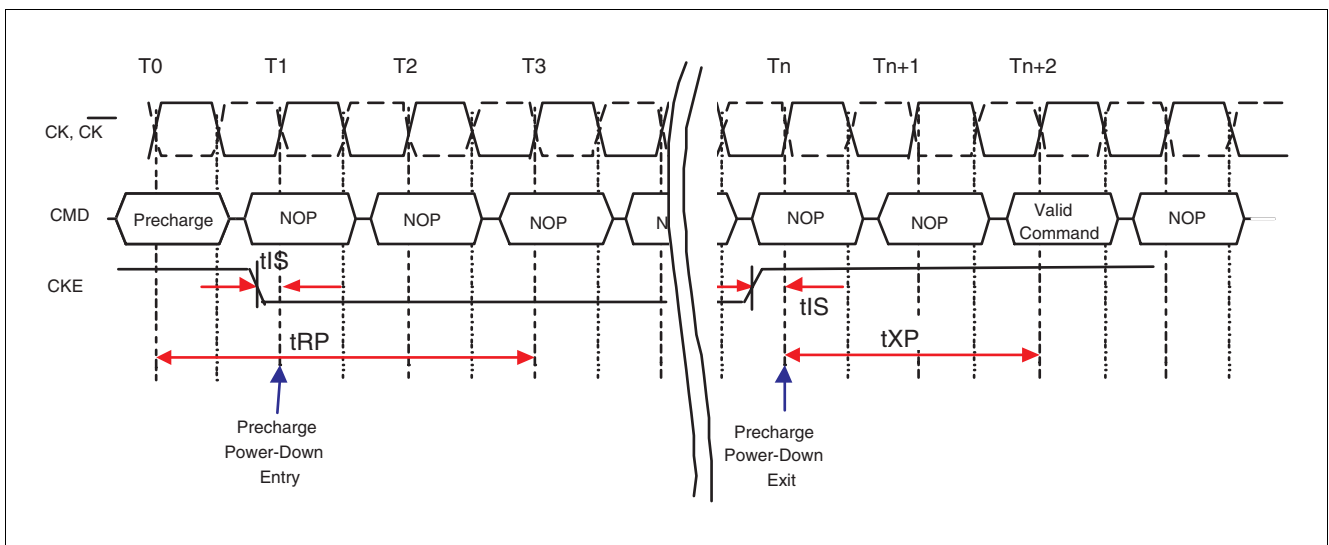
Note: Active Power-Down mode exit timing  $t_{XARD}$  ("fast exit") or  $t_{XARDS}$  ("slow exit") depends on the programmed state in the MR, address bit A12.



**Figure 58 Active Power-Down Mode Entry and Exit Example after a Write Command with AP**

WL = 2, WR = 3, BL = 4

Note: Active Power-Down mode exit timing  $t_{XARD}$  ("fast exit") or  $t_{XARDS}$  ("slow exit") depends on the programmed state in the MR, address bit A12. WR is the programmed value in the MRS mode register.



**Figure 59 Precharge Power Down Mode Entry and Exit**

Note: "Precharge" may be an external command or an internal precharge following Write with AP.

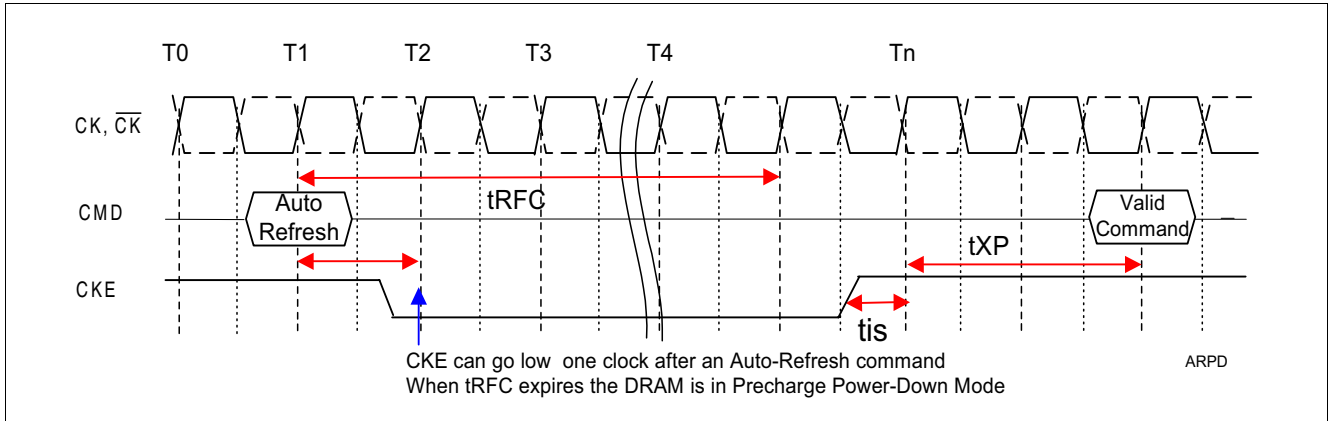


Figure 60 Auto-Refresh command to Power-Down entry

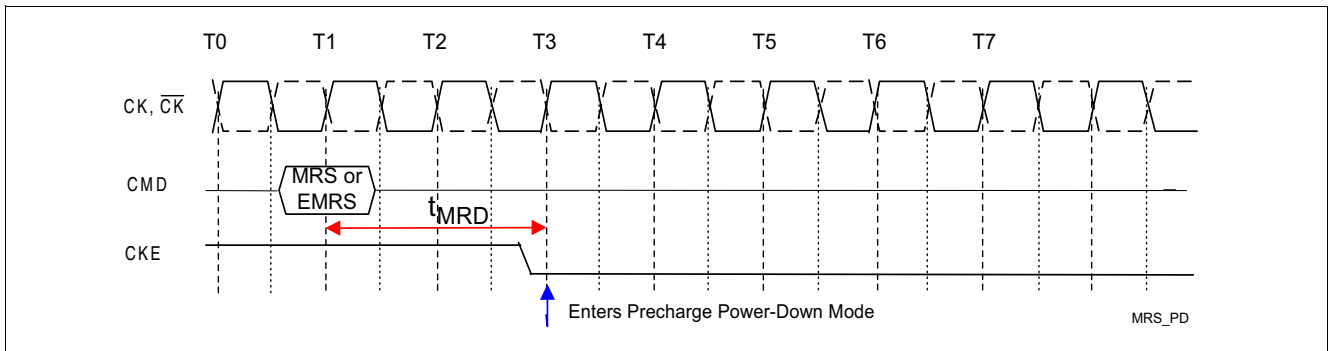


Figure 61 MRS, EMRS command to Power-Down entry

### 3.26 Other Commands

#### 3.26.1 No Operation Command

The No Operation Command (NOP) should be used in cases when the SDRAM is in a idle or a wait state. The purpose of the No Operation Command is to prevent the SDRAM from registering any unwanted commands between operations. A No Operation Command is

registered when  $\overline{CS}$  is LOW with  $\overline{RAS}$ ,  $\overline{CAS}$ , and  $\overline{WE}$  held HIGH at the rising edge of the clock. A No Operation Command will not terminate a previous operation that is still executing, such as a burst read or write cycle.

#### 3.26.2 Deselect Command

The Deselect Command performs the same function as a No Operation Command. Deselect Command occurs

when  $\overline{CS}$  is brought HIGH, the  $\overline{RAS}$ ,  $\overline{CAS}$ , and  $\overline{WE}$  signals become don't care.

### 3.27 Input Clock Frequency Change

During operation the DRAM input clock frequency can be changed under the following conditions:

- During Self-Refresh operation
- DRAM is in Precharge Power-down mode and ODT is completely turned off.

In the Precharge Power-down mode the DDR2-SDRAM has to be in Precharged Power-down mode and idle. ODT must be already turned off and CKE must be at a logic LOW state. After a minimum of two clock

cycles after  $t_{RP}$  and  $t_{AOFD}$  have been satisfied the input clock frequency can be changed. A stable new clock frequency has to be provided, before CKE can be changed to a HIGH logic level again. After  $t_{XP}$  has been satisfied a DLL RESET command via EMRS(1) has to be issued. During the following DLL re-lock period of 200 clock cycles, ODT must remain off. After the DLL-re-lock period the DRAM is ready to operate with the new clock frequency.

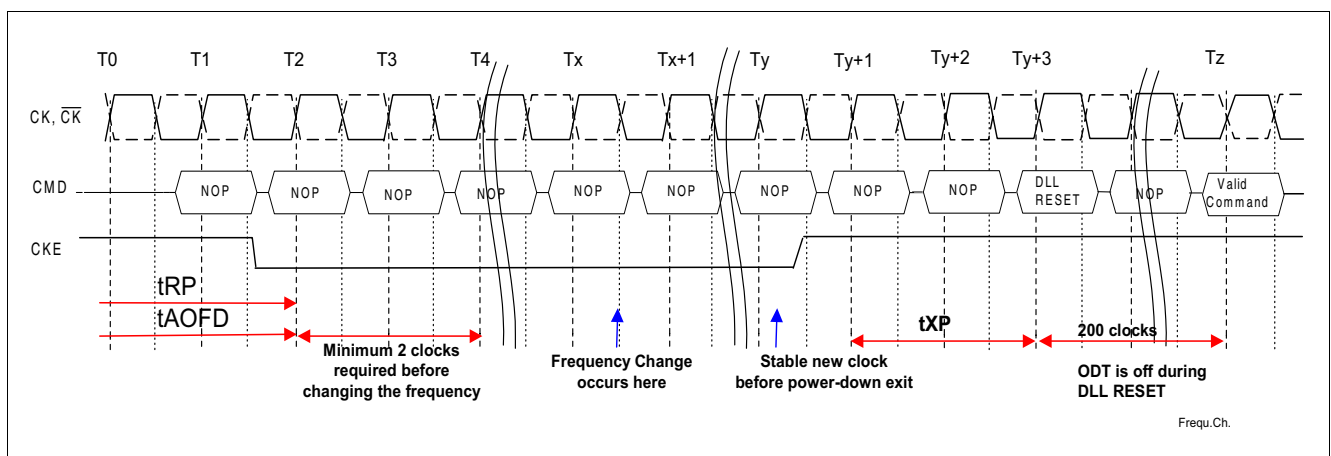


Figure 62 Input Frequency Change Example during Precharge Power-Down mode

### 3.28 Asynchronous CKE LOW Reset Event

In a given system, Asynchronous Reset event can occur at any time without prior knowledge. In this situation, memory controller is forced to drop CKE asynchronously LOW, immediately interrupting any valid operation. DRAM requires CKE to be maintained HIGH for all valid operations as defined in this data sheet. If CKE asynchronously drops LOW during any valid operation, the DRAM is not guaranteed to preserve the contents of the memory array. If this event

occurs, the memory controller must satisfy a time delay ( $t_{\text{DELAY}}$ ) before turning off the clocks. Stable clocks must exist at the input of DRAM before CKE is raised HIGH again. The DRAM must be fully re-initialized as described the initialization sequence (Power On and Initialization, step 4 through 13). DRAM is ready for normal operation after the initialization sequence. See Chapter 7 for  $t_{\text{DELAY}}$  specification.

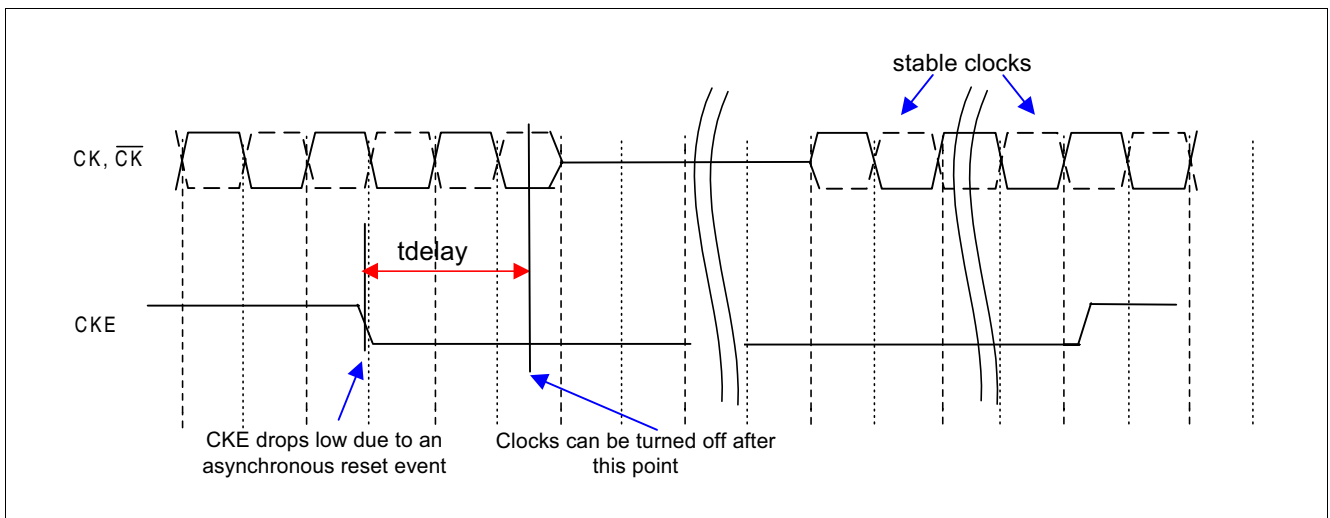


Figure 63 Asynchronous Low Reset Event

## 4 Truth tables

**Table 21 Command Truth Table**

Function	CKE		CS	RAS	CAS	WE	BA0 BA1	A[12:11]	A10	A[9:0]	Notes 1)2)3)
	Previous Cycle	Current Cycle									
(Extended) Mode Register Set	H	H	L	L	L	L	BA	OP Code			4)5)
Auto-Refresh	H	H	L	L	L	H	X	X	X	X	4)
Self-Refresh Entry	H	L	L	L	L	H	X	X	X	X	4)6)
Self-Refresh Exit	L	H	H	X	X	X	X	X	X	X	4)6)7)
			L	H	H	H					
Single Bank Precharge	H	H	L	L	H	L	BA	X	L	X	4)5)
Precharge all Banks	H	H	L	L	H	L	X	X	H	X	4)
Bank Activate	H	H	L	L	H	H	BA	Row Address			4)5)
Write	H	H	L	H	L	L	BA	Column	L	Column	4)5)8)
Write with Auto-Precharge	H	H	L	H	L	L	BA	Column	H	Column	4)5)8)
Read	H	H	L	H	L	H	BA	Column	L	Column	4)5)8)
Read with Auto-Precharge	H	H	L	H	L	H	BA	Column	H	Column	4)5)8)
No Operation	H	X	L	H	H	H	X	X	X	X	4)
Device Deselect	H	X	H	X	X	X	X	X	X	X	4)
Power Down Entry	H	L	H	X	X	X	X	X	X	X	4)9)
			L	H	H	H					
Power Down Exit	L	H	H	X	X	X	X	X	X	X	4)9)
			L	H	H	H					

- 1) The state of ODT does not affect the states described in this table. The ODT function is not available during Self Refresh.
- 2) "X" means "H or L (but a defined logic level)".
- 3) Operation that is not specified is illegal and after such an event, in order to guarantee proper operation, the DRAM must be powered down and then restarted through the specified initialization sequence before normal operation can continue.
- 4) All DDR2 SDRAM commands are defined by states of  $\overline{CS}$ ,  $\overline{WE}$ ,  $\overline{RAS}$ , CAS, and CKE at the rising edge of the clock.
- 5) Bank addresses BA[1:0] determine which bank is to be operated upon. For (E)MRS BA[1:0] selects an (Extended) Mode Register.
- 6)  $V_{REF}$  must be maintained during Self Refresh operation.
- 7) Self Refresh Exit is asynchronous.
- 8) Burst reads or writes at BL = 4 cannot be terminated. See [Chapter 3.19](#) for details.
- 9) The Power Down Mode does not perform any refresh operations. The duration of Power Down is therefore limited by the refresh requirements outlined in [Chapter 3.23](#)

**Table 22 Clock Enable (CKE) Truth Table for Synchronous Transitions**

Current State <sup>1)</sup>	CKE		Command (N) <sup>2)3)</sup> RAS, CAS, WE	Action (N) <sup>2)</sup>	Notes <sup>4)5)</sup>
	Previous Cycle <sup>6)</sup> (N-1)	Current Cycle <sup>6)</sup> (N)			
Power-Down	L	L	X	Maintain Power-Down	7)8)11)
	L	H	DESELECT or NOP	Power-Down Exit	7)9)10)11)
Self Refresh	L	L	X	Maintain Self Refresh	8)11)12)
	L	H	DESELECT or NOP	Self Refresh Exit	9)12)13)14)
Bank(s) Active	H	L	DESELECT or NOP	Active Power-Down Entry	7)9)10)11)15)
All Banks Idle	H	L	DESELECT or NOP	Precharge Power-Down Entry	9)10)11)15)
	H	L	AUTOREFRESH	Self Refresh Entry	7)11)14)16)
Any State other than listed above	H	H	Refer to the Command Truth Table		17)

- 1) Current state is the state of the DDR2 SDRAM immediately prior to clock edge N.
- 2) Command (N) is the command registered at clock edge N, and Action (N) is a result of Command (N)
- 3) The state of ODT does not affect the states described in this table. The ODT function is not available during Self Refresh. See [Chapter 3.23](#).
- 4) CKE must be maintained HIGH while the device is in OCD calibration mode.
- 5) Operation that is not specified is illegal and after such an event, in order to guarantee proper operation, the DRAM must be powered down and then restarted through the specified initialization sequence before normal operation can continue.
- 6) CKE (N) is the logic state of CKE at clock edge N; CKE (N-1) was the state of CKE at the previous clock edge.
- 7) The Power-Down Mode does not perform any refresh operations. The duration of Power-Down Mode is therefor limited by the refresh requirements
- 8) "X" means "don't care (including floating around  $V_{REF}$ )" in Self Refresh and Power Down. However ODT must be driven HIGH or LOW in Power Down if the ODT function is enabled (Bit A2 or A6 set to "1" in EMRS(1)).
- 9) All states and sequences not shown are illegal or reserved unless explicitly described elsewhere in this document.
- 10) Valid commands for Power-Down Entry and Exit are NOP and DESELECT only.
- 11)  $t_{CKE,MIN}$  of 3 clocks means CKE must be registered on three consecutive positive clock edges. CKE must remain at the valid input level the entire time it takes to achieve the 3 clocks of registration. Thus, after any CKE transition, CKE may not transition from its valid level during the time period of  $t_{IS} + 2xt_{CKE} + t_{IH}$ .
- 12)  $V_{REF}$  must be maintained during Self Refresh operation.
- 13) On Self Refresh Exit DESELECT or NOP commands must be issued on every clock edge occurring during the tXSNR period. Read commands may be issued only after  $t_{XSRD}$  (200 clocks) is satisfied.
- 14) Valid commands for Self Refresh Exit are NOP and DESELCT only.
- 15) Power-Down and Self Refresh can not be entered while Read or Write operations, (Extended) mode Register operations, Precharge or Refresh operations are in progress. See [Chapter 3.23](#) and [Chapter 3.22.2](#) for a detailed list of restrictions.
- 16) Self Refresh mode can only be entered from the All Banks Idle state.
- 17) Must be a legal command as defined in the Command Truth Table.

**Table 23 Data Mask (DM) Truth Table**

Name (Function)	DM	DQs	Note
Write Enable	L	Valid	1)
Write Inhibit	H	X	1)

- 1) Used to mask write data; provided coincident with the corresponding data.

## 5 AC & DC Operating Conditions

### 5.1 Absolute Maximum Ratings

**Table 24 Absolute Maximum Ratings**

Symbol	Parameter	Rating	Unit	Notes
$V_{DD}$	Voltage on $V_{DD}$ pin relative to $V_{SS}$	–1.0 to +2.3	V	1)2)
$V_{DDQ}$	Voltage on $V_{DDQ}$ pin relative to $V_{SS}$	–0.5 to +2.3	V	1)2)
$V_{DDL}$	Voltage on VDDL pin relative to $V_{SS}$	–0.5 to +2.3	V	1)2)
$V_{IN}, V_{OUT}$	Voltage on any pin relative to $V_{SS}$	–0.5 to +2.3	V	1)
$T_{STG}$	Storage Temperature	–55 to +100	°C	1)3)

- 1) Stresses greater than those listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.
- 2) When  $V_{DD}$  and  $V_{DDQ}$  and  $V_{DDL}$  are less than 500 mV;  $V_{REF}$  may be equal to or less than 300 mV.
- 3) Storage Temperature is the case surface temperature on the center/top side of the DRAM.

**Table 25 DRAM Component Operating Temperature Range**

Symbol	Parameter	Rating	Unit	Notes
$T_{OPER}$	Operating Temperature	0 to 95	°C	1)2)3)4)

- 1) Operating Temperature is the case surface temperature on the center / top side of the DRAM.
- 2) The operating temperature range are the temperatures where all DRAM specification will be supported. During operation, the DRAM case temperature must be maintained between 0 - 95 °C under all other specification parameters.
- 3) Above 85 °C case temperature the Auto-Refresh command interval has to be reduced to  $t_{REFI} = 3.9 \mu s$ .
- 4) When operating this product in the 85 °C to 95°C  $T_{CASE}$  temperature range, the High temperature Self Refresh has to be enabled by setting EMR(2) bit A7 to “1”. Note, when the high Temperature Self Refresh is enabled there is an increase of  $I_{DD6}$  by approximately 50%.

## 5.2 DC Characteristics

**Table 26 Recommended DC Operating Conditions (SSTL\_18)**

Symbol	Parameter	Rating			Unit	Note
		Min.	Typ.	Max.		
$V_{DD}$	Supply Voltage	1.7	1.8	1.9	V	1)
$V_{DDDL}$	Supply Voltage for DLL	1.7	1.8	1.9	V	1)
$V_{DDQ}$	Supply Voltage for Output	1.7	1.8	1.9	V	1)
$V_{REF}$	Input Reference Voltage	$0.49 \times V_{DDQ}$	$0.5 \times V_{DDQ}$	$0.51 \times V_{DDQ}$	V	2)3)
$V_{TT}$	Termination Voltage	$V_{REF} - 0.04$	$V_{REF}$	$V_{REF} + 0.04$	V	4)

- 1)  $V_{DDQ}$  tracks with  $V_{DD}$ ,  $V_{DDDL}$  tracks with  $V_{DD}$ . AC parameters are measured with  $V_{DD}$ ,  $V_{DDQ}$  and  $V_{DDDL}$  tied together.
- 2) The value of  $V_{REF}$  may be selected by the user to provide optimum noise margin in the system. Typically the value of  $V_{REF}$  is expected to be about  $0.5 \times V_{DDQ}$  of the transmitting device and  $V_{REF}$  is expected to track variations in  $V_{DDQ}$ .
- 3) Peak to peak ac noise on  $V_{REF}$  may not exceed  $\pm 2\% V_{REF}$  (dc)
- 4)  $V_{TT}$  is not applied directly to the device.  $V_{TT}$  is a system supply for signal termination resistors, is expected to be set equal to  $V_{REF}$ , and must track variations in die dc level of  $V_{REF}$ .

**Table 27 ODT DC Electrical Characteristics**

Parameter / Condition	Symbol	Min.	Nom.	Max.	Unit	Note
Termination resistor impedance value for EMRS(1)[A6,A2] = [0,1]; 75 Ohm	Rtt1(eff)	60	75	90	$\Omega$	1)
Termination resistor impedance value for EMRS(1)[A6,A2] =[1,0]; 150 Ohm	Rtt2(eff)	120	150	180	$\Omega$	1)
Termination resistor impedance value for EMRS(1)(A6,A2)=[1,1]; 50 Ohm	Rtt3(eff)	40	50	60	$\Omega$	1)
Deviation of $V_M$ with respect to $V_{DDQ} / 2$	delta $V_M$	-6.00	—	+ 6.00	%	2)

- 1) Measurement Definition for Rtt(eff): Apply  $V_{IH(ac)}$  and  $V_{IL(ac)}$  to test pin separately, then measure current  $I(V_{IHac})$  and  $I(V_{ILac})$  respectively.  $Rtt(eff) = (V_{IH(ac)} - V_{IL(ac)}) / (I(V_{IHac}) - I(V_{ILac}))$ .
- 2) Measurement Definition for  $V_M$ : Turn ODT on and measure voltage ( $V_M$ ) at test pin (midpoint) with no load:  $delta V_M = ((2 \times V_M / V_{DDQ}) - 1) \times 100\%$

**Table 28 Input and Output Leakage Currents**

Symbol	Parameter / Condition	Min.	Max.	Unit	Note
IIL	Input Leakage Current; any input $0 V < V_{IN} < V_{DD}$	-2	+2	$\mu A$	1)
IOL	Output Leakage Current; $0 V < V_{OUT} < V_{DDQ}$	-5	+5	$\mu A$	2)

- 1) All other pins not under test = 0 V
- 2) DQ's, LDQS,  $\overline{LDQS}$ , UDQS,  $\overline{UDQS}$ , DQS,  $\overline{DQS}$ , RDQS,  $\overline{RDQS}$  are disabled and ODT is turned off

### 5.3 DC & AC Characteristics

DDR2 SDRAM pin timing are specified for either single ended or differential mode depending on the setting of the EMRS(1) "Enable  $\overline{DQS}$ " mode bit; timing advantages of differential mode are realized in system design. The method by which the DDR2 SDRAM pin timing are measured is mode dependent. In single ended mode, timing relationships are measured

relative to the rising or falling edges of  $\overline{DQS}$  crossing at  $V_{REF}$ . In differential mode, these timing relationships are measured relative to the crosspoint of  $\overline{DQS}$  and its complement,  $\overline{DQS}$ . This distinction in timing methods is verified by design and characterization but not subject to production test. In single ended mode, the  $\overline{DQS}$  (and  $\overline{RDQS}$ ) signals are internally disabled and don't care.

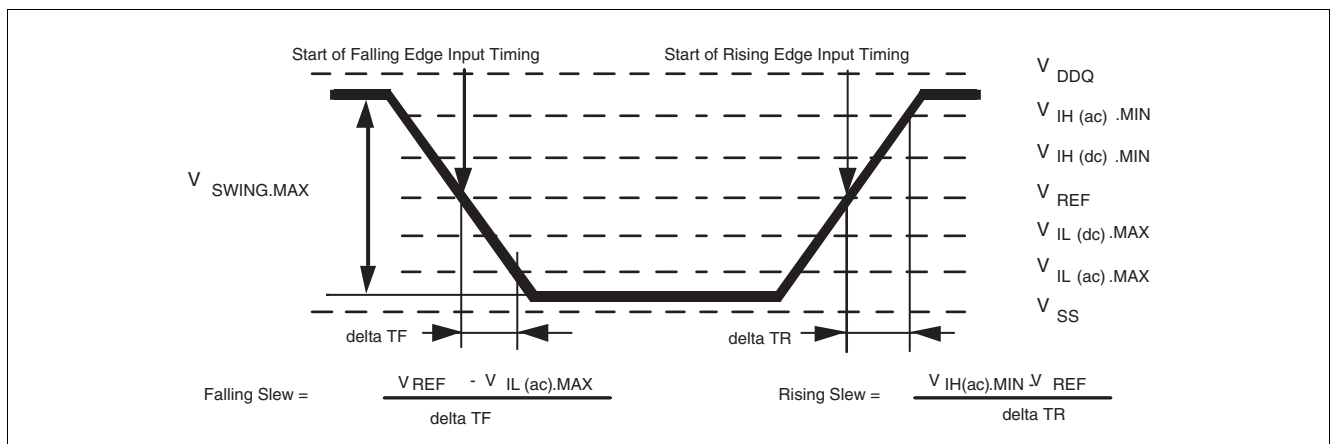
**Table 29 DC & AC Logic Input Levels**

Symbol	Parameter	DDR2-400 & DDR2-533		DDR2-667 & DDR2-800		Unit
		Min.	Max.	Min.	Max.	
$V_{IH(dc)}$	DC input logic high	$V_{REF} + 0.125$	$V_{DDQ} + 0.3$	$V_{REF} + 0.125$	$V_{DDQ} + 0.3$	V
$V_{IL(dc)}$	DC input low	-0.3	$V_{REF} - 0.125$	-0.3	$V_{REF} - 0.125$	V
$V_{IH(ac)}$	AC input logic high	$V_{REF} + 0.250$	—	$V_{REF} + 0.200$	—	V
$V_{IL(ac)}$	AC input low	—	$V_{REF} - 0.250$	—	$V_{REF} - 0.200$	V

**Table 30 Single-ended AC Input Test Conditions**

Symbol	Condition	Value	Unit	Note
$V_{REF}$	Input reference voltage	$0.5 \times V_{DDQ}$	V	1)
$V_{SWING.MAX}$	Input signal maximum peak to peak swing	1.0	V	1)
SLEW	Input signal minimum Slew Rate	1.0	V / ns	2)3)

- 1) Input waveform timing is referenced to the input signal crossing through the  $V_{REF}$  level applied to the device under test.
- 2) The input signal minimum Slew Rate is to be maintained over the range from  $V_{IH(ac).MIN}$  to  $V_{REF}$  for rising edges and the range from  $V_{REF}$  to  $V_{IL(ac).MAX}$  for falling edges as shown in [Figure 64](#).
- 3) AC timings are referenced with input waveforms switching from  $V_{IL(ac)}$  to  $V_{IH(ac)}$  on the positive transitions and  $V_{IH(ac)}$  to  $V_{IL(ac)}$  on the negative transitions.

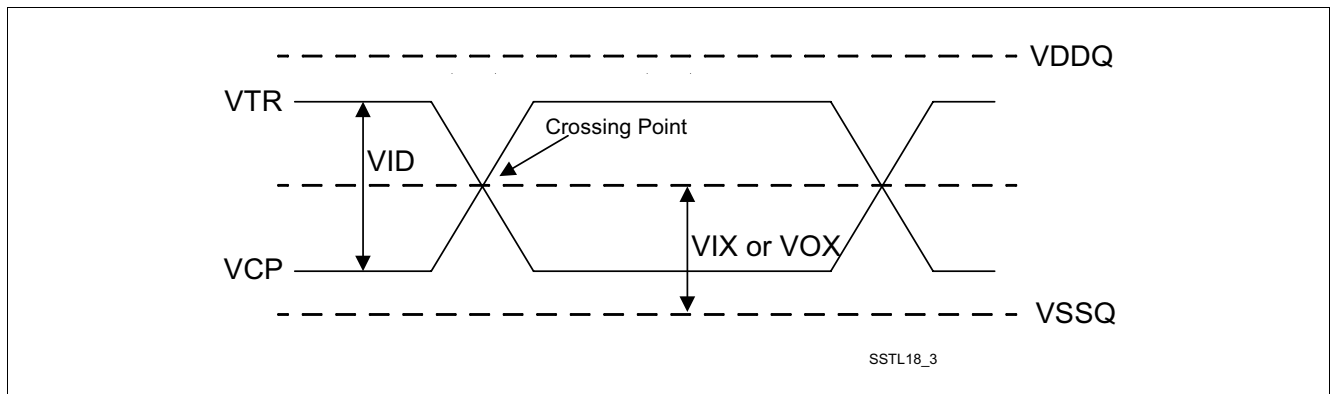


**Figure 64 Single-ended AC Input Test Conditions Diagram**

**Table 31 Differential DC and AC Input and Output Logic Levels**

Symbol	Parameter	Min.	Max.	Unit	Note
$V_{IN(dc)}$	DC input signal voltage	-0.3	$V_{DDQ} + 0.3$	—	1)
$V_{ID(dc)}$	DC differential input voltage	0.25	$V_{DDQ} + 0.6$	—	2)
$V_{ID(ac)}$	AC differential input voltage	0.5	$V_{DDQ} + 0.6$	V	3)
$V_{IX(ac)}$	AC differential cross point input voltage	$0.5 \times V_{DDQ} - 0.175$	$0.5 \times V_{DDQ} + 0.175$	V	4)
$V_{OX(ac)}$	AC differential cross point output voltage	$0.5 \times V_{DDQ} - 0.125$	$0.5 \times V_{DDQ} + 0.125$	V	5)

- 1)  $V_{IN(dc)}$  specifies the allowable DC execution of each input of differential pair such as CK,  $\overline{CK}$ , DQS,  $\overline{DQS}$  etc.
- 2)  $V_{ID(dc)}$  specifies the input differential voltage  $V_{TR} - V_{CP}$  required for switching. The minimum value is equal to  $V_{IH(dc)} - V_{IL(dc)}$ .
- 3)  $V_{ID(ac)}$  specifies the input differential voltage  $V_{TR} - V_{CP}$  required for switching. The minimum value is equal to  $V_{IH(ac)} - V_{IL(ac)}$ .
- 4) The value of  $V_{IX(ac)}$  is expected to equal  $0.5 \times V_{DDQ}$  of the transmitting device and  $V_{IX(ac)}$  is expected to track variations in  $V_{DDQ}$ .  $V_{IX(ac)}$  indicates the voltage at which differential input signals must cross.
- 5) The value of  $V_{OX(ac)}$  is expected to equal  $0.5 \times V_{DDQ}$  of the transmitting device and  $V_{OX(ac)}$  is expected to track variations in  $V_{DDQ}$ .  $V_{OX(ac)}$  indicates the voltage at which differential input signals must cross.



**Figure 65 Differential DC and AC Input and Output Logic Levels Diagram**

## 5.4 Output Buffer Characteristics

**Table 32 SSTL\_18 Output DC Current Drive**

Symbol	Parameter	SSTL_18	Unit	Note
$I_{OH}$	Output Minimum Source DC Current	–13.4	mA	1)2)
$I_{OL}$	Output Minimum Sink DC Current	13.4	mA	2)3)

- 1)  $V_{DDQ} = 1.7$  V;  $V_{OUT} = 1.42$  V.  $(V_{OUT} - V_{DDQ}) / I_{OH}$  must be less than 21 Ohm for values of  $V_{OUT}$  between  $V_{DDQ}$  and  $V_{DDQ} - 280$  mV.
- 2) The values of  $I_{OH(dc)}$  and  $I_{OL(dc)}$  are based on the conditions given in 1) and 3). They are used to test drive current capability to ensure  $V_{IH,MIN}$  plus a noise margin and  $V_{IL,MAX}$  minus a noise margin are delivered to an SSTL\_18 receiver. The actual current values are derived by shifting the desired driver operating points along 21 Ohm load line to define a convenient current for measurement.
- 3)  $V_{DDQ} = 1.7$  V;  $V_{OUT} = 280$  mV.  $V_{OUT} / I_{OL}$  must be less than 21 Ohm for values of  $V_{OUT}$  between 0 V and 280 mV.

**Table 33 SSTL\_18 Output AC Test Conditions**

Symbol	Parameter	SSTL_18	Unit	Note
$V_{OH}$	Minimum Required Output Pull-up	$V_{TT} + 0.603$	V	1)
$V_{OL}$	Maximum Required Output Pull-down	$V_{TT} - 0.603$	V	1)
$V_{OTR}$	Output Timing Measurement Reference Level	$0.5 \times V_{DDQ}$	V	

- 1) SSTL\_18 test load for  $V_{OH}$  and  $V_{OL}$  is different from the referenced load described in [Chapter 8.1](#). The SSTL\_18 test load has a 20 Ohm series resistor additionally to the 25 Ohm termination resistor into  $V_{TT}$ . The SSTL\_18 definition assumes that  $\pm 335$  mV must be developed across the effectively 25 Ohm termination resistor ( $13.4$  mA  $\times$   $25$  Ohm =  $335$  mV). With an additional series resistor of 20 Ohm this translates into a minimum requirement of 603 mV swing relative to  $V_{TT}$ , at the output device ( $13.4$  mA  $\times$   $45$  Ohm =  $603$  mV).

**Table 34 OCD Default Characteristics**

Symbol	Description	Min.	Nominal	Max.	Unit	Note
—	Output Impedance	See <a href="#">Chapter 5.5</a>			Ohms	1)2)
—	Pull-up / Pull down mismatch	0	—	4	Ohms	1)2)3)
—	Output Impedance step size for OCD calibration	0	—	1.5	Ohms	4)
$S_{OUT}$	Output Slew Rate	1.5	—	5.0	V / ns	1)5)6)7)8)

- 1) Absolute Specifications ( $T_{OPER}$ ;  $V_{DD} = 1.8$  V  $\pm$  0.1 V;  $V_{DDQ} = 1.8$  V  $\pm$  0.1 V), altering OCD from default state no longer requires DRAM to meet timing, voltage and slew rate specifications on I/O's.
- 2) Impedance measurement condition for output source dc current:  $V_{DDQ} = 1.7$  V,  $V_{OUT} = 1420$  mV;  $(V_{OUT} - V_{DDQ}) / I_{OH}$  must be less than 23.4 ohms for values of  $V_{OUT}$  between  $V_{DDQ}$  and  $V_{DDQ} - 280$  mV. Impedance measurement condition for output sink dc current:  $V_{DDQ} = 1.7$  V;  $V_{OUT} = -280$  mV;  $V_{OUT} / I_{OL}$  must be less than 23.4 Ohms for values of  $V_{OUT}$  between 0 V and 280 mV.
- 3) Mismatch is absolute value between pull-up and pull-down, both measured at same temperature and voltage.
- 4) This represents the step size when the OCD is near 18 ohms at nominal conditions across all process parameters and represents only the DRAM uncertainty. A 0 Ohm value (no calibration) can only be achieved if the OCD impedance is  $18 \pm 0.75$  Ohms under nominal conditions.
- 5) Slew Rates according to [Chapter 8.2.1](#)  $V_{IL(ac)}$  to  $V_{IH(ac)}$  with the load specified in [Figure 72](#).
- 6) The absolute value of the Slew Rate as measured from DC to DC is equal to or greater than the Slew Rate as measured from AC to AC. This is verified by design and characterization but not subject to production test.
- 7) Timing skew due to DRAM output Slew Rate mis-match between  $DQS / \overline{DQS}$  and associated DQ's is included in  $t_{DQSQ}$  and  $t_{QHS}$  specification.
- 8) DRAM output Slew Rate specification applies to 400, 533 and 667 MHz speed bins.

## 5.5 Full Strength Output V-I Characteristics

DDR2 SDRAM output driver characteristics are defined for full strength default operation as selected by the EMRS(1) bits A[9:7] = '111'. **Figure 66** and **Figure 67** show the driver characteristics graphically and the tables show the same data suitable for input into simulation tools.

**Table 35 Full Strength Default Pull-up Driver Characteristics**

Voltage (V)	Pull-up Driver Current [mA]			
	Min. <sup>1)</sup>	IBIS Target low <sup>2)</sup>	IBIS Target high <sup>2)</sup>	Max. <sup>3)</sup>
0.0	0.00	0.00	0.00	0.00
0.1	-4.30	-5.55	-5.90	-7.95
0.2	-8.60	-11.10	-11.80	-15.90
0.3	-12.90	-16.00	-17.00	-23.85
0.4	-16.90	-20.30	-22.20	-31.80
0.5	-20.05	-24.00	-27.50	-39.75
0.6	-22.10	-27.20	-32.40	-47.70
0.7	-23.27	-29.80	-36.90	-55.55
0.8	-24.10	-31.90	-40.80	-62.95
0.9	-24.73	-33.40	-44.50	-69.55
1.0	-25.23	-34.60	-47.70	-75.35
1.1	-25.65	-35.50	-50.40	-80.35
1.2	-26.02	-36.20	-52.50	-84.55
1.3	-26.35	-36.80	-54.20	-87.95
1.4	-26.65	-37.20	-55.90	-90.70
1.5	-26.93	-37.70	-57.10	-93.00
1.6	-27.20	-38.00	-58.40	-95.05
1.7	-27.46	-38.40	-59.60	-97.05
1.8	—	-38.60	-60.80	-99.05
1.9	—	—	—	-101.05

1) The driver characteristics evaluation conditions are Minimum 95 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.7$  V, slow–slow process

2) The driver characteristics evaluation conditions are Nominal Default 25 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.8$  V, typical process

3) The driver characteristics evaluation conditions are Maximum 0 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.9$  V, fast–fast process

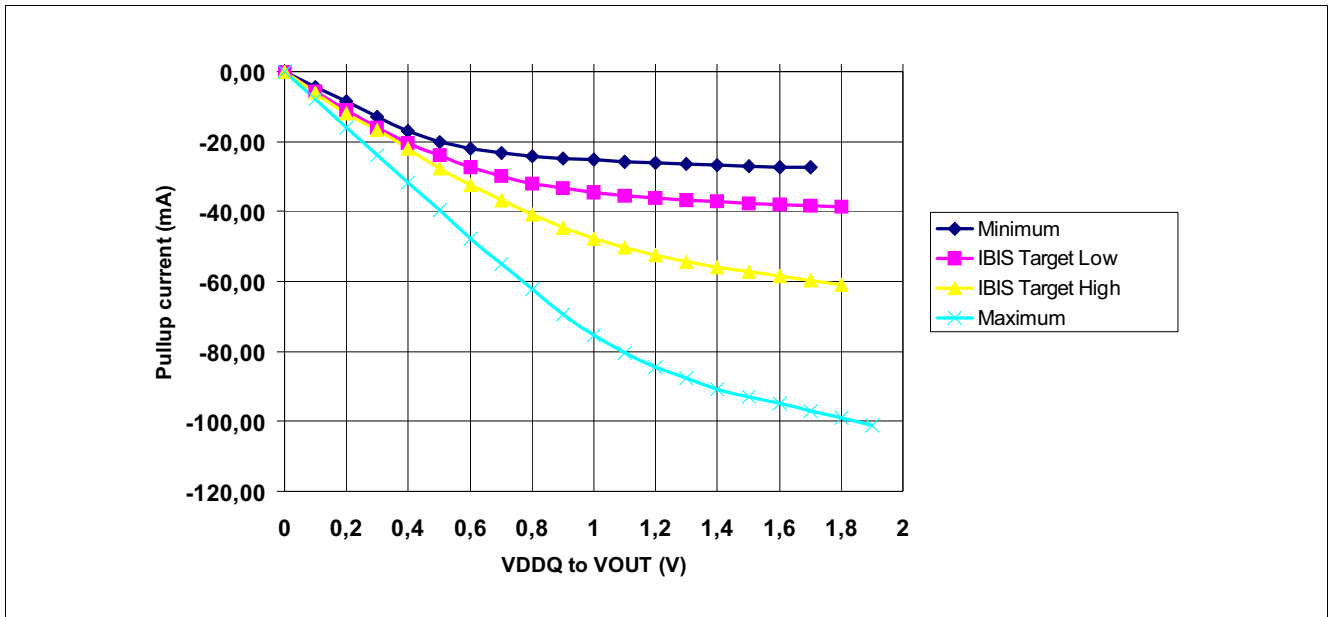


Figure 66 Full Strength Default Pull-up Driver Diagram

Table 36 Full Strength Default Pull-down Driver Characteristics

Voltage (V)	Pull-down Driver Current [mA]			
	Min. <sup>1)</sup>	Nominal Default low <sup>2)</sup>	Nominal Default high <sup>2)</sup>	Max. <sup>3)</sup>
0.0	0.00	0.00	0.00	0.00
0.1	4.30	5.65	5.90	7.95
0.2	8.60	11.30	11.80	15.90
0.3	12.90	16.50	16.80	23.85
0.4	16.90	21.20	22.10	31.80
0.5	20.05	25.00	27.60	39.75
0.6	22.10	28.30	32.40	47.70
0.7	23.27	30.90	36.90	55.05
0.8	24.10	33.00	40.90	62.95
0.9	24.73	34.50	44.60	69.55
1.0	25.23	35.50	47.70	75.35
1.1	25.65	36.10	50.40	80.35
1.2	26.02	36.60	52.60	84.55
1.3	26.35	36.90	54.20	87.95
1.4	26.65	37.10	55.90	90.70
1.5	26.93	37.40	57.10	93.00
1.6	27.20	37.60	58.40	95.05
1.7	27.46	37.70	59.60	97.05
1.8	—	37.90	60.90	99.05
1.9	—	—	—	101.05

1) The driver characteristics evaluation conditions are Minimum 95 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.7$  V, slow-slow process

2) The driver characteristics evaluation conditions are Nominal Default 25 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.8$  V, typical process

3) The driver characteristics evaluation conditions are Maximum 0 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.9$  V, fast-fast process

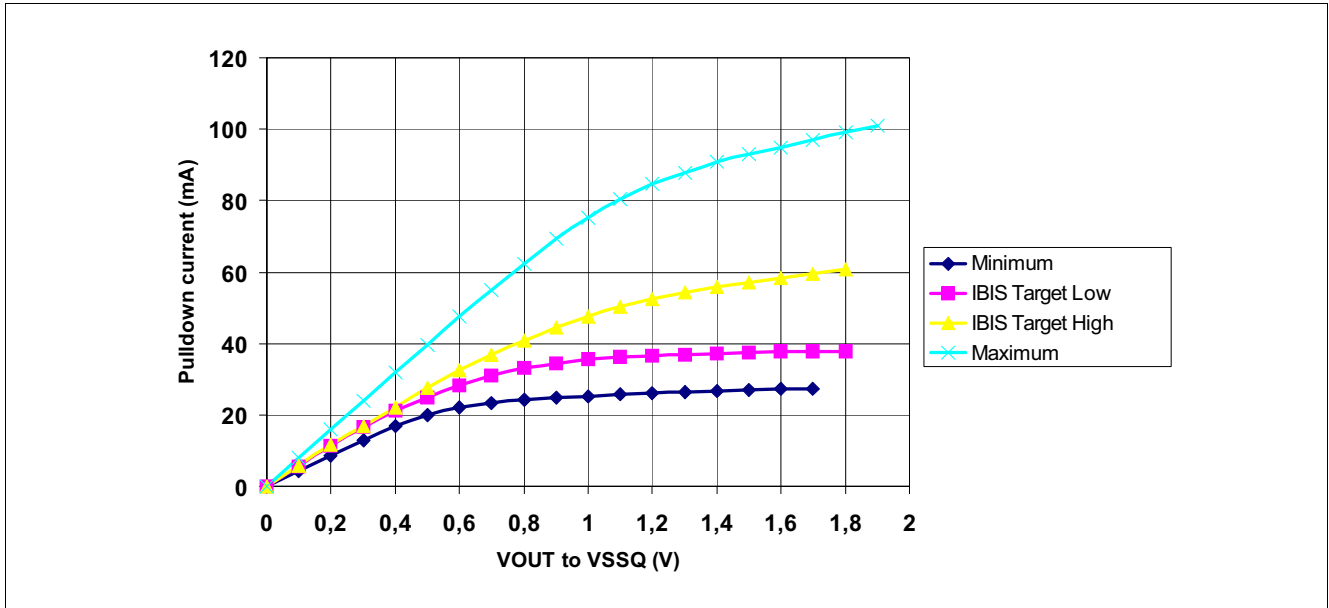


Figure 67 Full Strength Default Pull-down Driver Diagram

### 5.5.1 Calibrated Output Driver V-I Characteristics

DDR2 SDRAM output driver characteristics are defined for full strength calibrated operation as selected by the procedure outlined in the Off-Chip Driver (OCD) Impedance Adjustment. The [Table 37](#) and [Table 38](#) show the data in tabular format suitable for input into simulation tools. The nominal points represent a device at exactly 18 ohms. The nominal low and nominal high values represent the range that can be achieved with a maximum 1.5 ohms step size with no calibration error at the exact nominal conditions only (i.e. perfect calibration procedure, 1.5 ohm maximum step size guaranteed by specification). Real system calibration error needs to be added to these values. It must be understood that these V-I curves are represented here or in supplier IBIS models need to be adjusted to a wider range as a result of any system calibration error. Since this is a system specific phenomena, it cannot be quantified here. The values in the calibrated tables represent just the DRAM portion of uncertainty while

looking at one DQ only. If the calibration procedure is used, it is possible to cause the device to operate outside the bounds of the default device characteristics tables and figure. In such a situation, the timing parameters in the specification cannot be guaranteed. It is solely up to the system application to ensure that the device is calibrated between the minimum and maximum default values at all times. If this can't be guaranteed by the system calibration procedure, re-calibration policy and uncertainty with DQ to DQ variation, it is recommended that only the default values to be used. The nominal maximum and minimum values represent the change in impedance from nominal LOW and HIGH as a result of voltage and temperature change from the nominal condition to the maximum and minimum conditions. If calibrated at an extreme condition, the amount of variation could be as much as from the nominal minimum to the nominal maximum or vice versa.

**Table 37 Full Strength Calibrated Pull-down Driver Characteristics**

Voltage (V)	Calibrated Pull-down Driver Current [mA]				
	Nominal Minimum <sup>1)</sup> (21 Ohms)	Nominal Low <sup>2)</sup> (18.75 Ohms)	Nominal <sup>3)</sup> (18 ohms)	Nominal High <sup>2)</sup> (17.25 Ohms)	Nominal Maximum <sup>4)</sup> (15 Ohms)
0.2	9.5	10.7	11.5	11.8	13.3
0.3	14.3	16.0	16.6	17.4	20.0
0.4	18.7	21.0	21.6	23.0	27.0

- 1) The driver characteristics evaluation conditions are Nominal Minimum 95 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.7$  V, any process
- 2) The driver characteristics evaluation conditions are Nominal Low and Nominal High 25 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.8$  V, any process
- 3) The driver characteristics evaluation conditions are Nominal 25 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.8$  V, typical process
- 4) The driver characteristics evaluation conditions are Nominal Maximum 0 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.9$  V, any process

**Table 38 Full Strength Calibrated Pull-up Driver Characteristics**

Voltage (V)	Calibrated Pull-up Driver Current [mA]				
	Nominal Minimum <sup>1)</sup> (21 Ohms)	Nominal Low <sup>2)</sup> (18.75 Ohms)	Nominal (18 ohms) <sup>3)</sup>	Nominal High <sup>2)</sup> (17.25 Ohms)	Nominal Maximum <sup>4)</sup> (15 Ohms)
0.2	–9.5	–10.7	–11.4	–11.8	–13.3
0.3	–14.3	–16.0	–16.5	–17.4	–20.0
0.4	–18.3	–21.0	–21.2	–23.0	–27.0

- 1) The driver characteristics evaluation conditions are Nominal Minimum 95 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.7$  V, any process
- 2) The driver characteristics evaluation conditions are Nominal Low and Nominal High 25 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.8$  V, any process
- 3) The driver characteristics evaluation conditions are Nominal 25 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.8$  V, typical process
- 4) The driver characteristics evaluation conditions are Nominal Maximum 0 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.9$  V, any process

## 5.6 Reduced Output Drive Characteristics

A driver mode with reduced output drive characteristics can be selected by setting address bit A1 in the EMRS(1) extended mode register to 1.

**Table 39 Reduced Strength Default Pull-up Driver Characteristics**

Voltage (V)	Pull-up Driver Current [mA]			
	Min. <sup>1)</sup>	IBIS Target low <sup>2)</sup>	IBIS Target high <sup>2)</sup>	Max. <sup>3)</sup>
0.0	0.00	0.00	0.00	0.00
0.1	-1.72	-3.20	-3.70	-4.77
0.2	-3.44	-6.20	-7.22	-9.54
0.3	-5.16	-9.04	-10.56	-14.31
0.4	-6.76	-11.69	-13.75	-19.08
0.5	-8.02	-14.11	-16.78	-23.85
0.6	-8.84	-16.27	-19.61	-28.62
0.7	-9.31	-18.16	-22.20	-33.33
0.8	-9.64	-19.77	-24.50	-37.77
0.9	-9.89	-21.10	-26.46	-41.73
1.0	-10.09	-22.15	-28.07	-45.21
1.1	-10.26	-22.96	-29.36	-48.21
1.2	-10.41	-23.61	-30.40	-50.73
1.3	-10.54	-24.61	-31.24	-52.77
1.4	-10.66	-24.64	-31.93	-54.42
1.5	-10.77	-25.07	-32.51	-55.80
1.6	-10.88	-25.47	-33.01	-57.03
1.7	-10.98	-25.85	-33.46	-58.23
1.8	—	-26.21	-33.89	-59.43
1.9	—	—	—	-60.63

1) The driver characteristics evaluation conditions are Minimum 95 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.7$  V, slow–slow process

2) The driver characteristics evaluation conditions are Nominal Default 25 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.8$  V, typical process

3) The driver characteristics evaluation conditions are Maximum 0 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.9$  V, fast–fast process

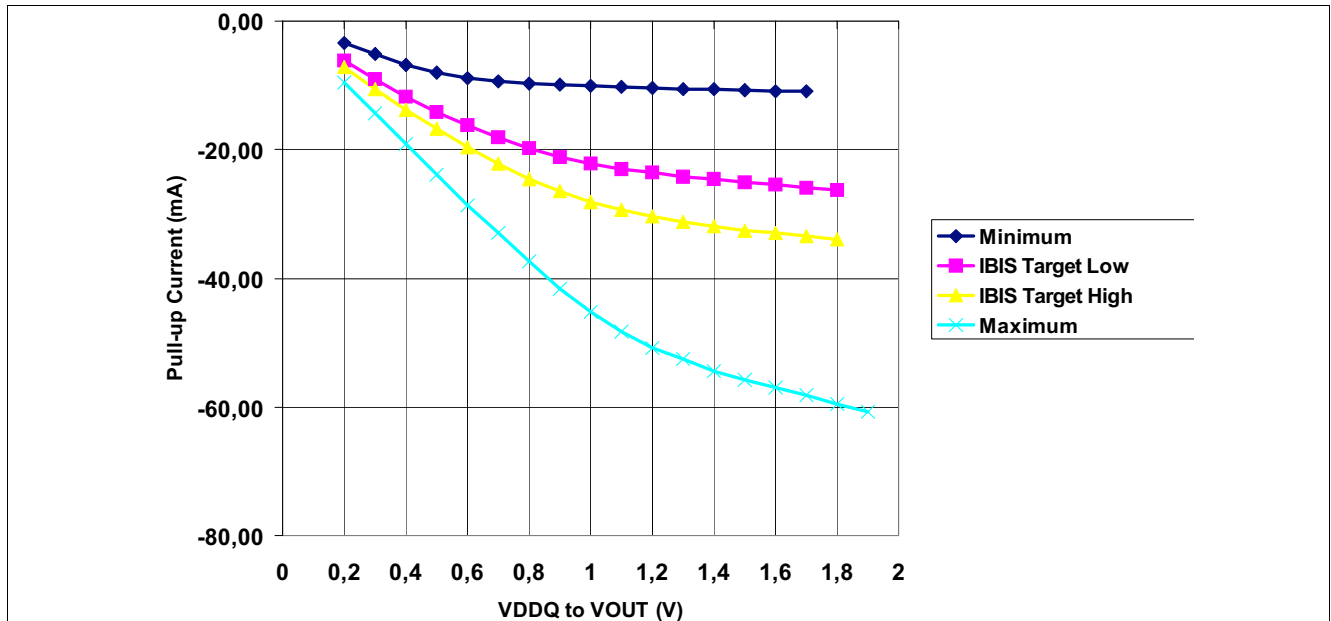


Figure 68 Reduced Strength Default Pull-up Driver Diagram

Table 40 Reduced Strength Default Pull-down Driver Characteristics

Voltage (V)	Pull-down Driver Current [mA]			
	Min. <sup>1)</sup>	IBIS Target low <sup>2)</sup>	IBIS Target high <sup>2)</sup>	Max. <sup>3)</sup>
0.0	0.00	0.00	0.00	0.00
0.1	1.72	3.24	4.11	4.77
0.2	3.44	6.25	8.01	9.54
0.3	5.16	9.03	11.67	14.31
0.4	6.76	11.52	15.03	19.08
0.5	8.02	13.66	18.03	23.85
0.6	8.84	15.41	20.61	28.62
0.7	9.31	16.77	22.71	33.33
0.8	9.64	17.74	24.35	37.77
0.9	9.89	18.83	25.56	41.73
1.0	10.09	18.80	26.38	45.21
1.1	10.26	19.06	26.90	48.21
1.2	10.41	19.23	27.24	50.73
1.3	10.54	19.35	27.47	52.77
1.4	10.66	19.46	27.64	54.42
1.5	10.77	19.56	27.78	55.80
1.6	10.88	19.65	27.89	57.03
1.7	10.98	19.73	27.97	58.23
1.8	—	19.80	28.02	59.43
1.9	—	—	—	60.63

1) The driver characteristics evaluation conditions are Minimum 95 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.7$  V, slow-slow process

2) The driver characteristics evaluation conditions are Nominal Default 25 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.8$  V, typical process

3) The driver characteristics evaluation conditions are Maximum 0 °C ( $T_{CASE}$ ),  $V_{DDQ} = 1.9$  V, fast-fast process

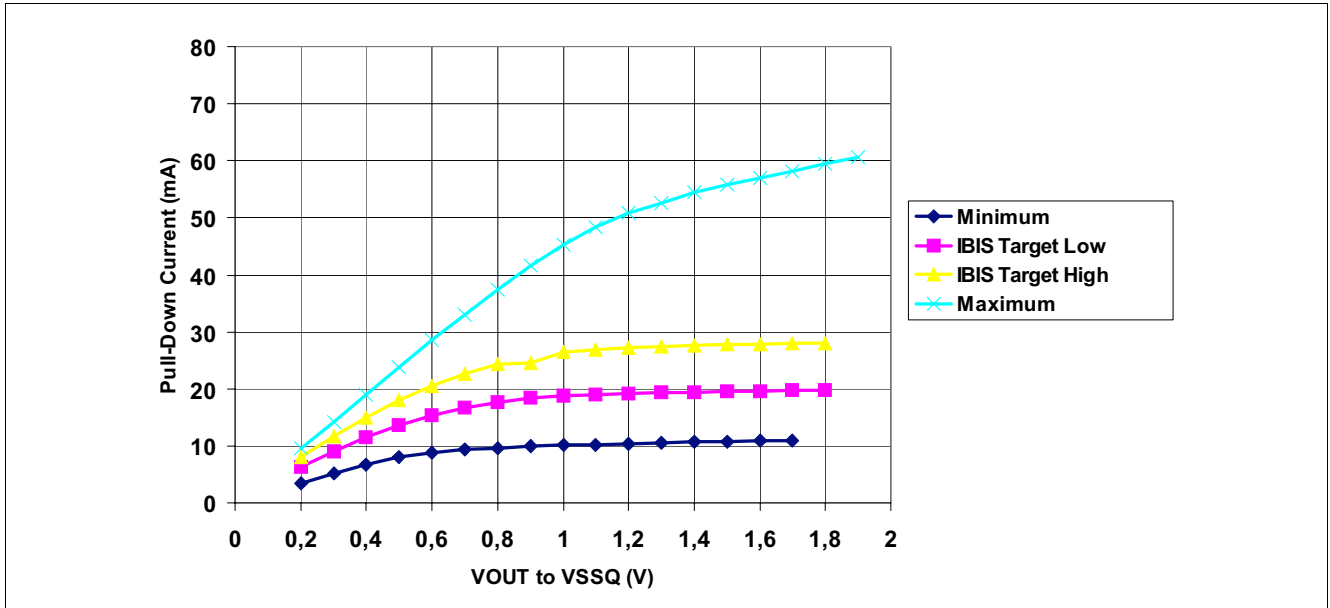


Figure 69 Reduced Strength Default Pull-down Driver Diagram

## 5.7 Input / Output Capacitance

Table 41 Input / Output Capacitance

Symbol	Parameter	DDR2-400 & DDR-2-533		DDR2-667		DDR2-800		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
CCK	Input capacitance, CK and $\overline{CK}$	1.0	2.0	1.0	2.0	1.0	2.0	pF
CDCK	Input capacitance delta, CK and $\overline{CK}$	—	0.25	—	0.25	—	0.25	pF
CI	Input capacitance, all other input-only pins	1.0	2.0	1.0	2.0	1.0	1.75	pF
CDI	Input capacitance delta, all other input-only pins	—	0.25	—	0.25	—	0.25	pF
CIO	Input/output capacitance, DQ, DM, DQS, $\overline{DQS}$ , RDQS, $\overline{RDQS}$	2.5	4.0	2.5	3.5	2.5	3.5	pF
CDIO	Input/output capacitance delta, DQ, DM, DQS, $\overline{DQS}$ , RDQS, $\overline{RDQS}$	—	0.5	—	0.5	—	0.5	pF

### 5.8 Power & Ground Clamp V-I Characteristics

Power and Ground clamps are provided on address (A[12:0], BA[1:0]),  $\overline{\text{RAS}}$ ,  $\overline{\text{CAS}}$ ,  $\overline{\text{CS}}$ ,  $\overline{\text{WE}}$ , and ODT pins. The V-I characteristics for pins with clamps is shown in [Table 42](#).

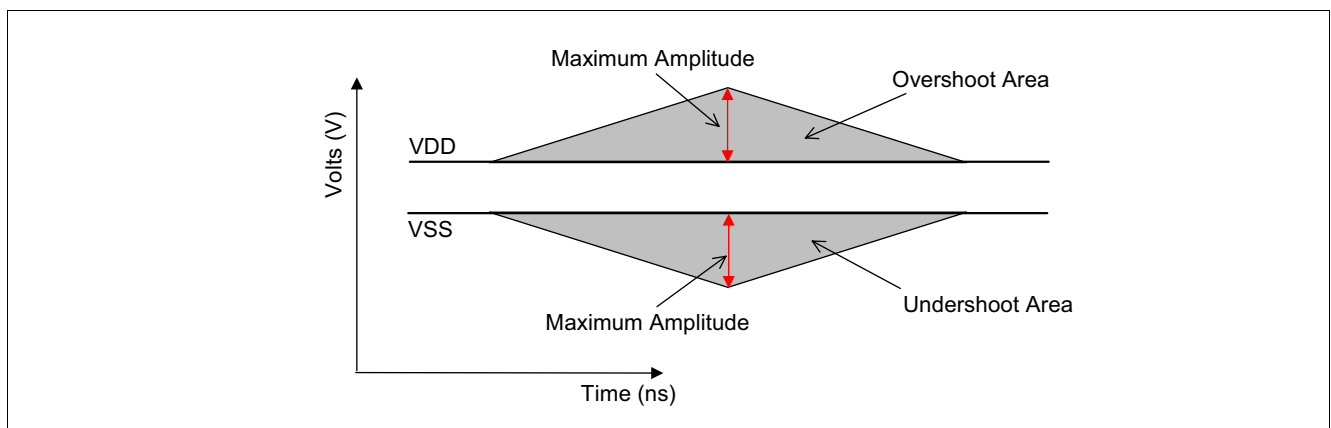
**Table 42 Power & Ground Clamp V-I Characteristics**

Voltage across clamp (V)	Minimum Power Clamp Current (mA)	Minimum Ground Clamp Current (mA)
0.0	0	0
0.1	0	0
0.2	0	0
0.3	0	0
0.4	0	0
0.5	0	0
0.6	0	0
0.7	0	0
0.8	0.1	0.1
0.9	1.0	1.0
1.0	2.5	2.5
1.1	4.7	4.7
1.2	6.8	6.8
1.3	9.1	9.1
1.4	11.0	11.0
1.5	13.5	13.5
1.6	16.0	16.0
1.7	18.2	18.2
1.8	21.0	21.0

## 5.9 Overshoot and Undershoot Specification

**Table 43 AC Overshoot / Undershoot Specification for Address and Control Pins**

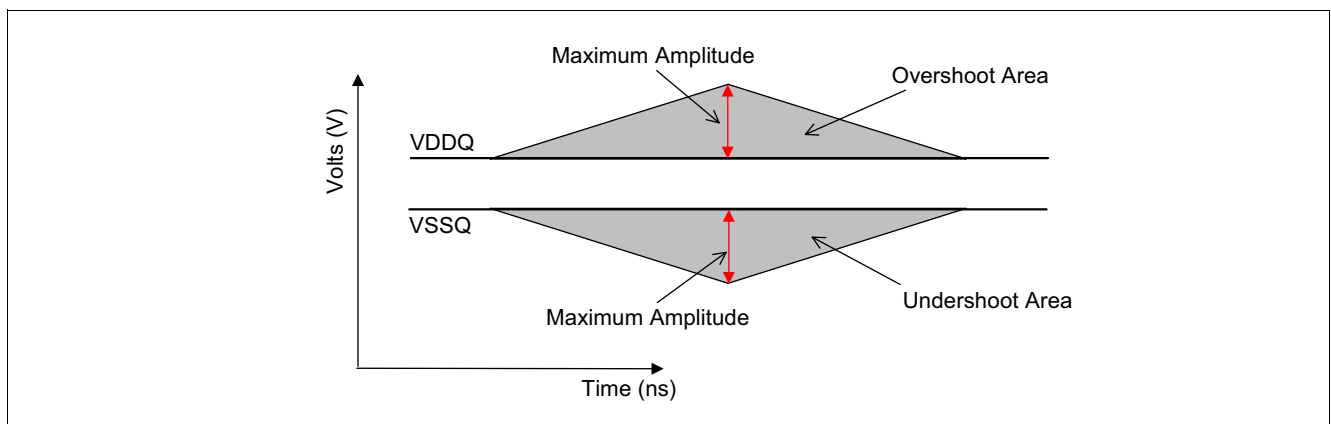
Parameter	DDR2-400	DDR2-533	DD2-667	Unit
Maximum peak amplitude allowed for overshoot area	0.5	0.5	0.5	V
Maximum peak amplitude allowed for undershoot area	0.5	0.5	0.5	V
Maximum overshoot area above $V_{DD}$	1.33	1.00	0.80	V.ns
Maximum undershoot area below $V_{SS}$	1.33	1.00	0.80	V.ns



**Figure 70 AC Overshoot / Undershoot Diagram for Address and Control Pins**

**Table 44 AC Overshoot / Undershoot Specification for Clock, Data, Strobe and Mask Pins**

Parameter	DDR2-400	DDR2-533	DD2-667	Unit
Maximum peak amplitude allowed for overshoot area	0.5	0.5	0.5	V
Maximum peak amplitude allowed for undershoot area	0.5	0.5	0.5	V
Maximum overshoot area above $V_{DDQ}$	0.38	0.28	0.23	V.ns
Maximum undershoot area below $V_{SSQ}$	0.38	0.28	0.23	V.ns



**Figure 71 AC Overshoot / Undershoot Diagram for Clock, Data, Strobe and Mask Pins**

## 6 Measurement Specifications and Conditions

**Table 45**  $I_{DD}$  Measurement Conditions

Parameter	Symbol	Notes
<b>Operating Current - One bank Active - Precharge</b> $t_{CK} = t_{CK(IDD)}$ , $t_{RC} = t_{RC(IDD)}$ , $t_{RAS} = t_{RAS.MIN(IDD)}$ , CKE is HIGH, $\overline{CS}$ is HIGH between valid commands. Address and control inputs are switching; Databus inputs are switching.	$I_{DD0}$	1)2)3)4)5)6)
<b>Operating Current - One bank Active - Read - Precharge</b> $I_{OUT} = 0$ mA, BL = 4, $t_{CK} = t_{CK(IDD)}$ , $t_{RC} = t_{RC(IDD)}$ , $t_{RAS} = t_{RAS.MIN(IDD)}$ , $t_{RCD} = t_{RCD(IDD)}$ , AL = 0, CL = CL(IDD); CKE is HIGH, CS is HIGH between valid commands. Address and control inputs are switching; Databus inputs are switching.	$I_{DD1}$	1)2)3)4)5)6)
<b>Precharge Power-Down Current</b> All banks idle; CKE is LOW; $t_{CK} = t_{CK(IDD)}$ ; Other control and address inputs are stable; Data bus inputs are floating.	$I_{DD2P}$	1)2)3)4)5)6)
<b>Precharge Standby Current</b> All banks idle; $\overline{CS}$ is HIGH; CKE is HIGH; $t_{CK} = t_{CK(IDD)}$ ; Other control and address inputs are switching, Data bus inputs are switching.	$I_{DD2N}$	1)2)3)4)5)6)
<b>Precharge Quiet Standby Current</b> All banks idle; $\overline{CS}$ is HIGH; CKE is HIGH; $t_{CK} = t_{CK(IDD)}$ ; Other control and address inputs are stable, Data bus inputs are floating.	$I_{DD2Q}$	1)2)3)4)5)6)
<b>Active Power-Down Current</b> All banks open; $t_{CK} = t_{CK(IDD)}$ , CKE is LOW; Other control and address inputs are stable; Data bus inputs are floating. MRS A12 bit is set to "0" (Fast Power-down Exit).	$I_{DD3P(0)}$	1)2)3)4)5)6)
<b>Active Power-Down Current</b> All banks open; $t_{CK} = t_{CK(IDD)}$ , CKE is LOW; Other control and address inputs are stable, Data bus inputs are floating. MRS A12 bit is set to 1 (Slow Power-down Exit);	$I_{DD3P(1)}$	1)2)3)4)5)6)
<b>Active Standby Current</b> All banks open; $t_{CK} = t_{CK(IDD)}$ ; $t_{RAS} = t_{RAS.MAX(IDD)}$ , $t_{RP} = t_{RP(IDD)}$ ; CKE is HIGH, $\overline{CS}$ is HIGH between valid commands. Address inputs are switching; Data Bus inputs are switching;	$I_{DD3N}$	1)2)3)4)5)6)
<b>Operating Current</b> Burst Read: All banks open; Continuous burst reads; BL = 4; AL = 0, CL = CL(IDD); $t_{CK} = t_{CK(IDD)}$ ; $t_{RAS} = t_{RAS.MAX(IDD)}$ ; $t_{RP} = t_{RP(IDD)}$ ; CKE is HIGH, $\overline{CS}$ is HIGH between valid commands. Address inputs are switching; Data Bus inputs are switching; $I_{OUT} = 0$ mA.	$I_{DD4R}$	1)2)3)4)5)6)
<b>Operating Current</b> Burst Write: All banks open; Continuous burst writes; BL = 4; AL = 0, CL = CL(IDD); $t_{CK} = t_{CK(IDD)}$ ; $t_{RAS} = t_{RAS.MAX(IDD)}$ , $t_{RP} = t_{RP(IDD)}$ ; CKE is HIGH, $\overline{CS}$ is HIGH between valid commands. Address inputs are switching; Data Bus inputs are switching;	$I_{DD4W}$	1)2)3)4)5)6)
<b>Burst Refresh Current</b> $t_{CK} = t_{CK(IDD)}$ , Refresh command every $t_{RFC} = t_{RFC(IDD)}$ interval, CKE is HIGH, $\overline{CS}$ is HIGH between valid commands, Other control and address inputs are switching, Data bus inputs are switching.	$I_{DD5B}$	1)2)3)4)5)6)
<b>Distributed Refresh Current</b> $t_{CK} = t_{CK(IDD)}$ , Refresh command every $t_{REFI} = 7.8$ $\mu$ s interval, CKE is LOW and $\overline{CS}$ is HIGH between valid commands, Other control and address inputs are switching, Data bus inputs are switching.	$I_{DD5D}$	1)2)3)4)5)6)

**Measurement Specifications and Conditions**

**Table 45**  $I_{DD}$  Measurement Conditions (cont'd)

Parameter	Symbol	Notes
<b>Self-Refresh Current</b> CKE $\leq$ 0.2 V; external clock off, CK and $\overline{CK}$ at 0 V; Other control and address inputs are floating, Data bus inputs are floating.	$I_{DD6}$	1)2)3)4)5)6)
<b>Operating Bank Interleave Read Current</b> 1. All banks interleaving reads, $I_{OUT} = 0$ mA; BL = 4, CL = $\overline{CL}_{(IDD)}$ ; AL = $t_{RCD(IDD)} - 1 \times t_{CK(IDD)}$ ; $t_{CK} = t_{CK(IDD)}$ , $t_{RC} = t_{RC(IDD)}$ , $t_{RRD} = t_{RRD(IDD)}$ ; CKE is HIGH, CS is HIGH between valid commands. Address bus inputs are stable during deselects; Data bus is switching. 2. Timing pattern: DDR2-400-333: A0 RA0 A1 RA1 A2 RA2 A3 RA3 D D D (11 clocks) DDR2-533-333: A0 RA0 D A1 RA1 D A2 RA2 D A3 RA3 D D D D (15 clocks) DDR2-533-444: A0 RA0 D A1 RA1 D A2 RA2 D A3 RA3 D D D D D (16 clocks) DDR2-667-444: A0 RA0 D D A1 RA1 D D A2 RA2 D D A3 RA3 D D D D D (19 clocks) DDR2-667-555: A0 RA0 D D A1 RA1 D D A2 RA2 D D A3 RA3 D D D D D D (20 clocks) DDR2-800-444: A0 RA0 D D A1 RA1 D D A2 RA2 D D A3 RA3 D D D D D D D (22 clocks) DDR2-800-555: A0 RA0 D D A1 RA1 D D A2 RA2 D D A3 RA3 D D D D D D D D (23 clocks) DDR2-800-666: A0 RA0 D D A1 RA1 D D A2 RA2 D D A3 RA3 D D D D D D D D D (24 clocks)	$I_{DD7}$	1)2)3)4)5)6)7)

- 1)  $V_{DDQ} = 1.8\text{ V} \pm 0.1\text{ V}$ ;  $V_{DD} = 1.8\text{ V} \pm 0.1\text{ V}$
- 2)  $I_{DD}$  specifications are tested after the device is properly initialized.
- 3)  $I_{DD}$  parameter are specified with ODT disabled.
- 4) Data Bus consists of DQ, DM, DQS,  $\overline{DQS}$ , RDQS,  $\overline{RDQS}$ , LDQS,  $\overline{LDQS}$ , UDQS and  $\overline{UDQS}$ .
- 5) Definitions for  $I_{DD}$ : see [Table 46](#)
- 6) Timing parameter minimum and maximum values for  $I_{DD}$  current measurements are defined in chapter 7.
- 7) A = Activate, RA = Read with Auto-Precharge, D=DESELECT

**Table 46** Definition for  $I_{DD}$

Parameter	Description
LOW	defined as $V_{IN} \leq V_{IL(ac).MAX}$
HIGH	defined as $V_{IN} \geq V_{IH(ac).MIN}$
STABLE	defined as inputs are stable at a HIGH or LOW level
FLOATING	defined as inputs are $V_{REF} = V_{DDQ} / 2$
SWITCHING	defined as: Inputs are changing between high and low every other clock (once per two clocks) for address and control signals, and inputs changing between high and low every other clock (once per clock) for DQ signals not including mask or strobes

**Measurement Specifications and Conditions**

**Table 47**  $I_{DD}$  Specification for HYB18T256xxxAF

Symbol	-25F	-2.5	-3	-3S	-3.7	-5	Unit	Notes
	DDR2-800	DDR2-800	DDR2-667	DDR2-667	DDR2-533	DDR2-400		
	Max.	Max.	Max.	Max.	Max.	Max.		
$I_{DD0}$	80	75	65	62	55	50	mA	
$I_{DD1}$	90	85	75	71	60	55	mA	
$I_{DD2N}$	50	50	45	45	35	28	mA	
$I_{DD2P}$	5	5	5	5	4.5	4.5	mA	
$I_{DD2P(L)}$	—	—	—	—	2	—	mA	1)
$I_{DD2Q}$	35	35	30	30	25	20	mA	
$I_{DD3N}$	50	50	45	45	35	30	mA	
$I_{DD3P(MRS=0)}$	22	22	19	19	16	13	mA	2)
$I_{DD3P(MRS=1)}$	5	5	5	5	4.5	4.5	mA	3)
$I_{DD4R}$	125	125	110	110	90	70	mA	×4/×8
	175	175	145	145	115	90	mA	×16
$I_{DD4W}$	135	135	115	115	95	75	mA	×4/×8
	190	190	160	160	130	105	mA	×16
$I_{DD5B}$	95	95	95	95	90	85	mA	
$I_{DD5D}$	6	6	6	6	6	6	mA	4)
$I_{DD6}$	4.5	4.5	4.5	4.5	4.5	4.5	mA	4)
$I_{DD6(L)}$	—	—	—	—	2	—	mA	1)4)
$I_{DD7}$	165	155	145	138	135	125	mA	×4/×8
	180	170	165	157	150	140	mA	×16

1) For LowPower Components

2) MRS(12)=0

3) MRS(12)=1

4)  $0 \leq T_{CASE} \leq 85^{\circ}C$

## 6.1 $I_{DD}$ Test Conditions

For testing the  $I_{DD}$  parameters, the following timing parameters are used:

**Table 48  $I_{DD}$  Measurement Test Condition for DDR2–800**

Parameter	Symbol	–25F	–2.5	Unit	Notes
		DDR2–800	DDR2–800		
CAS Latency	$CL_{IDD}$	5	6	$t_{CK}$	
Clock Cycle Time	$t_{CK,IDD}$	2.5	2.5	ns	
Active to Read or Write delay	$t_{RCD,IDD}$	12.5	15	ns	
Active to Active / Auto-Refresh command period	$t_{RC,IDD}$	57.5	60	ns	
Active bank A to Active bank B command delay	$t_{RRD,IDD}$	7.5	7.5	ns	1)
		10	10	ns	2)
Active to Precharge Command	$t_{RAS,MIN,IDD}$	45	45	ns	
	$t_{RAS,MAX,IDD}$	70000	70000	ns	
Precharge Command Period	$t_{RP,IDD}$	12.5	15	ns	
Auto-Refresh to Active / Auto-Refresh command period	$t_{RFC,IDD}$	75	75	ns	
Average periodic Refresh interval	$t_{REFI}$	7.8	7.8	$\mu$ s	

1)  $\times 4$  &  $\times 8$  (1 KByte page size)

2)  $\times 16$  (2 KByte page size); not on 256M component

**Table 49  $I_{DD}$  Measurement Test Conditions for DDR2–667**

Parameter	Symbol	–3	–3S	Unit	Notes
		DDR2–667 4–4–4	DDR2–667 5–5–5		
CAS Latency	$CL_{(IDD)}$	4	5	$t_{CK}$	
Clock Cycle Time	$t_{CK(IDD)}$	3	3	ns	
Active to Read or Write delay	$t_{RCD(IDD)}$	12	15	ns	
Active to Active / Auto-Refresh command period	$t_{RC(IDD)}$	57	60	ns	
Active bank A to Active bank B command delay	$t_{RRD(IDD)}$	7.5	7.5	ns	1)
	$t_{RRD(IDD)}$	10	10	ns	2)
Active to Precharge Command	$t_{RAS,MIN(IDD)}$	45	45	ns	
	$t_{RAS,MAX(IDD)}$	70000	70000	ns	
Precharge Command Period	$t_{RP(IDD)}$	12	15	ns	
Auto-Refresh to Active / Auto-Refresh command period	$t_{RFC(IDD)}$	75	75	ns	
Average periodic Refresh interval	$t_{REFI}$	7.8	7.8	$\mu$ s	

1)  $\times 4$  &  $\times 8$  (1 KByte Page Size)

2)  $\times 16$  (2 KByte Page Size); not on 256M component

**Measurement Specifications and Conditions**

**Table 50  $I_{DD}$  Measurement Test Condition for DDR2–533C and DDR2–400B**

Parameter	Symbol	–3.7	–5	Unit	Notes
		DDR2–533 4–4–4	DDR2–400 3–3–3		
CAS Latency	$CL_{(IDD)}$	4	3	$t_{CK}$	
Clock Cycle Time	$t_{CK(IDD)}$	3.75	5	ns	
Active to Read or Write delay	$t_{RCD(IDD)}$	15	15	ns	
Active to Active / Auto-Refresh command period	$t_{RC(IDD)}$	60	55	ns	
Active bank A to Active bank B command delay	$t_{RRD(IDD)}$	7.5	7.5	ns	1)
		10	10	ns	2)
Active to Precharge Command	$t_{RAS.MIN(IDD)}$	45	40	ns	
	$t_{RAS.MAX(IDD)}$	70000	70000	ns	
Precharge Command Period	$t_{RP(IDD)}$	15	15	ns	
Auto-Refresh to Active / Auto-Refresh command period	$t_{RFC(IDD)}$	75	75	ns	
Average periodic Refresh interval	$t_{REFI}$	7.8	7.8	$\mu$ s	

1)×4 & ×8 (1 KByte Page Size)

2)×16 (2 KByte Page Size); not on 256M component

### 6.1.1 On Die Termination (ODT) Current

The ODT function adds additional current consumption to the DDR2 SDRAM when enabled by the EMRS(1). Depending on address bits A6 & A2 in the EMRS(1) a full or reduced termination can be selected. The current

consumption for any terminated input pin depends on whether the input pin is in tri-state or driving “0” or “1”, as long a ODT is enabled during a given period of time. See [Table 51](#).

**Table 51 ODT current per terminated input pin**

ODT Current		EMRS(1) State	Min.	Typ.	Max.	Unit
Enabled ODT current per DQ added $I_{DDQ}$ current for ODT enabled; ODT is HIGH; Data Bus inputs are floating	$I_{ODTO}$	A6 = 0, A2 = 1	5	6	7.5	mA/DQ
		A6 = 1, A2 = 0	2.5	3	3.75	mA/DQ
		A6 = 1, A2 = 1	7.5	9	11.25	mA/DQ
Active ODT current per DQ added $I_{DDQ}$ current for ODT enabled; ODT is HIGH; worst case of Data Bus inputs are stable or switching.	$I_{ODTT}$	A6 = 0, A2 = 1	10	12	15	mA/DQ
		A6 = 1, A2 = 0	5	6	7.5	mA/DQ
		A6 = 1, A2 = 0	15	18	22.5	mA/DQ

*Note: For power consumption calculations the ODT duty cycle has to be taken into account*

## 7 Electrical Characteristics

### 7.1 Speed Grade Definitions

Table 52 Speed Grade Definition Speed Bins DDR2-800

Speed Grade			DDR2-800		DDR2-800		Unit	Notes
IFX Sort Name			-2.5F		-2.5			
CAS-RCD-RP latencies			5-5-5		6-6-6		$t_{CK}$	
Parameter		Symbol	Min.	Max.	Min.	Max.	—	
Clock Frequency	@ CL = 3	$t_{CK}$	5	8	5	8	ns	1)2)3)4)
	@ CL = 4	$t_{CK}$	3.75	8	3.75	8	ns	1)2)3)4)
	@ CL = 5	$t_{CK}$	2.5	8	3	8	ns	1)2)3)4)
	@ CL = 6	$t_{CK}$	2.5	8	2.5	8	ns	1)2)3)4)
Row Active Time		$t_{RAS}$	45	70000	45	70000	ns	1)2)3)4)5)
Row Cycle Time		$t_{RC}$	57.5	—	60	—	ns	1)2)3)4)
RAS-CAS-Delay		$t_{RCD}$	12.5	—	15	—	ns	1)2)3)4)
Row Precharge Time		$t_{RP}$	12.5	—	15	—	ns	1)2)3)4)

- 1) Timings are guaranteed with CK/ $\overline{CK}$  differential Slew Rate of 2.0 V/ns. For DQS signals timings are guaranteed with a differential Slew Rate of 2.0 V/ns in differential strobe mode and a Slew Rate of 1 V/ns in single ended mode. For other Slew Rates see Chapter 8 Timings are further guaranteed for normal OCD drive strength (EMRS(1) A1 = 0) under the "Reference Load for Timing Measurements" according to Chapter 8.1 only.
- 2) The CK/ $\overline{CK}$  input reference level (for timing reference to CK/ $\overline{CK}$ ) is the point at which CK and  $\overline{CK}$  cross. The DQS /  $\overline{DQS}$ , RDQS /  $\overline{RDQS}$ , input reference level is the crosspoint when in differential strobe mode; The input reference level for signals other than CK/ $\overline{CK}$ , DQS /  $\overline{DQS}$ , RDQS /  $\overline{RDQS}$  is defined in Chapter 8.3.
- 3) Inputs are not recognized as valid until  $V_{REF}$  stabilizes. During the period before  $V_{REF}$  stabilizes, CKE =  $0.2 \times V_{DDQ}$  is recognized as low.
- 4) The output timing reference voltage level is  $V_{TT}$ . See section 8 for the reference load for timing measurements.
- 5)  $t_{RAS,MAX}$  is calculated from the maximum amount of time a DDR2 device can operate without a refresh command which is equal to  $9 \times t_{REFI}$ .

**Table 53 Speed Grade Definition Speed Bins for DDR2-667**

Speed Grade		DDR2-667		DDR2-667		Unit	Notes	
IFX Sort Name		-3		-3S				
CAS-RCD-RP latencies		4-4-4		5-5-5		$t_{CK}$		
Parameter	Symbol	Min.	Max.	Min.	Max.	—		
Clock Frequency	@ CL = 3	$t_{CK}$	5	8	5	8	ns	1)2)3)4)
	@ CL = 4	$t_{CK}$	3	8	3.75	8	ns	1)2)3)4)
	@ CL = 5	$t_{CK}$	3	8	3	8	ns	1)2)3)4)
Row Active Time		$t_{RAS}$	45	70000	45	70000	ns	1)2)3)4)5)
Row Cycle Time		$t_{RC}$	57	—	60	—	ns	1)2)3)4)
RAS-CAS-Delay		$t_{RCD}$	12	—	15	—	ns	1)2)3)4)
Row Precharge Time		$t_{RP}$	12	—	15	—	ns	1)2)3)4)

- 1) Timings are guaranteed with CK/ $\overline{CK}$  differential Slew Rate of 2.0 V/ns. For DQS signals timings are guaranteed with a differential Slew Rate of 2.0 V/ns in differential strobe mode and a Slew Rate of 1 V/ns in single ended mode. For other Slew Rates see Chapter 8. Timings are further guaranteed for normal OCD drive strength (EMRS(1) A1 = 0) under the "Reference Load for Timing Measurements" according to Chapter 8.1 only.
- 2) The CK/ $\overline{CK}$  input reference level (for timing reference to CK/ $\overline{CK}$ ) is the point at which CK and  $\overline{CK}$  cross. The DQS/ $\overline{DQS}$ , RDQS/ $\overline{RDQS}$ , input reference level is the crosspoint when in differential strobe mode; The input reference level for signals other than CK/CK, DQS/ $\overline{DQS}$ , RDQS/ $\overline{RDQS}$  is defined in Chapter 8.3.
- 3) Inputs are not recognized as valid until  $V_{REF}$  stabilizes. During the period before  $V_{REF}$  stabilizes, CKE = 0.2 x  $V_{DDQ}$  is recognized as low.
- 4) The output timing reference voltage level is  $V_{TT}$ . See section 8 for the reference load for timing measurements.
- 5)  $t_{RAS,MAX}$  is calculated from the maximum amount of time a DDR2 device can operate without a refresh command which is equal to 9 x  $t_{REFI}$ .

**Table 54 Speed Grade Definition Speed Bins for DDR2-533C and DDR2-400B**

Speed Grade		DDR2-533		DDR2-400		Unit	Note	
IFX Sort Name		-3.7		-5				
CAS-RCD-RP latencies		4-4-4		3-3-3		$t_{CK}$		
Parameter	Symbol	Min.	Max.	Min.	Max.	—		
Clock Frequency	@ CL = 3	$t_{CK}$	5	8	5	8	ns	1)2)3)4)
	@ CL = 4	$t_{CK}$	3.75	8	5	8	ns	1)2)3)4)
	@ CL = 5	$t_{CK}$	3.75	8	5	8	ns	1)2)3)4)
Row Active Time	$t_{RAS}$	45	70000	40	70000	ns	1)2)3)4)5)	
Row Cycle Time	$t_{RC}$	60	—	55	—	ns	1)2)3)4)	
RAS-CAS-Delay	$t_{RCD}$	15	—	15	—	ns	1)2)3)4)	
Row Precharge Time	$t_{RP}$	15	—	15	—	ns	1)2)3)4)	

- 1) Timings are guaranteed with CK/ $\overline{CK}$  differential Slew Rate of 2.0 V/ns. For DQS signals timings are guaranteed with a differential Slew Rate of 2.0 V/ns in differential strobe mode and a Slew Rate of 1 V/ns in single ended mode. For other Slew Rates see Chapter 8 Timings are further guaranteed for normal OCD drive strength (EMRS(1) A1 = 0) under the "Reference Load for Timing Measurements" according to Chapter 8.1 only.
- 2) The CK/ $\overline{CK}$  input reference level (for timing reference to CK/ $\overline{CK}$ ) is the point at which CK and  $\overline{CK}$  cross. The DQS /  $\overline{DQS}$ , RDQS /  $\overline{RDQS}$ , input reference level is the crosspoint when in differential strobe mode; The input reference level for signals other than CK/CK, DQS / DQS, RDQS / RDQS is defined in Chapter 8.3.
- 3) Inputs are not recognized as valid until  $V_{REF}$  stabilizes. During the period before  $V_{REF}$  stabilizes, CKE = 0.2 x  $V_{DDQ}$  is recognized as low.
- 4) The output timing reference voltage level is  $V_{TT}$ . See section 8 for the reference load for timing measurements.
- 5)  $t_{RAS,MAX}$  is calculated from the maximum amount of time a DDR2 device can operate without a refresh command which is equal to 9 x  $t_{REFI}$ .

## 7.2 AC Timing Parameters

Table 55 Timing Parameter by Speed Grade - DDR2-800

Parameter	Symbol	DDR2-800		Unit	Note 1)2)3)4)5)6)
		Min.	Max.		
DQ output access time from CK / $\overline{\text{CK}}$	$t_{AC}$	–400	+400	ps	
CAS A to CAS B command period	$t_{CCD}$	2	—	$t_{CK}$	
CK, $\overline{\text{CK}}$ high-level width	$t_{CH}$	0.45	0.55	$t_{CK}$	
CKE minimum high and low pulse width	$t_{CKE}$	3	—	$t_{CK}$	
CK, $\overline{\text{CK}}$ low-level width	$t_{CL}$	0.45	0.55	$t_{CK}$	
Auto-Precharge write recovery + precharge time	$t_{DAL}$	WR + $t_{RP}$	—	$t_{CK}$	7)
Minimum time clocks remain ON after CKE asynchronously drops LOW	$t_{DELAY}$	$t_{IS} + t_{CK} + t_{IH}$	—	ns	8)
DQ and DM input hold time (differential data strobe)	$t_{DH}(\text{base})$	125	—	ps	9)
DQ and DM input hold time (single ended data strobe)	$t_{DH1}(\text{base})$	—	—	ps	10)
DQ and DM input pulse width (each input)	$t_{DIPW}$	0.35	—	$t_{CK}$	
DQS output access time from CK / $\overline{\text{CK}}$	$t_{DQSCK}$	–350	+350	ps	
DQS input low (high) pulse width (write cycle)	$t_{DQSL,H}$	0.35	—	$t_{CK}$	
DQS-DQ skew (for DQS & associated DQ signals)	$t_{DQSQ}$	—	200	ps	11)
Write command to 1st DQS latching transition	$t_{DQSS}$	–0.25	+0.25	$t_{CK}$	
DQ and DM input setup time (differential data strobe)	$t_{DS}(\text{base})$	50	—	ps	9)
DQ and DM input setup time (single ended data strobe)	$t_{DS1}(\text{base})$	—	—	ps	9)
DQS falling edge hold time from CK (write cycle)	$t_{DSH}$	0.2	—	$t_{CK}$	
DQS falling edge to CK setup time (write cycle)	$t_{DSS}$	0.2	—	$t_{CK}$	
Clock half period	$t_{HP}$	MIN. ( $t_{CL}, t_{CH}$ )			12)
Data-out high-impedance time from CK / $\overline{\text{CK}}$	$t_{HZ}$	—	$t_{AC,MAX}$	ps	13)
Address and control input hold time	$t_{IH}(\text{base})$	250	—	ps	9)
Address and control input pulse width (each input)	$t_{IPW}$	0.6	—	$t_{CK}$	
Address and control input setup time	$t_{IS}(\text{base})$	175	—	ps	9)
DQ low-impedance time from CK / $\overline{\text{CK}}$	$t_{LZ(DQ)}$	$2 \times t_{AC,MIN}$	$t_{AC,MAX}$	ps	13)
DQS low-impedance from CK / $\overline{\text{CK}}$	$t_{LZ(DQS)}$	$t_{AC,MIN}$	$t_{AC,MAX}$	ps	13)
Mode register set command cycle time	$t_{MRD}$	2	—	$t_{CK}$	
OCD drive mode output delay	$t_{OIT}$	0	12	ns	
Data output hold time from DQS	$t_{QH}$	$t_{HP} - t_{QHS}$	—		
Data hold skew factor	$t_{QHS}$	—	300	ps	
Average periodic refresh Interval	$t_{REFI}$	—	7.8	$\mu\text{s}$	14)15)
		—	3.9	$\mu\text{s}$	14)16)
Auto-Refresh to Active/Auto-Refresh command period	$t_{RFC}$	75	—	ns	17)
Read preamble	$t_{RPRE}$	0.9	1.1	$t_{CK}$	13)
Read postamble	$t_{RPST}$	0.40	0.60	$t_{CK}$	13)

**Table 55 Timing Parameter by Speed Grade - DDR2-800**

Parameter	Symbol	DDR2-800		Unit	Note 1)2)3)4)5)6)
		Min.	Max.		
Active bank A to Active bank B command period	$t_{RRD}$	7.5	—	ns	18)19)
		10	—	ns	20)20)
Internal Read to Precharge command delay	$t_{RTP}$	7.5	—	ns	
Write preamble	$t_{WPRE}$	$0.35 \times t_{CK}$	—	$t_{CK}$	
Write postamble	$t_{WPST}$	0.40	0.60	$t_{CK}$	21)
Write recovery time for write without Auto-Precharge	$t_{WR}$	15	—	ns	
Write recovery time for write with Auto-Precharge	WR	$t_{WR}/t_{CK}$		$t_{CK}$	
Internal Write to Read command delay	$t_{WTR}$	7.5	—	ns	22)
Exit power down to any valid command (other than NOP or Deselect)	$t_{XARD}$	2	—	$t_{CK}$	23)
Exit active power-down mode to Read command (slow exit, lower power)	$t_{XARDS}$	8 – AL	—	$t_{CK}$	24)
Exit precharge power-down to any valid command (other than NOP or Deselect)	$t_{XP}$	2	—	$t_{CK}$	
Exit Self-Refresh to non-Read command	$t_{XSNR}$	$t_{RFC} + 10$	—	ns	
Exit Self-Refresh to Read command	$t_{XSRD}$	200	—	$t_{CK}$	

- 1)  $V_{DDQ} = 1.8 \text{ V} \pm 0.1 \text{ V}$ ;  $V_{DD} = 1.8 \text{ V} \pm 0.1 \text{ V}$ . See notes 3)4)5)6)
- 2) Timing that is not specified is illegal and after such an event, in order to guarantee proper operation, the DRAM must be powered down and then restarted through the specified initialization sequence before normal operation can continue.
- 3) Timings are guaranteed with  $\text{CK}/\overline{\text{CK}}$  differential Slew Rate of 2.0 V/ns. For DQS signals timings are guaranteed with a differential Slew Rate of 2.0 V/ns in differential strobe mode and a Slew Rate of 1 V/ns in single ended mode. For other Slew Rates see Chapter 8 of this data sheet. Timings are further guaranteed for normal OCD drive strength (EMRS(1) A1 = 0) under the Reference Load for Timing Measurements according to Chapter 8.1 only.
- 4) The  $\text{CK}/\overline{\text{CK}}$  input reference level (for timing reference to  $\text{CK}/\overline{\text{CK}}$ ) is the point at which CK and  $\overline{\text{CK}}$  cross. The  $\text{DQS}/\overline{\text{DQS}}$ ,  $\text{RDQS}/\overline{\text{RDQS}}$ , input reference level is the crosspoint when in differential strobe mode; The input reference level for signals other than  $\text{CK}/\overline{\text{CK}}$ ,  $\text{DQS}/\overline{\text{DQS}}$ ,  $\text{RDQS}/\overline{\text{RDQS}}$  is defined in Chapter 8.3 of this data sheet.
- 5) Inputs are not recognized as valid until  $V_{REF}$  stabilizes. During the period before  $V_{REF}$  stabilizes,  $\text{CKE} = 0.2 \times V_{DDQ}$  is recognized as low.
- 6) The output timing reference voltage level is  $V_{TT}$ . See Chapter 8 for the reference load for timing measurements.
- 7) For each of the terms, if not already an integer, round to the next highest integer.  $t_{CK}$  refers to the application clock period. WR refers to the WR parameter stored in the MR.
- 8) The clock frequency is allowed to change during self-refresh mode or precharge power-down mode. In case of clock frequency change during power-down, a specific procedure is required as describes in Chapter 2.12.
- 9) For timing definition, Slew Rate and Slew Rate derating see Chapter 8.3
- 10) For timing definition, Slew Rate and Slew Rate derating see Chapter 8.3
- 11) Consists of data pin skew and output pattern effects, and p-channel to n-channel variation of the output drivers as well as output Slew Rate mis-match between  $\text{DQS}/\overline{\text{DQS}}$  and associated DQ in any given cycle.
- 12) MIN ( $t_{CL}$ ,  $t_{CH}$ ) refers to the smaller of the actual clock low time and the actual clock high time as provided to the device (i.e. this value can be greater than the minimum specification limits for  $t_{CL}$  and  $t_{CH}$ ).
- 13) The  $t_{HZ}$ ,  $t_{RPST}$  and  $t_{LZ}$ ,  $t_{RPRE}$  parameters are referenced to a specific voltage level, which specify when the device output is no longer driving ( $t_{HZ}$ ,  $t_{RPST}$ ), or begins driving ( $t_{LZ}$ ,  $t_{RPRE}$ ).  $t_{HZ}$  and  $t_{LZ}$  transitions occur in the same access time windows as valid data transitions. These parameters are verified by design and characterization, but not subject to production test.
- 14) The Auto-Refresh command interval has be reduced to 3.9  $\mu\text{s}$  when operating the DDR2 DRAM in a temperature range between 85 °C and 95 °C.
- 15)  $0 \leq T_{CASE} \leq 85 \text{ }^\circ\text{C}$
- 16)  $85 \text{ }^\circ\text{C} < T_{CASE} \leq 95 \text{ }^\circ\text{C}$

**Electrical Characteristics**

- 17) A maximum of eight Auto-Refresh commands can be posted to any given DDR2 SDRAM device.
- 18) x4 & x8 (1k page size)
- 19) The  $t_{RRD}$  timing parameter depends on the page size of the DRAM organization. See Chapter 1.5
- 20) x16 (2k page size), not on 256Mbit component
- 21) The maximum limit for the  $t_{WPST}$  parameter is not a device limit. The device operates with a greater value for this parameter, but system performance (bus turnaround) degrades accordingly.
- 22) Minimum  $t_{WTR}$  is two clocks when operating the DDR2-SDRAM at frequencies  $\leq 200$  MHz.
- 23) User can choose two different active power-down modes for additional power saving via MRS address bit A12. In “standard active power-down mode” (MR, A12 = “0”) a fast power-down exit timing  $t_{XARD}$  can be used. In “low active power-down mode” (MR, A12 = “1”) a slow power-down exit timing  $t_{XARDS}$  has to be satisfied.

**Table 56 Timing Parameter by Speed Grade - DDR2-667**

Parameter	Symbol	DDR2-667		Unit	Note 1)2)3)4)5)6)
		Min.	Max.		
DQ output access time from CK / $\overline{CK}$	$t_{AC}$	–450	+450	ps	
CAS A to CAS B command period	$t_{CCD}$	2	—	$t_{CK}$	
CK, $\overline{CK}$ high-level width	$t_{CH}$	0.45	0.55	$t_{CK}$	
CKE minimum high and low pulse width	$t_{CKE}$	3	—	$t_{CK}$	
CK, $\overline{CK}$ low-level width	$t_{CL}$	0.45	0.55	$t_{CK}$	
Auto-Precharge write recovery + precharge time	$t_{DAL}$	WR + $t_{RP}$	—	$t_{CK}$	7)
Minimum time clocks remain ON after CKE asynchronously drops LOW	$t_{DELAY}$	$t_{IS} + t_{CK} + t_{IH}$	—	ns	8)
DQ and DM input hold time (differential data strobe)	$t_{DH}(\text{base})$	175	—	ps	9)
DQ and DM input hold time (single ended data strobe)	$t_{DH1}(\text{base})$	—	—	ps	10)
DQ and DM input pulse width (each input)	$t_{DIPW}$	0.35	—	$t_{CK}$	
DQS output access time from CK / $\overline{CK}$	$t_{DQSCK}$	–400	+400	ps	
DQS input low (high) pulse width (write cycle)	$t_{DQSL,H}$	0.35	—	$t_{CK}$	
DQS-DQ skew (for DQS & associated DQ signals)	$t_{DQSQ}$	240	—	ps	11)
Write command to 1st DQS latching transition	$t_{DQSS}$	–0.25	+0.25	$t_{CK}$	
DQ and DM input setup time (differential data strobe)	$t_{DS}(\text{base})$	100	—	ps	9)
DQ and DM input setup time (single ended data strobe)	$t_{DS1}(\text{base})$	—	—	ps	9)
DQS falling edge hold time from CK (write cycle)	$t_{DSH}$	0.2	—	$t_{CK}$	
DQS falling edge to CK setup time (write cycle)	$t_{DSS}$	0.2	—	$t_{CK}$	
Clock half period	$t_{HP}$	MIN. ( $t_{CL}, t_{CH}$ )			12)
Data-out high-impedance time from CK / $\overline{CK}$	$t_{HZ}$	—	$t_{AC,MAX}$	ps	13)
Address and control input hold time	$t_{IH}(\text{base})$	275	—	ps	9)
Address and control input pulse width (each input)	$t_{IPW}$	0.6	—	$t_{CK}$	
Address and control input setup time	$t_{IS}(\text{base})$	200	—	ps	9)
DQ low-impedance time from CK / $\overline{CK}$	$t_{LZ(DQ)}$	$2 \times t_{AC,MIN}$	$t_{AC,MAX}$	ps	13)
DQS low-impedance from CK / $\overline{CK}$	$t_{LZ(DQS)}$	$t_{AC,MIN}$	$t_{AC,MAX}$	ps	13)
Mode register set command cycle time	$t_{MRD}$	2	—	$t_{CK}$	
OCD drive mode output delay	$t_{OIT}$	0	12	ns	
Data output hold time from DQS	$t_{QH}$	$t_{HP} - t_{QHS}$	—		
Data hold skew factor	$t_{QHS}$	340	—	ps	

**Table 56 Timing Parameter by Speed Grade - DDR2-667**

Parameter	Symbol	DDR2-667		Unit	Note 1)2)3)4)5)6)
		Min.	Max.		
Average periodic refresh Interval	$t_{REFI}$	—	7.8	$\mu$ s	14)15)
		—	3.9	$\mu$ s	14)16)
Auto-Refresh to Active/Auto-Refresh command period	$t_{RFC}$	75	—	ns	17)
Precharge-All (4 banks) command period	$t_{RP}$	$t_{RP} + 1t_{CK}$	—	ns	18)
Read preamble	$t_{RPRE}$	0.9	1.1	$t_{CK}$	13)
Read postamble	$t_{RPST}$	0.40	0.60	$t_{CK}$	13)
Active bank A to Active bank B command period	$t_{RRD}$	7.5	—	ns	19)20)
		10	—	ns	21)
Internal Read to Precharge command delay	$t_{RTP}$	7.5	—	ns	
Write preamble	$t_{WPRE}$	0.35	—	$t_{CK}$	
Write postamble	$t_{WPST}$	0.40	0.60	$t_{CK}$	22)
Write recovery time for write without Auto-Precharge	$t_{WR}$	15	—	ns	
Write recovery time for write with Auto-Precharge	WR	$t_{WR}/t_{CK}$		$t_{CK}$	
Internal Write to Read command delay	$t_{WTR}$	7.5	—	ns	23)
Exit power down to any valid command (other than NOP or Deselect)	$t_{XARD}$	2	—	$t_{CK}$	24)
Exit active power-down mode to Read command (slow exit, lower power)	$t_{XARDS}$	7 – AL	—	$t_{CK}$	24)
Exit precharge power-down to any valid command (other than NOP or Deselect)	$t_{XP}$	2	—	$t_{CK}$	
Exit Self-Refresh to non-Read command	$t_{XSNR}$	$t_{RFC} + 10$	—	ns	
Exit Self-Refresh to Read command	$t_{XSRD}$	200	—	$t_{CK}$	

- 1)  $V_{DDQ} = 1.8 \text{ V} \pm 0.1 \text{ V}$ ;  $V_{DD} = 1.8 \text{ V} \pm 0.1 \text{ V}$ . See notes 3)4)5)6)
- 2) Timing that is not specified is illegal and after such an event, in order to guarantee proper operation, the DRAM must be powered down and then restarted through the specified initialization sequence before normal operation can continue.
- 3) Timings are guaranteed with  $\text{CK}/\overline{\text{CK}}$  differential Slew Rate of 2.0 V/ns. For DQS signals timings are guaranteed with a differential Slew Rate of 2.0 V/ns in differential strobe mode and a Slew Rate of 1 V/ns in single ended mode. For other Slew Rates see Chapter 8 of this data sheet. Timings are further guaranteed for normal OCD drive strength (EMRS(1) A1 = 0) under the Reference Load for Timing Measurements according to Chapter 8.1 only.
- 4) The  $\text{CK}/\overline{\text{CK}}$  input reference level (for timing reference to  $\text{CK}/\overline{\text{CK}}$ ) is the point at which CK and  $\overline{\text{CK}}$  cross. The DQS/DQS, RDQS/RDQS, input reference level is the crosspoint when in differential strobe mode; The input reference level for signals other than  $\text{CK}/\overline{\text{CK}}$ , DQS/DQS, RDQS/RDQS is defined in Chapter 8.3 of this data sheet.
- 5) Inputs are not recognized as valid until  $V_{REF}$  stabilizes. During the period before  $V_{REF}$  stabilizes,  $\text{CKE} = 0.2 \times V_{DDQ}$  is recognized as low.
- 6) The output timing reference voltage level is  $V_{TT}$ . See Chapter 8 for the reference load for timing measurements.
- 7) For each of the terms, if not already an integer, round to the next highest integer.  $t_{CK}$  refers to the application clock period. WR refers to the WR parameter stored in the MR.
- 8) The clock frequency is allowed to change during self-refresh mode or precharge power-down mode. In case of clock frequency change during power-down, a specific procedure is required as describes in Chapter 2.12.
- 9) For timing definition, Slew Rate and Slew Rate derating see Chapter 8.3
- 10) For timing definition, Slew Rate and Slew Rate derating see Chapter 8.3
- 11) Consists of data pin skew and output pattern effects, and p-channel to n-channel variation of the output drivers as well as output Slew Rate mis-match between DQS/DQS and associated DQ in any given cycle.
- 12) MIN ( $t_{CL}$ ,  $t_{CH}$ ) refers to the smaller of the actual clock low time and the actual clock high time as provided to the device (i.e. this value can be greater than the minimum specification limits for  $t_{CL}$  and  $t_{CH}$ ).

**Electrical Characteristics**

- 13) The  $t_{HZ}$ ,  $t_{RPST}$  and  $t_{LZ}$ ,  $t_{RPRE}$  parameters are referenced to a specific voltage level, which specify when the device output is no longer driving ( $t_{HZ}$ ,  $t_{RPST}$ ), or begins driving ( $t_{LZ}$ ,  $t_{RPRE}$ ).  $t_{HZ}$  and  $t_{LZ}$  transitions occur in the same access time windows as valid data transitions. These parameters are verified by design and characterization, but not subject to production test.
- 14) The Auto-Refresh command interval has been reduced to 3.9  $\mu$ s when operating the DDR2 DRAM in a temperature range between 85 °C and 95 °C.
- 15)  $0 \leq T_{CASE} \leq 85$  °C
- 16)  $85$  °C <  $T_{CASE} \leq 95$  °C
- 17) A maximum of eight Auto-Refresh commands can be posted to any given DDR2 SDRAM device.
- 18)  $t_{RP(A)}$  for a Precharge-All command for an 8 bank device is equal to  $t_{RP} + 1t_{CK}$ , where  $t_{RP}$  are the values for a single bank precharge.
- 19) x4 & x8 (1k page size)
- 20) The  $t_{RRD}$  timing parameter depends on the page size of the DRAM organization. See Chapter 1.5
- 21) x16 (2k page size), not on 256Mbit component
- 22) The maximum limit for the  $t_{WPST}$  parameter is not a device limit. The device operates with a greater value for this parameter, but system performance (bus turnaround) degrades accordingly.
- 23) Minimum  $t_{WTR}$  is two clocks when operating the DDR2-SDRAM at frequencies  $\leq 200$  MHz.
- 24) User can choose two different active power-down modes for additional power saving via MRS address bit A12. In “standard active power-down mode” (MR, A12 = “0”) a fast power-down exit timing  $t_{XARD}$  can be used. In “low active power-down mode” (MR, A12 = “1”) a slow power-down exit timing  $t_{XARDS}$  has to be satisfied.

**Table 57 Timing Parameter by Speed Grade - DDR2-533**

Parameter	Symbol	DDR2–533		Unit	Note <sup>1)2)</sup> 3)4)5)6)
		Min.	Max.		
DQ output access time from CK / $\overline{CK}$	$t_{AC}$	–500	+500	ps	
CAS A to CAS B command period	$t_{CCD}$	2	—	$t_{CK}$	
CK, $\overline{CK}$ high-level width	$t_{CH}$	0.45	0.55	$t_{CK}$	
CKE minimum high and low pulse width	$t_{CKE}$	3	—	$t_{CK}$	
CK, $\overline{CK}$ low-level width	$t_{CL}$	0.45	0.55	$t_{CK}$	
Auto-Precharge write recovery + precharge time	$t_{DAL}$	WR + $t_{RP}$	—	$t_{CK}$	7)
Minimum time clocks remain ON after CKE asynchronously drops LOW	$t_{DELAY}$	$t_{IS} + t_{CK} + t_{IH}$	—	ns	8)
DQ and DM input hold time (differential data strobe)	$t_{DH}(\text{base})$	225	—	ps	9)
DQ and DM input hold time (single ended data strobe)	$t_{DH1}(\text{base})$	–25	—	ps	9)
DQ and DM input pulse width (each input)	$t_{DIPW}$	0.35	—	$t_{CK}$	
DQS output access time from CK / $\overline{CK}$	$t_{DQSCK}$	–450	+450	ps	
DQS input low (high) pulse width (write cycle)	$t_{DQSL,H}$	0.35	—	$t_{CK}$	
DQS-DQ skew (for DQS & associated DQ signals)	$t_{DQSQ}$	—	300	ps	10)
Write command to 1st DQS latching transition	$t_{DQSS}$	–0.25	+0.25	$t_{CK}$	
DQ and DM input setup time (differential data strobe)	$t_{DS}(\text{base})$	100	—	ps	9)
DQ and DM input setup time (single ended data strobe)	$t_{DS1}(\text{base})$	–25	—	ps	9)
DQS falling edge hold time from CK (write cycle)	$t_{DSH}$	0.2	—	$t_{CK}$	
DQS falling edge to CK setup time (write cycle)	$t_{DSS}$	0.2	—	$t_{CK}$	
Clock half period	$t_{HP}$	MIN. ( $t_{CL}$ , $t_{CH}$ )			11)

**Table 57 Timing Parameter by Speed Grade - DDR2-533 (cont'd)**

Parameter	Symbol	DDR2–533		Unit	Note <sup>1)2)</sup> 3)4)5)6)
		Min.	Max.		
Data-out high-impedance time from CK / $\overline{\text{CK}}$	$t_{\text{HZ}}$	—	$t_{\text{AC.MAX}}$	ps	12)
Address and control input hold time	$t_{\text{IH}}(\text{base})$	375	—	ps	9)
Address and control input pulse width (each input)	$t_{\text{IPW}}$	0.6	—	$t_{\text{CK}}$	
Address and control input setup time	$t_{\text{IS}}(\text{base})$	250	—	ps	9)
DQ low-impedance time from CK / $\overline{\text{CK}}$	$t_{\text{LZ}}(\text{DQ})$	$2 \cdot t_{\text{AC.MIN}}$	$t_{\text{AC.MAX}}$	ps	12)
DQS low-impedance from CK / $\overline{\text{CK}}$	$t_{\text{LZ}}(\text{DQS})$	$t_{\text{AC.MIN}}$	$t_{\text{AC.MAX}}$	ps	12)
Mode register set command cycle time	$t_{\text{MRD}}$	2	—	$t_{\text{CK}}$	
OCD drive mode output delay	$t_{\text{OIT}}$	0	12	ns	
Data output hold time from DQS	$t_{\text{QH}}$	$t_{\text{HP}} - t_{\text{QHS}}$	—		
Data hold skew factor	$t_{\text{QHS}}$	—	400	ps	
Average periodic refresh Interval	$t_{\text{REFI}}$	—	7.8	$\mu\text{s}$	13)14)
		—	3.9	$\mu\text{s}$	13)15)
Auto-Refresh to Active/Auto-Refresh command period	$t_{\text{RFC}}$	75	—	ns	16)
Precharge-All (4 banks) command period	$t_{\text{RP}}$	$t_{\text{RP}} + 1t_{\text{CK}}$	—	ns	17)
Read preamble	$t_{\text{RPRE}}$	0.9	1.1	$t_{\text{CK}}$	12)
Read postamble	$t_{\text{RPST}}$	0.40	0.60	$t_{\text{CK}}$	12)
Active bank A to Active bank B command period	$t_{\text{RRD}}$	7.5	—	ns	1)18)19)
		10	—	ns	1)1)20)
Internal Read to Precharge command delay	$t_{\text{RTP}}$	7.5	—	ns	
Write preamble	$t_{\text{WPRE}}$	$0.35 \times t_{\text{CK}}$	—	$t_{\text{CK}}$	
Write postamble	$t_{\text{WPST}}$	0.40	0.60	$t_{\text{CK}}$	21)
Write recovery time for write without Auto-Precharge	$t_{\text{WR}}$	15	—	ns	
Write recovery time for write with Auto-Precharge	WR	$t_{\text{WR}}/t_{\text{CK}}$		$t_{\text{CK}}$	
Internal Write to Read command delay	$t_{\text{WTR}}$	7.5	—	ns	22)
Exit power down to any valid command (other than NOP or Deselect)	$t_{\text{XARD}}$	2	—	$t_{\text{CK}}$	23)
Exit active power-down mode to Read command (slow exit, lower power)	$t_{\text{XARDS}}$	6 – AL	—	$t_{\text{CK}}$	1)
Exit precharge power-down to any valid command (other than NOP or Deselect)	$t_{\text{XP}}$	2	—	$t_{\text{CK}}$	
Exit Self-Refresh to non-Read command	$t_{\text{XSNR}}$	$t_{\text{RFC}} + 10$	—	ns	
Exit Self-Refresh to Read command	$t_{\text{XSRD}}$	200	—	$t_{\text{CK}}$	

1)  $V_{\text{DDQ}} = 1.8 \text{ V} \pm 0.1 \text{ V}$ ;  $V_{\text{DD}} = 1.8 \text{ V} \pm 0.1 \text{ V}$ . See notes 3)4)5)6)

2) Timing that is not specified is illegal and after such an event, in order to guarantee proper operation, the DRAM must be powered down and then restarted through the specified initialization sequence before normal operation can continue.

3) Timings are guaranteed with CK/ $\overline{\text{CK}}$  differential Slew Rate of 2.0 V/ns. For DQS signals timings are guaranteed with a differential Slew Rate of 2.0 V/ns in differential strobe mode and a Slew Rate of 1 V/ns in single ended mode. For other Slew Rates see Chapter 8 of this data sheet. Timings are further guaranteed for normal OCD drive strength (EMRS(1) A1 = 0) under the Reference Load for Timing Measurements according to Chapter 8.1 only.

**Electrical Characteristics**

- 4) The  $\overline{CK} / \overline{CK}$  input reference level (for timing reference to  $\overline{CK} / \overline{CK}$ ) is the point at which  $\overline{CK}$  and  $\overline{CK}$  cross. The  $\overline{DQS} / \overline{DQS}$ ,  $\overline{RDQS} / \overline{RDQS}$ , input reference level is the crosspoint when in differential strobe mode;  
The input reference level for signals other than  $\overline{CK} / \overline{CK}$ ,  $\overline{DQS} / \overline{DQS}$ ,  $\overline{RDQS} / \overline{RDQS}$  is defined in Chapter 8.3 of this data sheet.
- 5) Inputs are not recognized as valid until  $V_{REF}$  stabilizes. During the period before  $V_{REF}$  stabilizes,  $CKE = 0.2 \times V_{DDQ}$  is recognized as low.
- 6) The output timing reference voltage level is  $V_{TT}$ . See Chapter 8 for the reference load for timing measurements.
- 7) For each of the terms, if not already an integer, round to the next highest integer.  $t_{CK}$  refers to the application clock period.  $WR$  refers to the  $WR$  parameter stored in the MR.
- 8) The clock frequency is allowed to change during self-refresh mode or precharge power-down mode. In case of clock frequency change during power-down, a specific procedure is required as describes in Chapter 2.12.
- 9) For timing definition, Slew Rate and Slew Rate derating see Chapter 8.3
- 10) Consists of data pin skew and output pattern effects, and p-channel to n-channel variation of the output drivers as well as output Slew Rate mis-match between  $\overline{DQS} / \overline{DQS}$  and associated  $\overline{DQ}$  in any given cycle.
- 11)  $\text{MIN}(t_{CL}, t_{CH})$  refers to the smaller of the actual clock low time and the actual clock high time as provided to the device (i.e. this value can be greater than the minimum specification limits for  $t_{CL}$  and  $t_{CH}$ ).
- 12) The  $t_{HZ}$ ,  $t_{RPST}$  and  $t_{LZ}$ ,  $t_{RPRE}$  parameters are referenced to a specific voltage level, which specify when the device output is no longer driving ( $t_{HZ}$ ,  $t_{RPST}$ ), or begins driving ( $t_{LZ}$ ,  $t_{RPRE}$ ).  $t_{HZ}$  and  $t_{LZ}$  transitions occur in the same access time windows as valid data transitions. These parameters are verified by design and characterization, but not subject to production test.
- 13) The Auto-Refresh command interval has be reduced to 3.9  $\mu\text{s}$  when operating the DDR2 DRAM in a temperature range between 85 °C and 95 °C.
- 14)  $0 \leq T_{CASE} \leq 85 \text{ }^\circ\text{C}$
- 15)  $85 < T_{CASE} \leq 95 \text{ }^\circ\text{C}$
- 16) A maximum of eight Auto-Refresh commands can be posted to any given DDR2 SDRAM device.
- 17)  $t_{RP(A)}$  for a Precharge-All command for an 8 bank device is equal to  $t_{RP} + 1t_{CK}$ , where  $t_{RP}$  are the values for a single bank precharge.
- 18) The  $t_{RRD}$  timing parameter depends on the page size of the DRAM organization. See Chapter 1.5
- 19) x4 & x8
- 20) x16
- 21) The maximum limit for the  $t_{WPST}$  parameter is not a device limit. The device operates with a greater value for this parameter, but system performance (bus turnaround) degrades accordingly.
- 22) Minimum  $t_{WTR}$  is two clocks when operating the DDR2-SDRAM at frequencies  $\leq 200 \text{ MHz}$ .
- 23) User can choose two different active power-down modes for additional power saving via MRS address bit A12. In “standard active power-down mode” (MR, A12 = “0”) a fast power-down exit timing  $t_{XARD}$  can be used. In “low active power-down mode” (MR, A12 = “1”) a slow power-down exit timing  $t_{XARDS}$  has to be satisfied.

**Table 58 Timing Parameter by Speed Grade - DDR2-400**

Parameter	Symbol	DDR2-400		Unit	Note 1)2)3)4)5)6)
		Min.	Max.		
DQ output access time from $\overline{CK} / \overline{CK}$	$t_{AC}$	–600	+600	ps	
$\overline{CAS} A$ to $\overline{CAS} B$ command period	$t_{CCD}$	2	—	$t_{CK}$	
$\overline{CK}$ , $\overline{CK}$ high-level width	$t_{CH}$	0.45	0.55	$t_{CK}$	
CKE minimum high and low pulse width	$t_{CKE}$	3	—	$t_{CK}$	
$\overline{CK}$ , $\overline{CK}$ low-level width	$t_{CL}$	0.45	0.55	$t_{CK}$	
Auto-Precharge write recovery + precharge time	$t_{DAL}$	$WR + t_{RP}$	—	$t_{CK}$	7)
Minimum time clocks remain ON after CKE asynchronously drops LOW	$t_{DELAY}$	$t_{IS} + t_{CK} + t_{IH}$	—	ns	8)
DQ and DM input hold time (differential data strobe)	$t_{DH}(\text{base})$	275	—	ps	9)
DQ and DM input hold time (single-ended strobe)	$t_{DH1}(\text{base})$	25	—	ps	10)
DQ and DM input pulse width (each input)	$t_{DIPW}$	0.35	—	$t_{CK}$	

**Electrical Characteristics**
**Table 58 Timing Parameter by Speed Grade - DDR2-400**

Parameter	Symbol	DDR2-400		Unit	Note 1)2)3)4)5)6)
		Min.	Max.		
DQS output access time from CK / $\overline{\text{CK}}$	$t_{\text{DQSCK}}$	–500	+500	ps	
DQS input low (high) pulse width (write cycle)	$t_{\text{DQSL,H}}$	0.35	—	$t_{\text{CK}}$	
DQS-DQ skew (for DQS & associated DQ signals)	$t_{\text{DQSQ}}$	—	350	ps	11)
Write command to 1st DQS latching transition	$t_{\text{DQSS}}$	–0.25	+0.25	$t_{\text{CK}}$	
DQ and DM input setup time (differential data strobe)	$t_{\text{DS}}(\text{base})$	150	—	ps	9)
DQ and DM input setup time (single-ended strobe)	$t_{\text{DS1}}(\text{base})$	25	—	ps	9)
DQS falling edge hold time from CK (write cycle)	$t_{\text{DSH}}$	0.2	—	$t_{\text{CK}}$	
DQS falling edge to CK setup time (write cycle)	$t_{\text{DSS}}$	0.2	—	$t_{\text{CK}}$	
Clock half period	$t_{\text{HP}}$	MIN. ( $t_{\text{CL}}, t_{\text{CH}}$ )			12)
Data-out high-impedance time from CK / $\overline{\text{CK}}$	$t_{\text{HZ}}$	—	$t_{\text{AC,MAX}}$	ps	13)
Address and control input hold time	$t_{\text{IH}}(\text{base})$	475	—	ps	9)
Address and control input pulse width (each input)	$t_{\text{IPW}}$	0.6	—	$t_{\text{CK}}$	
Address and control input setup time	$t_{\text{IS}}(\text{base})$	350	—	ps	9)
DQ low-impedance time from CK / $\overline{\text{CK}}$	$t_{\text{LZ}}(\text{DQ})$	$2 \times t_{\text{AC,MIN}}$	$t_{\text{AC,MAX}}$	ps	13)
DQS low-impedance from CK / $\overline{\text{CK}}$	$t_{\text{LZ}}(\text{DQS})$	$t_{\text{AC,MIN}}$	$t_{\text{AC,MAX}}$	ps	13)
Mode register set command cycle time	$t_{\text{MRD}}$	2	—	$t_{\text{CK}}$	
OCD drive mode output delay	$t_{\text{OIT}}$	0	12	ns	
Data output hold time from DQS	$t_{\text{QH}}$	$t_{\text{HP}} - t_{\text{QHS}}$	—		
Data hold skew factor	$t_{\text{QHS}}$	—	450	ps	
Average periodic refresh Interval	$t_{\text{REFI}}$	—	7.8	$\mu\text{s}$	14)15)
		—	3.9	$\mu\text{s}$	14)16)
Auto-Refresh to Active/Auto-Refresh command period	$t_{\text{RFC}}$	75	—	ns	17)
Precharge-All (4 banks) command period	$t_{\text{RP}}$	$t_{\text{RP}} + 1t_{\text{CK}}$	—	ns	18)
Read preamble	$t_{\text{RPRE}}$	0.9	1.1	$t_{\text{CK}}$	13)
Read postamble	$t_{\text{RPST}}$	0.40	0.60	$t_{\text{CK}}$	13)
Active bank A to Active bank B command period	$t_{\text{RRD}}$	7.5	—	ns	19)20)
		10	—	ns	20)21)
Internal Read to Precharge command delay	$t_{\text{RTP}}$	7.5	—	ns	
Write preamble	$t_{\text{WPRE}}$	0.35	—	$t_{\text{CK}}$	
Write postamble	$t_{\text{WPST}}$	0.40	0.60	$t_{\text{CK}}$	22)
Write recovery time for write without Auto-Precharge	$t_{\text{WR}}$	15	—	ns	
Write recovery time for write with Auto-Precharge	WR	$t_{\text{WR}}/t_{\text{CK}}$		$t_{\text{CK}}$	
Internal Write to Read command delay	$t_{\text{WTR}}$	7.5	—	ns	23)
Exit power down to any valid command (other than NOP or Deselect)	$t_{\text{XARD}}$	2	—	$t_{\text{CK}}$	24)
Exit active power-down mode to Read command (slow exit, lower power)	$t_{\text{XARDS}}$	6 – AL	—	$t_{\text{CK}}$	24)
Exit precharge power-down to any valid command (other than NOP or Deselect)	$t_{\text{XP}}$	2	—	$t_{\text{CK}}$	

**Table 58 Timing Parameter by Speed Grade - DDR2-400**

Parameter	Symbol	DDR2-400		Unit	Note 1)2)3)4)5)6)
		Min.	Max.		
Exit Self-Refresh to non-Read command	$t_{XSNR}$	$t_{RFC} + 10$	—	ns	
Exit Self-Refresh to Read command	$t_{XSRD}$	200	—	$t_{CK}$	

- 1)  $V_{DDQ} = 1.8 \text{ V} \pm 0.1 \text{ V}$ ;  $V_{DD} = 1.8 \text{ V} \pm 0.1 \text{ V}$ . See notes <sup>3)4)5)6)</sup>
- 2) Timing that is not specified is illegal and after such an event, in order to guarantee proper operation, the DRAM must be powered down and then restarted through the specified initialization sequence before normal operation can continue.
- 3) Timings are guaranteed with  $\overline{CK}/\overline{CK}$  differential Slew Rate of 2.0 V/ns. For DQS signals timings are guaranteed with a differential Slew Rate of 2.0 V/ns in differential strobe mode and a Slew Rate of 1 V/ns in single ended mode. For other Slew Rates see Chapter 8 of this data sheet. Timings are further guaranteed for normal OCD drive strength (EMRS(1) A1 = 0) under the Reference Load for Timing Measurements according to Chapter 8.1 only.
- 4) The  $\overline{CK}/\overline{CK}$  input reference level (for timing reference to  $\overline{CK}/\overline{CK}$ ) is the point at which  $\overline{CK}$  and  $\overline{CK}$  cross. The  $\overline{DQS}/\overline{DQS}$ ,  $\overline{RDQS}/\overline{RDQS}$ , input reference level is the crosspoint when in differential strobe mode; The input reference level for signals other than  $\overline{CK}/\overline{CK}$ ,  $\overline{DQS}/\overline{DQS}$ ,  $\overline{RDQS}/\overline{RDQS}$  is defined in Chapter 8.3 of this data sheet.
- 5) Inputs are not recognized as valid until  $V_{REF}$  stabilizes. During the period before  $V_{REF}$  stabilizes,  $CKE = 0.2 \times V_{DDQ}$  is recognized as low.
- 6) The output timing reference voltage level is  $V_{TT}$ . See Chapter 8 for the reference load for timing measurements.
- 7) For each of the terms, if not already an integer, round to the next highest integer.  $t_{CK}$  refers to the application clock period. WR refers to the WR parameter stored in the MR.
- 8) The clock frequency is allowed to change during self-refresh mode or precharge power-down mode. In case of clock frequency change during power-down, a specific procedure is required as describes in Chapter 2.12.
- 9) For timing definition, Slew Rate and Slew Rate derating see Chapter 8.3
- 10) For timing definition, Slew Rate and Slew Rate derating see Chapter 8.3
- 11) Consists of data pin skew and output pattern effects, and p-channel to n-channel variation of the output drivers as well as output Slew Rate mis-match between  $\overline{DQS}/\overline{DQS}$  and associated DQ in any given cycle.
- 12) MIN ( $t_{CL}$ ,  $t_{CH}$ ) refers to the smaller of the actual clock low time and the actual clock high time as provided to the device (i.e. this value can be greater than the minimum specification limits for  $t_{CL}$  and  $t_{CH}$ ).
- 13) The  $t_{HZ}$ ,  $t_{RPST}$  and  $t_{LZ}$ ,  $t_{RPRE}$  parameters are referenced to a specific voltage level, which specify when the device output is no longer driving ( $t_{HZ}$ ,  $t_{RPST}$ ), or begins driving ( $t_{LZ}$ ,  $t_{RPRE}$ ).  $t_{HZ}$  and  $t_{LZ}$  transitions occur in the same access time windows as valid data transitions. These parameters are verified by design and characterization, but not subject to production test.
- 14) The Auto-Refresh command interval has be reduced to 3.9  $\mu\text{s}$  when operating the DDR2 DRAM in a temperature range between 85 °C and 95 °C.
- 15)  $0 \leq T_{CASE} \leq 85 \text{ }^\circ\text{C}$
- 16)  $85 \text{ }^\circ\text{C} < T_{CASE} \leq 95 \text{ }^\circ\text{C}$
- 17) A maximum of eight Auto-Refresh commands can be posted to any given DDR2 SDRAM device.
- 18)  $t_{RP(A)}$  for a Precharge-All command for an 8 bank device is equal to  $t_{RP} + 1t_{CK}$ , where  $t_{RP}$  are the values for a single bank precharge.
- 19) x4 & x8 (1k page size)
- 20) The  $t_{RRD}$  timing parameter depends on the page size of the DRAM organization. See Chapter 1.5
- 21) x16 (2k page size), not on 256Mbit component
- 22) The maximum limit for the  $t_{WPST}$  parameter is not a device limit. The device operates with a greater value for this parameter, but system performance (bus turnaround) degrades accordingly.
- 23) Minimum  $t_{WTR}$  is two clocks when operating the DDR2-SDRAM at frequencies  $\leq 200 \text{ MHz}$ .
- 24) User can choose two different active power-down modes for additional power saving via MRS address bit A12. In "standard active power-down mode" (MR, A12 = "0") a fast power-down exit timing  $t_{XARD}$  can be used. In "low active power-down mode" (MR, A12 = "1") a slow power-down exit timing  $t_{XARDS}$  has to be satisfied.

### 7.3 ODT AC Electrical Characteristics

**Table 59 ODT AC Electrical Characteristics and Operating Conditions for DDR2-667 and DDR2-800**

Symbol	Parameter / Condition	Values		Unit	Note
		Min.	Max.		
$t_{AOND}$	ODT turn-on delay	2	2	$t_{CK}$	
$t_{AON}$	ODT turn-on	$t_{AC.MIN}$	$t_{AC.MAX} + 0.7 \text{ ns}$	ns	1)
$t_{AONPD}$	ODT turn-on (Power-Down Modes)	$t_{AC.MIN} + 2 \text{ ns}$	$2 t_{CK} + t_{AC.MAX} + 1 \text{ ns}$	ns	
$t_{AOFD}$	ODT turn-off delay	2.5	2.5	$t_{CK}$	
$t_{AOF}$	ODT turn-off	$t_{AC.MIN}$	$t_{AC.MAX} + 0.6 \text{ ns}$	ns	2)
$t_{AOFPD}$	ODT turn-off (Power-Down Modes)	$t_{AC.MIN} + 2 \text{ ns}$	$2.5 t_{CK} + t_{AC.MAX} + 1 \text{ ns}$	ns	
$t_{ANPD}$	ODT to Power Down Mode Entry Latency	3	—	$t_{CK}$	
$t_{AXPD}$	ODT Power Down Exit Latency	8	—	$t_{CK}$	

- 1) ODT turn on time min. is when the device leaves high impedance and ODT resistance begins to turn on. ODT turn on time max is when the ODT resistance is fully on. Both are measure from  $t_{AOND}$ .
- 2) ODT turn off time min. is when the device starts to turn off ODT resistance. ODT turn off time max is when the bus is in high impedance. Both are measured from  $t_{AOFD}$ .

**Table 60 ODT AC Electrical Characteristics and Operating Conditions for DDR2-533 and DDR2-400**

Symbol	Parameter / Condition	Values		Unit	Note
		Min.	Max.		
$t_{AOND}$	ODT turn-on delay	2	2	$t_{CK}$	
$t_{AON}$	ODT turn-on	$t_{AC.MIN}$	$t_{AC.MAX} + 1 \text{ ns}$	ns	1)
$t_{AONPD}$	ODT turn-on (Power-Down Modes)	$t_{AC.MIN} + 2 \text{ ns}$	$2 t_{CK} + t_{AC.MAX} + 1 \text{ ns}$	ns	
$t_{AOFD}$	ODT turn-off delay	2.5	2.5	$t_{CK}$	
$t_{AOF}$	ODT turn-off	$t_{AC.MIN}$	$t_{AC.MAX} + 0.6 \text{ ns}$	ns	2)
$t_{AOFPD}$	ODT turn-off (Power-Down Modes)	$t_{AC.MIN} + 2 \text{ ns}$	$2.5 t_{CK} + t_{AC.MAX} + 1 \text{ ns}$	ns	
$t_{ANPD}$	ODT to Power Down Mode Entry Latency	3	—	$t_{CK}$	
$t_{AXPD}$	ODT Power Down Exit Latency	8	—	$t_{CK}$	

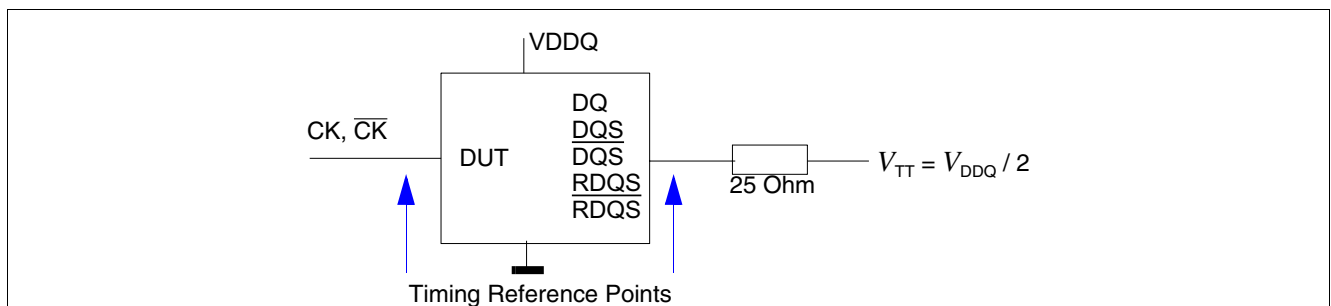
- 1) ODT turn on time min. is when the device leaves high impedance and ODT resistance begins to turn on. ODT turn on time max is when the ODT resistance is fully on. Both are measure from  $t_{AOND}$ .
- 2) ODT turn off time min. is when the device starts to turn off ODT resistance. ODT turn off time max is when the bus is in high impedance. Both are measured from  $t_{AOFD}$ .

## 8 AC Timing Measurement Conditions

### 8.1 Reference Load for Timing Measurements

**Figure 72** represents the timing reference load used in defining the relevant timing parameters of the device. It is not intended to either a precise representation of the typical system environment nor a depiction of the actual load presented by a production tester. System designers should use IBIS or other simulation tools to correlate the timing reference load to a system environment. Manufacturers correlate to their

production test conditions, generally a coaxial transmission line terminated at the tester electronics. This reference load is also used for output Slew Rate characterization. The output timing reference voltage level for single ended signals is the crosspoint with  $V_{TT}$ . The output timing reference voltage level for differential signals is the crosspoint of the true (e.g. DQS) and the complement (e.g.  $\overline{DQS}$ ) signal.



**Figure 72** Reference Load for Timing Measurements

### 8.2 Slew Rate Measurement Conditions

#### 8.2.1 Output Slew Rate

For DQ and single ended DQS signals output Slew Rate for falling and rising edges is measured between  $V_{TT} - 250$  mV and  $V_{TT} + 250$  mV.

For differential signals (DQS /  $\overline{DQS}$ ) output Slew Rate is measured between  $DQS - \overline{DQS} = -500$  mV and

$DQS - \overline{DQS} = +500$  mV. Output Slew Rate is defined with the reference load according to **Figure 72** and verified by design and characterization, but not subject to production test.

#### 8.2.2 Input Slew Rate - Differential signals

Input Slew Rate for differential signals (CK /  $\overline{CK}$ , DQS /  $\overline{DQS}$ , RDQS /  $\overline{RDQS}$ ) for rising edges are measured from  $CK - \overline{CK} = -250$  mV to  $CK - \overline{CK} = +500$  mV and

from  $CK - \overline{CK} = +250$  mV to  $CK - \overline{CK} = -500$  mV for falling edges.

### 8.3 Input and Data Setup and Hold Time

#### 8.3.1 Definition for Input Setup ( $t_{IS}$ ) and Hold Time ( $t_{IH}$ )

Address and control input setup time ( $t_{IS}$ ) is referenced from the input signal crossing at the  $V_{IH(ac)}$  level for a rising signal and  $V_{IL(ac)}$  for a falling signal applied to the device under test. Address and control input hold time

( $t_{IH}$ ) is referenced from the input signal crossing at the  $V_{IL(dc)}$  level for a rising signal and  $V_{IH(dc)}$  for a falling signal applied to the device under test.

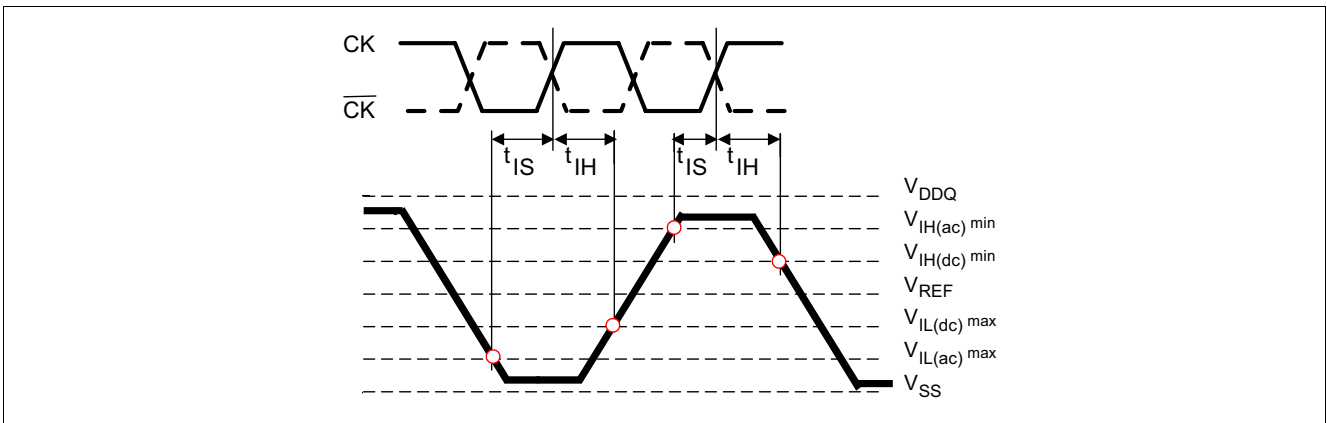


Figure 73 Input Setup and Hold Time

#### 8.3.2 Definition for Data Setup ( $t_{DS}$ ) and Hold Time ( $t_{DH}$ ), differential Data Strobes

Data input setup time ( $t_{DS}$ ) with differential data strobe enabled MR[bit10]=0, is referenced from the input signal crossing at the  $V_{IH(ac)}$  level to the differential data strobe crosspoint for a rising signal, and from the input signal crossing at the  $V_{IL(ac)}$  level to the differential data strobe crosspoint for a falling signal applied to the device under test.

differential data strobe enabled MR[bit10]=0, is referenced from the input signal crossing at the  $V_{IL(dc)}$  level to the differential data strobe crosspoint for a rising signal and  $V_{IH(dc)}$  to the differential data strobe crosspoint for a falling signal applied to the device under test.

DQS/ $\overline{DQS}$  signals must be monotonic between  $V_{IL(dc).MAX}$  and  $V_{IH(dc).MIN}$ . Data input hold time ( $t_{DH}$ ) with

DQS/ $\overline{DQS}$  signals must be monotonic between  $V_{IL(dc).MAX}$  and  $V_{IH(dc).MIN}$ .

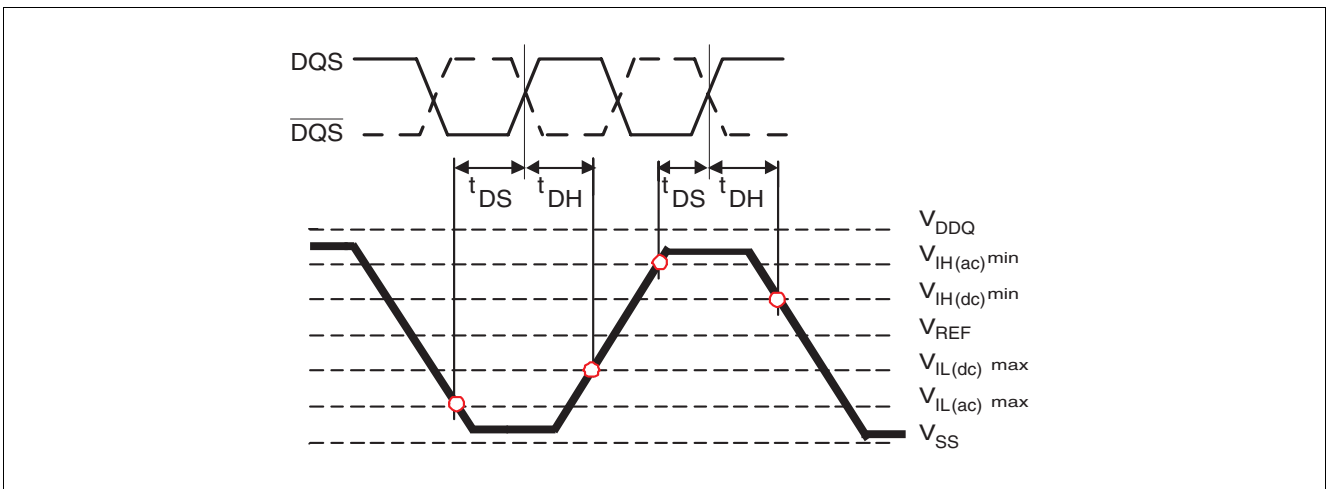


Figure 74 Data Setup and Hold Time (Differential Data Strobes)

### 8.3.3 Definition Data Setup ( $t_{DS1}$ ) and Hold Time ( $t_{DH1}$ ), Single-Ended Data Strobes

Data input setup time ( $t_{DS1}$ ) with single-ended data strobe enabled MR[bit10]=1, is referenced from the input signal crossing at the  $V_{IH(ac)}$  level to the single-ended data strobe crossing  $V_{IH/L(dc)}$  at the start of its transition for a rising signal, and from the input signal crossing at the  $V_{IL(ac)}$  level to the single-ended data strobe crossing  $V_{IH/L(dc)}$  at the start of its transition for a falling signal applied to the device under test.

Data input hold time ( $t_{DH1}$ ) with single-ended data strobe enabled MR[bit10]=1, is referenced from the

input signal crossing at the  $V_{IH(dc)}$  level to the single-ended data strobe crossing  $V_{IH/L(ac)}$  at the end of its transition for a rising signal and from the input signal crossing at the  $V_{IL(dc)}$  level to the single-ended data strobe crossing  $V_{IH/L(ac)}$  at the end of its transition for a falling signal applied to the device under test.

The DQS signal must be monotonic between  $V_{IL(dc).MAX}$  and  $V_{IH(dc).MIN}$ .

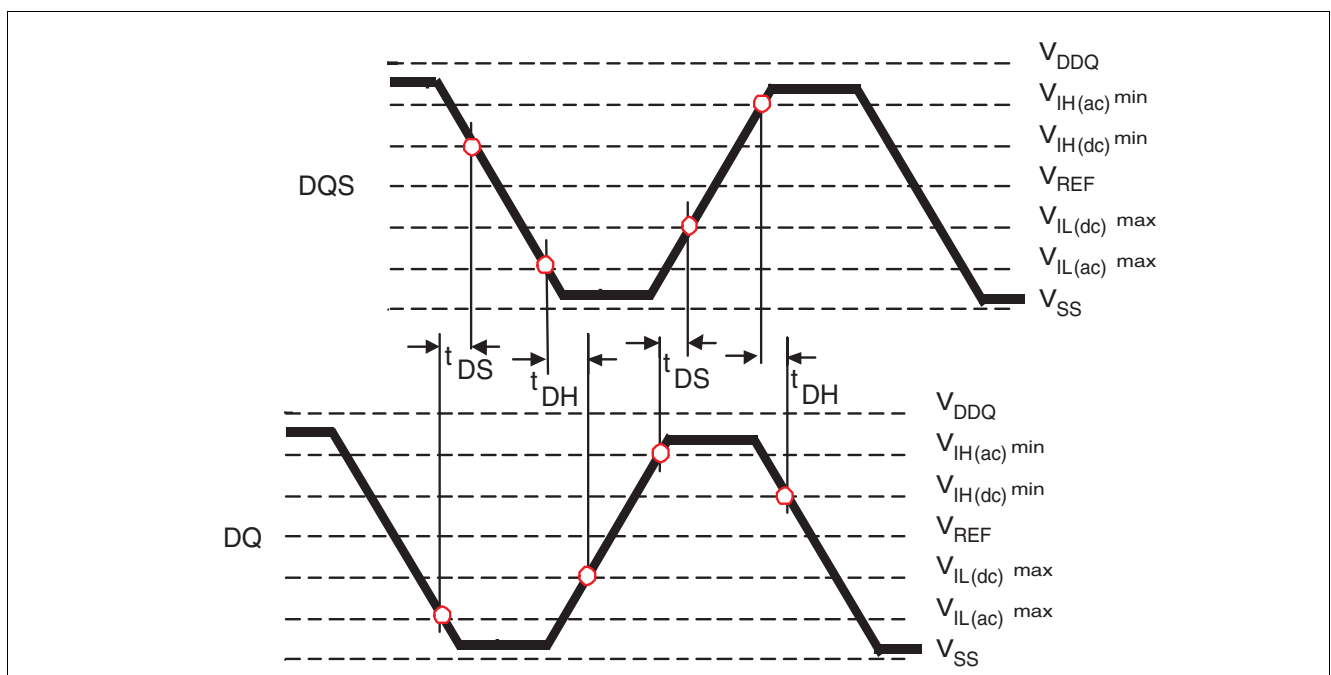


Figure 75 Data Setup and Hold Time (Single Ended Data Strobes)

### 8.3.4 Slew Rate Definition for Input and Data Setup and Hold Times

Setup ( $t_{IS}$  &  $t_{DS}$ ) nominal Slew Rate for a rising signal is defined as the Slew Rate between the last crossing of  $V_{REF(dc)}$  and the first crossing of  $V_{IH(ac).MIN}$ . Setup ( $t_{IS}$  &  $t_{DS}$ ) nominal Slew Rate for a falling signal is defined as the Slew Rate between the last crossing of  $V_{REF(dc)}$  and the first crossing of  $V_{IL(ac).MAX}$ . If the actual signal is always earlier than the nominal Slew Rate line between shaded 'dc to  $V_{REF}$  region', use nominal Slew Rate for derating value (see [Figure 76](#)). If the actual signal is later than the nominal Slew Rate line anywhere between shaded ' $V_{REF(dc)}$  to ac region', the Slew Rate of a tangent line to the actual signal from the ac level to dc

level is used for derating value.(see [Figure 77](#)) Hold ( $t_{IH}$  &  $t_{DH}$ ) nominal Slew Rate for a rising signal is defined as the Slew Rate between the last crossing of  $V_{IL(dc).MAX}$  and the first crossing of  $V_{REF(dc)}$ . Hold ( $t_{IH}$  &  $t_{DH}$ ) nominal Slew Rate for a falling signal is defined as the Slew Rate between the last crossing of  $V_{IH(dc).MIN}$  and the first crossing of  $V_{REF(dc)}$ . If the actual signal is always later than the nominal Slew Rate line between shaded 'dc to  $V_{REF}$  region', use nominal Slew Rate for derating value (see [Figure 76](#)). If the actual signal is earlier than the actual signal from the dc level to  $V_{REF}$  level is used for derating value (see [Figure 77](#))

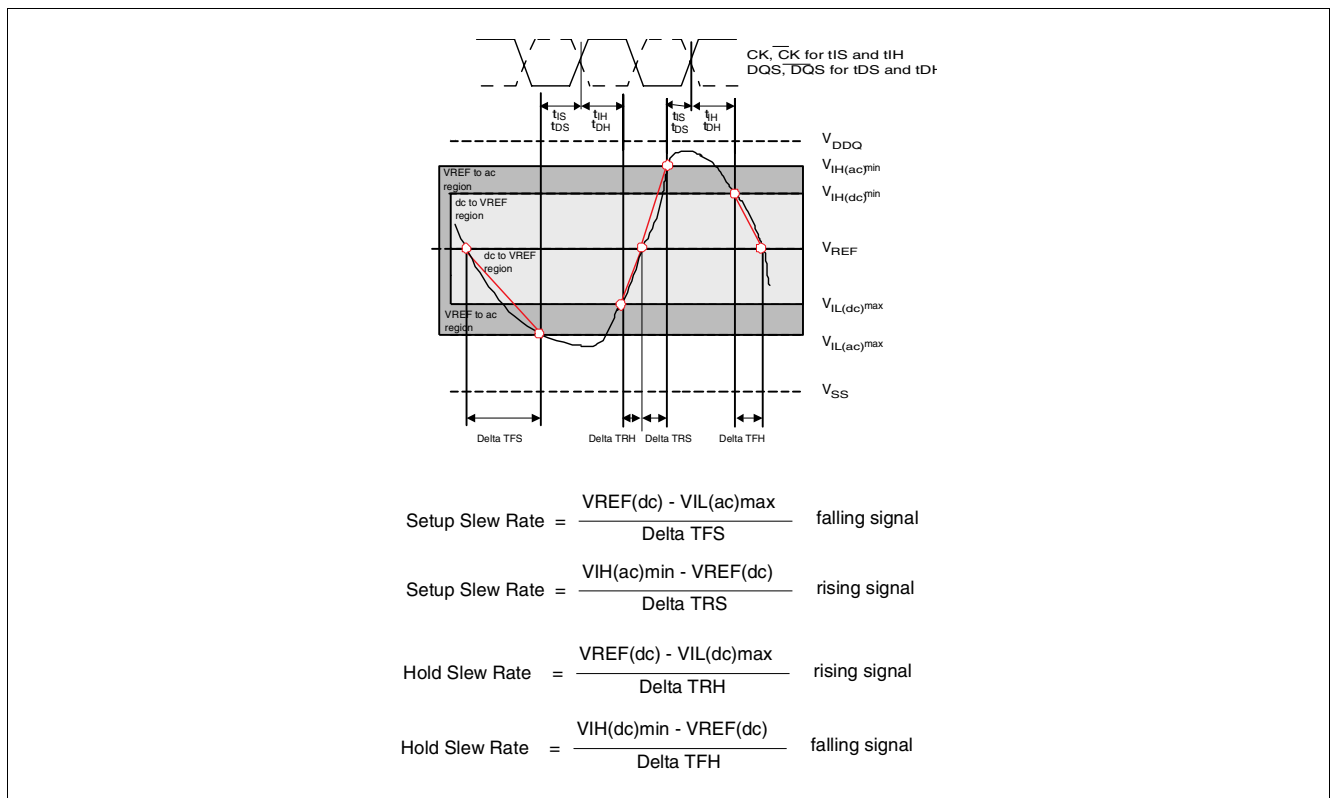


Figure 76 Slew Rate Definition Nominal

AC Timing Measurement Conditions

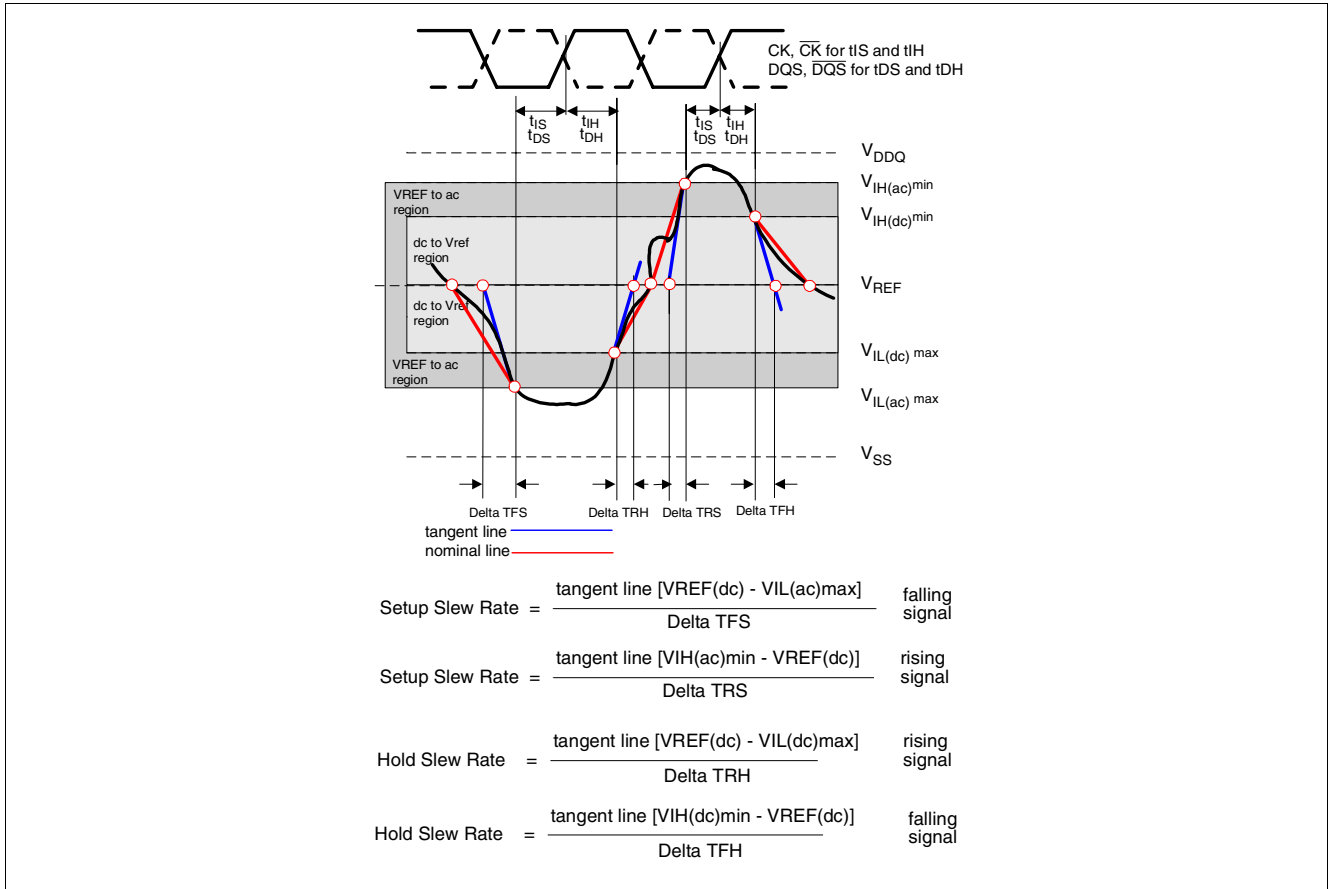


Figure 77 Slew Rate Definition Tangent

### 8.3.5 Setup ( $t_{IS}$ ) and Hold ( $t_{IH}$ ) Time Derating Tables

- For all input signals the total input setup time and input hold time required is calculated by adding the data sheet value to the derating value respectively.  
Example:  $t_{IS}(\text{total setup time}) = t_{IS}(\text{base}) + \Delta t_{IS}$
- For slow Slew Rate the total setup time might be negative (i.e. a valid input signal will not have reached  $V_{IH(ac)} / V_{IL(ac)}$  at the time of the rising clock)

a valid input signal is still required to complete the transition and reach  $V_{IH(ac)} / V_{IL(ac)}$ . For Slew Rates in between the values listed in the next tables, the derating values may be obtained by linear interpolation. These values are not subject to production test. They are verified only by design and characterization.

**Table 61 Derating Values for Input Setup and Hold Time (DDR2-667 & DDR2-800)**

Command / Address Slew Rate (V/ns)	CK, CK Differential Slew Rate						Unit	Note
	2.0 V/ns		1.5 V/ns		1.0 V/ns			
	$\Delta t_{IS}$	$\Delta t_{IH}$	$\Delta t_{IS}$	$\Delta t_{IH}$	$\Delta t_{IS}$	$\Delta t_{IH}$		
4.0	+150	+94	+180	+124	+210	+154	ps	1)2)
3.5	+143	+89	+173	+119	+203	+149	ps	1)
3.0	+133	+83	+163	+113	+193	+143	ps	1)
2.5	+120	+75	+150	+105	+180	+135	ps	1)
2.0	+100	+45	+130	+75	+160	+105	ps	1)
1.5	+67	+21	+97	+51	+127	+81	ps	1)
1.0	0	0	+30	+30	+60	+60	ps	1)
0.9	-5	-14	+25	+16	+55	+46	ps	1)
0.8	-13	-31	+17	-1	+47	+29	ps	1)
0.7	-22	-54	+8	-24	+38	+6	ps	1)
0.6	-34	-83	-4	-53	+26	-23	ps	1)
0.5	-60	-125	-30	-95	0	-65	ps	1)
0.4	-100	-188	-70	-158	-40	-128	ps	1)
0.3	-168	-292	-138	-262	-108	-232	ps	1)
0.25	-200	-375	-170	-345	-140	-315	ps	1)
0.2	-325	-500	-295	-470	-265	-440	ps	1)
0.15	-517	-708	-487	-678	-457	-648	ps	1)
0.1	-1000	-1125	-970	-1095	-940	-1065	ps	1)

- For all input signals  $t_{IS}(\text{total}) = t_{IS}(\text{base}) + \Delta t_{IS}$  and  $t_{IH}(\text{total}) = t_{IH}(\text{base}) + \Delta t_{IH}$
- For slow slewrate the total setup time might be negative (i.e. valid input signal will not have reached  $V_{IH(ac)} / V_{IL(ac)}$  at the time of the rising clock) a valid signal is still required to complete the transition and reach  $V_{IH(ac)} / V_{IL(ac)}$ . For slew rates in between the values listed in the next tables, the derating values may be obtained by linear interpolation. These values are not subject to production test. They are verified only by design and characterisation.

**AC Timing Measurement Conditions**

**Table 62 Derating Values for Input Setup and Hold Time (DDR2-400 & DDR2-533)**

Command / Address Slew Rate (V/ns)	CK, CK Differential Slew Rate						Unit	Note
	2.0 V/ns		1.5 V/ns		1.0 V/ns			
	$\Delta t_{IS}$	$\Delta t_{IH}$	$\Delta t_{IS}$	$\Delta t_{IH}$	$\Delta t_{IS}$	$\Delta t_{IH}$		
4.0	+187	+94	+217	+124	+247	+154	ps	1)2)
3.5	+179	+89	+209	+119	+239	+149	ps	1)
3.0	+167	+83	+197	+113	+227	+143	ps	1)
2.5	+150	+75	+180	+105	+210	+135	ps	1)
2.0	+125	+45	+155	+75	+185	+105	ps	1)
1.5	+83	+21	+113	+51	+143	+81	ps	1)
1.0	0	0	+30	+30	+60	+60	ps	1)
0.9	-11	-14	+19	+16	+49	+46	ps	1)
0.8	-25	-31	+5	-1	+35	+29	ps	1)
0.7	-43	-54	-13	-24	+17	+6	ps	1)
0.6	-67	-83	-37	-53	-7	-23	ps	1)
0.5	-110	-125	-80	-95	-50	-65	ps	1)
0.4	-175	-188	-145	-158	-115	-128	ps	1)
0.3	-285	-292	-255	-262	-225	-232	ps	1)
0.25	-350	-375	-320	-345	-290	-315	ps	1)
0.2	-525	-500	-495	-470	-465	-440	ps	1)
0.15	-800	-708	-770	-678	-740	-648	ps	1)
0.1	-1450	-1125	-1420	-1095	-1390	-1065	ps	1)

- 1) For all input signals  $t_{IS}(\text{total}) = t_{IS}(\text{base}) + \Delta t_{IS}$  and  $t_{IH}(\text{total}) = t_{IH}(\text{base}) + \Delta t_{IH}$
- 2) For slow slewrates the total setup time might be negative (i.e. valid input signal will not have reached  $V_{IH(ac)} / V_{IL(ac)}$  at the time of the rising clock) a valid signal is still required to complete the transistion and reach  $V_{IH(ac)} / V_{IL(ac)}$ . For slewrates in between the values listed in the next tables, the derating values may be obtained by linear interpolation. These values are not subject to production test. They are verified only by design and characterisation.

**Table 63 Derating Values for Data Setup and Hold Time of Differential DQS (DDR2-667 & DDR2-800)**

DQ Slew Rate (V/ns)	DQS, DQS Differential Slew Rate <sup>1)2)</sup>																	
	4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns		0.8 V/ns	
	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$
2.0	+100	+45	+100	+45	+100	+45	—	—	—	—	—	—	—	—	—	—	—	—
1.5	+67	+21	+67	+21	+67	+21	+97	+33	—	—	—	—	—	—	—	—	—	—
1.0	0	0	0	0	0	0	+12	+12	+24	+24	—	—	—	—	—	—	—	—
0.9	—	—	-5	-14	-5	-14	+7	-2	+19	+10	+31	+22	—	—	—	—	—	—
0.8	—	—	—	—	-13	-31	-1	-19	+11	-7	+23	+5	+35	+17	—	—	—	—
0.7	—	—	—	—	—	—	-10	-42	+2	-30	+14	-18	+26	-6	+38	+6	—	—
0.6	—	—	—	—	—	—	—	—	-10	-59	+2	-47	+14	-35	+26	-23	+538	-11
0.5	—	—	—	—	—	—	—	—	—	—	-24	-89	-12	-77	0	-65	+12	-53
0.4	—	—	—	—	—	—	—	—	—	—	—	—	-52	-140	-20	-28	-28	-116

1) All units in ps.

2) For all input signals  $t_{DS}(\text{total}) = t_{DS}(\text{base}) + \Delta t_{DS}$  and  $t_{DH}(\text{total}) = t_{DH}(\text{base}) + \Delta t_{DH}$

**AC Timing Measurement Conditions**

**Table 64 Derating Values for Data Setup and Hold Time of Differential DQS (DDR2-400 & -533)**

DQ Slew Rate (V/ns)	DQS, DQS Differential Slew Rate <sup>1)2)</sup>																	
	4.0 V/ns		3.0 V/ns		2.0 V/ns		1.8 V/ns		1.6 V/ns		1.4 V/ns		1.2 V/ns		1.0 V/ns		0.8 V/ns	
	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$	$\Delta t_{DS}$	$\Delta t_{DH}$
2.0	+125	+45	+125	+45	+125	+45	—	—	—	—	—	—	—	—	—	—	—	—
1.5	+83	+21	+83	+21	+83	+21	+95	+33	—	—	—	—	—	—	—	—	—	—
1.0	0	0	0	0	0	0	+12	+12	+24	+24	—	—	—	—	—	—	—	—
0.9	—	—	-11	-14	-11	-14	+1	-2	+13	+10	+25	+22	—	—	—	—	—	—
0.8	—	—	—	—	-25	-31	-13	-19	-1	-7	+11	+5	+23	+17	—	—	—	—
0.7	—	—	—	—	—	—	-31	-42	-19	-30	-7	-18	+5	-6	+17	+6	—	—
0.6	—	—	—	—	—	—	—	—	-43	-59	-31	-47	-19	-35	-7	-23	+5	-11
0.5	—	—	—	—	—	—	—	—	—	—	-74	-89	-62	-77	-50	-65	-38	-53
0.4	—	—	—	—	—	—	—	—	—	—	—	—	-127	-140	-115	-128	-103	-116

1) All units in ps.

2) For all input signals  $t_{DS}(\text{total}) = t_{DS}(\text{base}) + \Delta t_{DS}$  and  $t_{DH}(\text{total}) = t_{DH}(\text{base}) + \Delta t_{DH}$

**Table 65 Derating Values for Data Setup and Hold Time of Single-ended DQS (DDR2-400 & -533)**

DQ Slew Rate (V/ns)	DQS, DQS Single-ended Slew Rate <sup>1)2)</sup>																	
	2.0 V/ns		1.5 V/ns		1.0 V/ns		0.9 V/ns		0.8 V/ns		0.7 V/ns		0.6 V/ns		0.5 V/ns		0.4 V/ns	
	$\Delta t_{DS1}$	$\Delta t_{DH1}$	$\Delta t_{DS1}$	$\Delta t_{DH1}$	$\Delta t_{DS1}$	$\Delta t_{DH1}$	$\Delta t_{DS1}$	$\Delta t_{DH1}$	$\Delta t_{DS1}$	$\Delta t_{DH1}$	$\Delta t_{DS1}$	$\Delta t_{DH1}$	$\Delta t_{DS1}$	$\Delta t_{DH1}$	$\Delta t_{DS1}$	$\Delta t_{DH1}$	$\Delta t_{DS1}$	$\Delta t_{DH1}$
2.0	+188	+188	+167	+146	+125	+63	—	—	—	—	—	—	—	—	—	—	—	—
1.5	+146	+167	+125	+125	+83	+42	+81	+43	—	—	—	—	—	—	—	—	—	—
1.0	+63	+125	+42	+83	0	0	-2	+1	-7	-13	—	—	—	—	—	—	—	—
0.9	—	—	+31	+69	-11	-14	-13	-13	-18	-27	-29	-45	—	—	—	—	—	—
0.8	—	—	—	—	-25	-31	-27	-30	-32	-44	-43	-62	-60	-86	—	—	—	—
0.7	—	—	—	—	—	—	-45	-53	-50	-67	-61	-85	-78	-109	-108	-152	—	—
0.6	—	—	—	—	—	—	—	—	-74	-96	-85	-114	-102	-138	-132	-181	-183	-246
0.5	—	—	—	—	—	—	—	—	—	—	-128	-156	-145	-180	-175	-223	-226	-288
0.4	—	—	—	—	—	—	—	—	—	—	—	—	-210	-243	-240	-286	-291	-351

1) All units in ps.

2) For all input signals  $t_{DS1}(\text{total}) = t_{DS1}(\text{base}) + \Delta t_{DS1}$  and  $t_{DH1}(\text{total}) = t_{DH1}(\text{base}) + \Delta t_{DH1}$

## 9 Package Dimensions

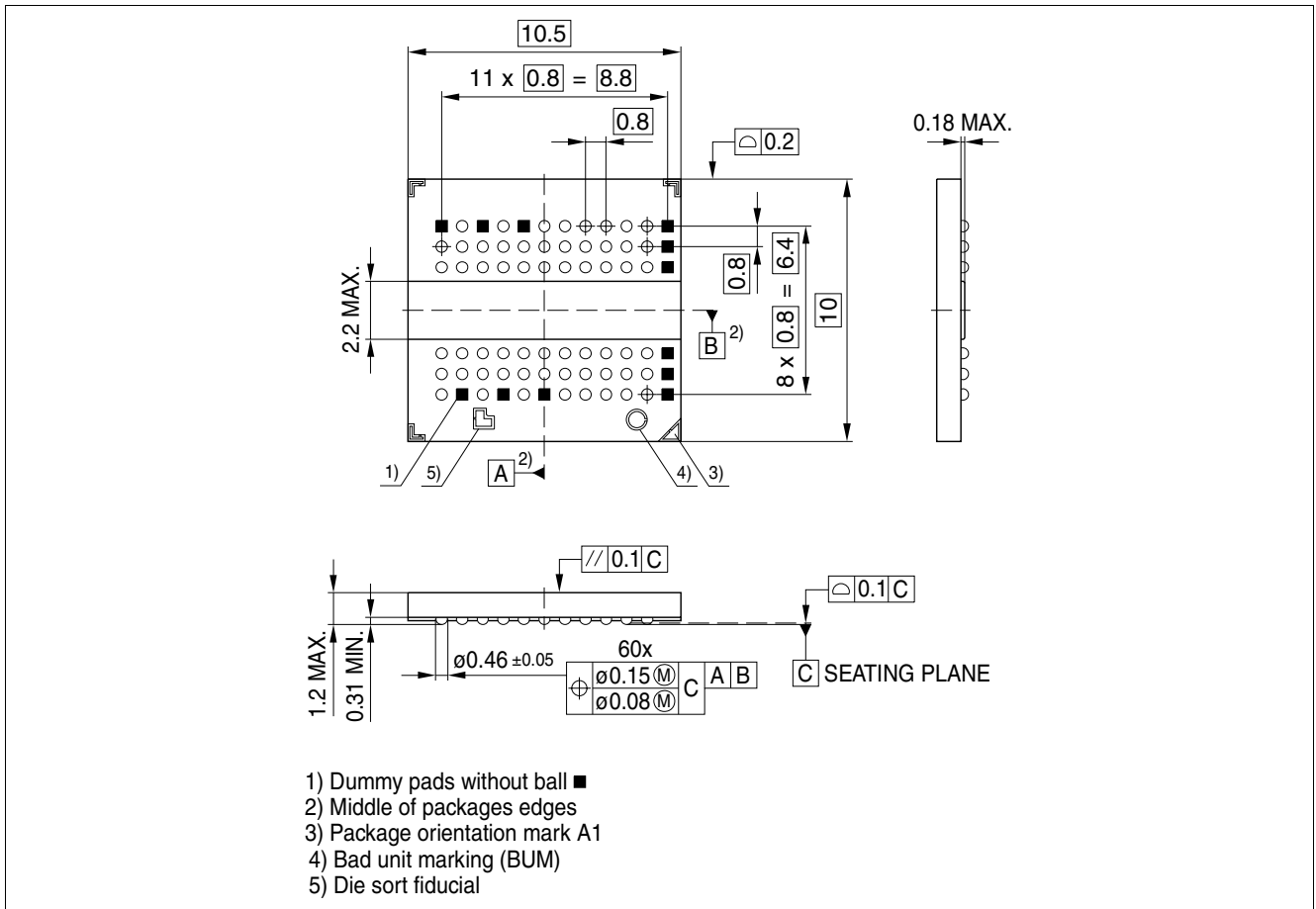


Figure 78 Package Pinout PG-TFBGA-60 (top view)

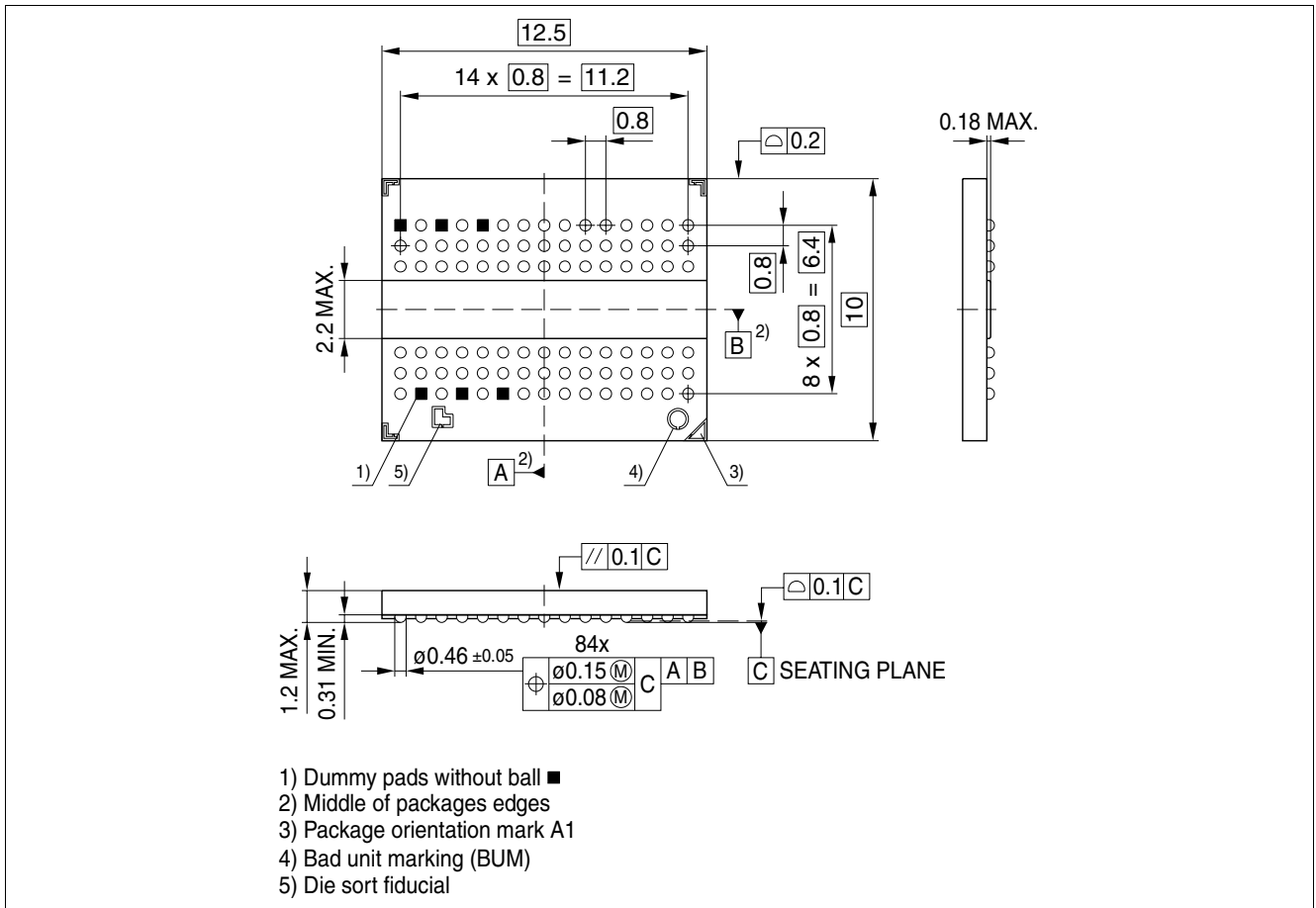


Figure 79 Package Pinout PG-TFBGA-84 (top view)

## 10 Product Nomenclature

**Table 66 Nomenclature Fields and Examples**

Example for	Field Number										
	1	2	3	4	5	6	7	8	9	10	11
DDR2 DRAM	HYB	18	T	512	16		0	A	C	-3.7	

**Table 67 DDR2 Memory Components**

Field	Description	Values	Coding
1	INFINEON Component Prefix	HYB	Constant
2	Interface Voltage [V]	18	SSTL_18
3	DRAM Technology	T	DDR2
4	Component Density [Mbit]	256	256 M
		512	512 M
		1G	1 Gb
5+6	Number of I/Os	40	×4
		80	×8
		160	×16
7	Product Variations	0 .. 9	look up table
8	Die Revision	A	First
		B	Second
9	Package, Lead-Free Status	C	FBGA, lead-containing
		F	FBGA, lead-free
	Power	L	low power product
10	Speed Grade	-2.5	DDR2-800 6-6-6
		-25F	DDR2-800 5-5-5
		-3	DDR2-667 4-4-4
		-3S	DDR2-667 5-5-5
		-3.7	DDR2-533 4-4-4
		-5	DDR2-400 3-3-3
11	N/A for Components		

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